

N32G052xx

Datasheet

N32G052 series based on Arm® Cortex®-M0, run up to 64MHz, up to 128KB embedded Flash, 8KB data Flash, 16KB SRAM, integrated analog interface, 1x12bit 1Msps ADC, 4x Comparator, 1x8/12bit 1Msps DAC, integrated multi-channel UART, I2C, SPI, CAN and other digital communication interfaces, Segment LCD Driver Interface, built-in password algorithm hardware acceleration engine.

Key features

- **Core**
 - A 32-bit general-purpose microcontroller based on the Arm® Cortex®-M0 core, Single-cycle hardware multiply instruction
 - Run up to 64MHz
- **Encrypted memory**
 - Up to 128KByte embedded Flash memory, 8KByte embedded Data Flash memory, supports encrypted storage, supports hardware ECC verification, data 100,000 cycling and 10 years of data retention
 - SRAM of 16KB, STOP modes can be configured as retention, supporting hardware parity
- **Low-power management**
 - Run mode: all peripherals configurable
 - SLEEP mode: all peripherals configurable
 - STOP mode: TIM6, IWDG, RTC configurable operation, 16KByte SRAM retention, CPU register retention, all IO retention
 - Power Down mode: support NRST, PA0_WKUP0, PA2_WKUP1 wakeup
- **Clock**
 - HSE: 8MHz~16MHz external high-speed crystal
 - HSI: Internal high-speed RC OSC 8MHz
 - HSI_24MHz: Internal high-speed RC OSC 24MHz, available only as an ADC sample clock source option
 - LSI: Internal low-speed RC OSC 32KHz
 - Built-in high-speed PLL
 - MCO: Support 1-way clock output, configurable SYSLCK, HSI, HSE, LSI, and PLL clock output that can be divided.
- **Reset**
 - Support power-on/power-off/external pin reset
 - Supports programmable low voltage detection reset(LVR)
 - Support watchdog reset, Support software reset
- **Communication interface**
 - 5xUART, Supports asynchronous mode, multiprocessor communication mode, single-wire half-duplex mode
 - 3xSPI, up to 16 MHz
 - 2xI2C, up to 1 MHz, configurable master/slave mode
 - 1xCAN 2.0A/B bus interface, up to 1Mbps
- **1xDMA, 5-channel, channel source address and destination address can be arbitrarily configurable**

- **1x RTC real-time clock, support leap year perpetual calendar, alarm event, periodic wake up, support internal and external clock calibration**
- **Segment LCD display driver, support up to 256 segments (8x32) or 144 segments (4x36) or 111 segments (3x37)**
- **Analog interface**
 - 1x12bit 1Msps ADC , up to 15 external single-ended input channels
 - 4xCOMP (Comparator has an internal independent 6bit DAC)
 - 1x 12bit DAC, sampling rate 1Msps
 - Internal 1.2V independent reference voltage reference source
 - Internal integrated low voltage check unit
- **Up to 61 GPIOs**
- **1xBeeper, 16mA output drive capacity**
- **Timer counter**
 - 1x16-bit advanced timer counters, support input capture, complementary output, orthogonal encoding input, each timer support 5 independent channels. 4 channels support 8 complementary PWM outputs
 - 4x16-bit general purpose timer counters, 4 independent channels, supports input capture/output compare/PWM output
 - 1x16-bit basic timer counters, supports STOP wake-up low-power mode.
 - 1x24-bit SysTick
 - 1x14-bit Window Watchdog (WWDG)
 - 1x12-bit Independent watchdog (IWDG)
- **Programming mode**
 - Support SWD online debugging interface
 - Support UART Bootloader
- **Security features**
 - CRC16 calculation
 - Flash storage encryption, multi-user partition management (MMU)
 - Support write protection(WRP), multiple read protection(RDP) levels (L0/L1/L2)
 - Support external clock failure detection, tamper detection
- **96-bit UID and 128-bit UCID**
- **Working conditions**
 - Operating voltage Range: 2.0V~5.5V
 - Operating Temperature Range: -40°C~105°C
- **Package**
 - LQFP64(14mm x14mm, 0.8mm pitch)
 - LQFP64(10mm x10mm, 0.5mm pitch)
 - LQFP64(7mm x7mm, 0.4mm pitch)
 - LQFP48(7mm x7mm, 0.5mm pitch)
 - LQFP44(10mm x10mm, 0.8mm pitch, pinouts 1)

- LQFP44(10mm x10mm,0.8mm pitch,pinouts 2)
- QFN32(5mm x5mm, 0.5mm pitch)

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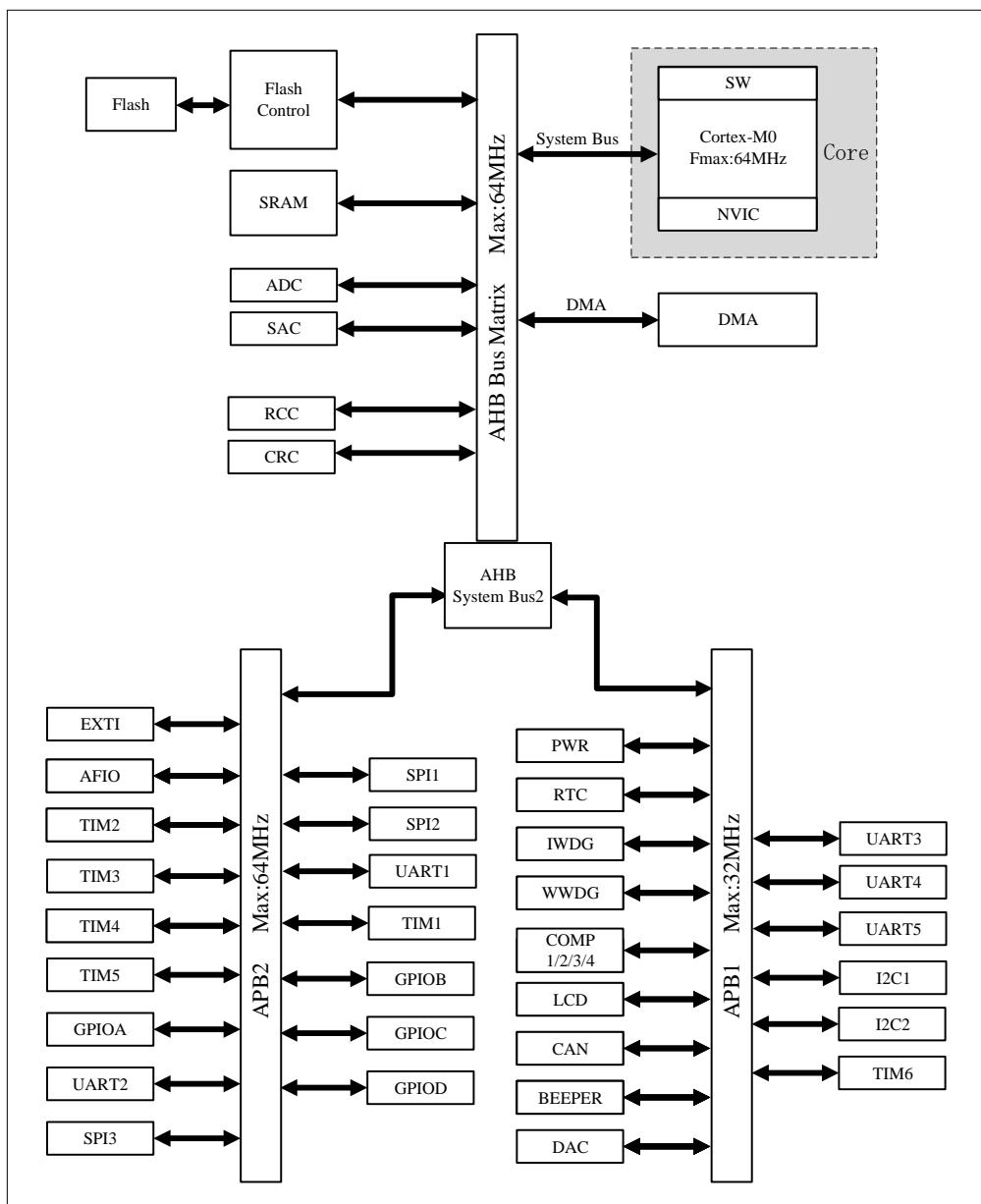
1 Product introduction

N32G052 family of microcontrollers features an ARM Cortex®-M0 core. Maximum operating main frequency 64MHz, integrated up to 128KB of in-chip encrypted storage Flash, 8KB DataFlash, maximum 16KB of embedded SRAM. It has an internal high speed AHB bus, two low speed peripherals clock bus APB and bus matrix. It supports up to 61 reusable I/Os and provides a rich array of high performance analog interfaces, including 1x 12-bit 1Msps ADC, up to 15 external input channels, and 4 high-speed comparator, 1x 12-bit 1Msps DAC. At the same time, it provides a variety of digital communication interfaces, including 5x UART, 2x I2C, 3x SPI, 1x CAN2.0A/B communication interface.

N32G052 series products can work stably in the temperature range of -40 °C to +105 °C, supply voltage from 2.0V to 5.5V, provide a variety of power modes for users to choose, meet the requirements of low-power applications.

Figure 1-1 shows the bus block diagram of this series of products.

Figure 1-1 N32G052 Block Diagram



1.1 List of devices

Table 1-1 N32G052 Series devices features and peripheral list

| Part Number | N32G052RBL7 | N32G052RBL7B | N32G052RBL7C | N32G052CBL7 | N32G052KBQ7 |
|-------------------------|---------------------------------|---------------------------------|---------------------------------|---------------------------------|---------------------------------|
| Flash (KB) | 128 | 128 | 128 | 128 | 128 |
| DATA flash(KB) | 8 | 8 | 8 | 8 | 8 |
| SRAM (KB) | 16 | 16 | 16 | 16 | 16 |
| CPU frequency | ARM Cortex-M0 @64MHz |
| Working environment | 2.0~5.5V/-40~105°C | 2.0~5.5V/-40~105°C | 2.0~5.5V/-40~105°C | 2.0~5.5V/-40~105°C | 2.0~5.5V/-40~105°C |
| Timer | Advanced | 1 | 1 | 1 | 1 |
| | General | 4 | 4 | 4 | 4 |
| | Basic | 1 | 1 | 1 | 1 |
| | Beep | 1 | 1 | 1 | 1 |
| Communication interface | SPI | 3 | 3 | 3 | 3 |
| | I2C | 2 | 2 | 2 | 2 |
| | UART | 5 | 5 | 5 | 5 |
| | CAN | 1 | 1 | 1 | 1 |
| GPIO | 61 | 61 | 61 | 45 | 29 |
| DMA | 1x 5 Channel |
| RTC | 1 | 1 | 1 | 1 | 1 |
| 12bit ADC | 1x 15Channel | 1x 15Channel | 1x 15Channel | 1x 12Channel | 1x 8Channel |
| 12bit DAC | 1x 1Channel |
| COMP | 4 | 4 | 4 | 4 | 3 |
| Segment LCD | 8x32/4x36/ 3*37 | 8x32/4x36/ 3*37 | 8x32/4x36/ 3*37 | 8x22/4x26/ 3*27 | 4*11/2*13 |
| Algorithm support | CRC16 | CRC16 | CRC16 | CRC16 | CRC16 |
| Security protection | Read/write protection (RDP/WRP) |
| Package | LQFP64(14*14mm, 0.8mm pitch) | LQFP64(10*10mm, 0.5mm pitch) | LQFP64(7*7mm, 0.4mm pitch) | LQFP48(7*7mm, 0.5mm pitch) | QFN32(5x5mm, 0.5mm pitch) |

| Part Number | N32G052SBL7 | | N32G052SBL7A |
|-------------------------|----------------------|---|----------------------|
| Flash (KB) | 128 | | 128 |
| DATA flash(KB) | 8 | | 8 |
| SRAM (KB) | 16 | | 16 |
| CPU frequency | ARM Cortex-M0 @64MHz | | ARM Cortex-M0 @64MHz |
| Working environment | 2.0~5.5V/-40~105°C | | 2.0~5.5V/-40~105°C |
| Timer | Advanced | 1 | 1 |
| | General | 4 | 4 |
| | Basic | 1 | 1 |
| | Beep | 1 | 1 |
| Communication interface | SPI | 3 | 3 |
| | I2C | 2 | 2 |
| | UART | 5 | 5 |
| | CAN | 1 | 1 |
| GPIO | 41 | | 41 |
| DMA | 1x 5 Channel | | 1x 5 Channel |

| | | |
|---------------------|---|---|
| RTC | 1 | 1 |
| 12bit ADC | 1x 15Channel | 1x 15Channel |
| 12bit DAC | 1x 1Channel | 1x 1Channel |
| COMP | 4 | 4 |
| Segment LCD | 3*27 | 3*27 |
| Algorithm support | CRC16 | CRC16 |
| Security protection | read/write protection (RDP/WRP) | read/write protection (RDP/WRP) |
| Package | LQFP44(10*10mm, 0.8mm pitch, pinouts 1) | LQFP44(10*10mm, 0.8mm pitch, pinouts 2) |

2 Functional description

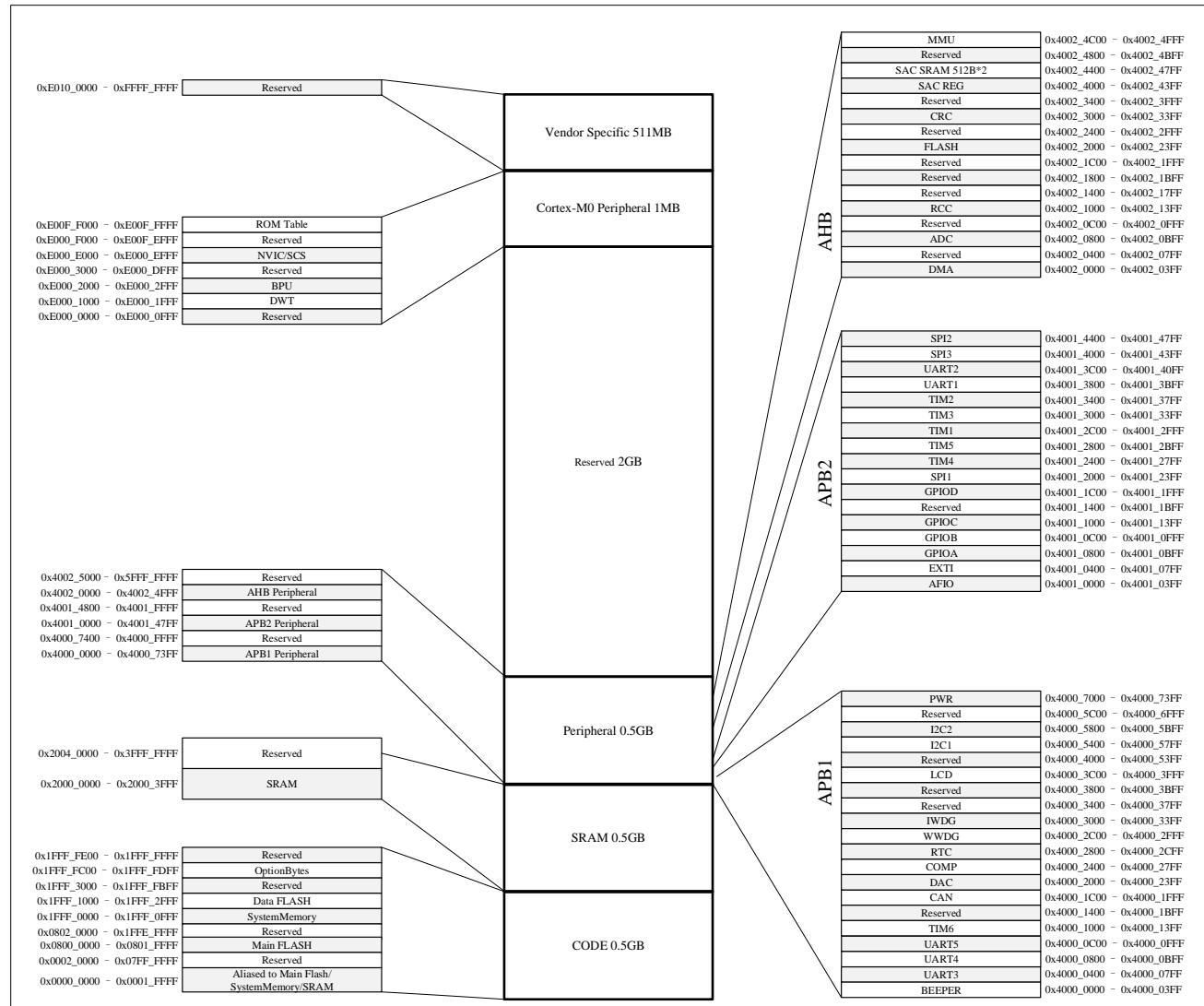
2.1 Processor core

N32G052 series integrates the latest generation of embedded ARM Cortex®-M0 processor

2.2 Storage

N32G052 series devices include embedded encrypted Flash memory and embedded SRAM.

Figure 2-1 Memory address map



2.2.1 Embedded FLASH memory

Integrated up to 128K bytes embedded encryption FLASH, used to store programs and data, page size of 512byte, supporting page erasing, word writing, word reading, half word reading, byte reading operations.

Integrated 8K bytes embedded encryption Data FLASH, used to store data, page size of 512byte, supporting page erasing, word writing, word reading, half word reading, byte reading operations.

Support storage encryption protection, write automatic encryption, read automatic decryption (including program

execution operation).

2.2.2 Embedded SRAM

Integrated up to 16K bytes SRAM. In STOP mode, SRAM can hold data.

2.2.3 Nested vectored interrupt controller (NVIC)

The Nested Vectored Interrupt Controller (NVIC) is tightly connected to the interface of the kernel, which can realize low-latency interrupt processing and efficiently handle late-arriving interrupts. The nested vectored interrupt controller manages interrupts including kernel exceptions.

- 32 maskable interrupt channels (not including 16 Cortex®-M0 interrupt lines)
- 4 programmable priority levels (using 2-bit interrupt priority levels)
- Low-latency exception and interrupt handling
- Power management control
- Realization of system control register

The module provides flexible interrupt management functions with minimal interrupt delay

2.3 External interrupt/event controller (EXTI)

The external interrupt/event controller contains 21 edge detectors for generating interrupt/event requests. Each interrupt line can be independently configured with its triggering event (rising edge or falling edge or bilateral edge) and can be individually shielded. There is a suspended register that maintains the state of all interrupt requests. The corresponding bit of the suspend register can be cleared by writing '1'.

2.4 Clock system

The device provides a variety of clocks for users to choose from, including internal high speed RC oscillator HSI (8MHz), internal low speed clock LSI (32KHz), external high speed clock HSE (8MHz~16MHz), PLL.

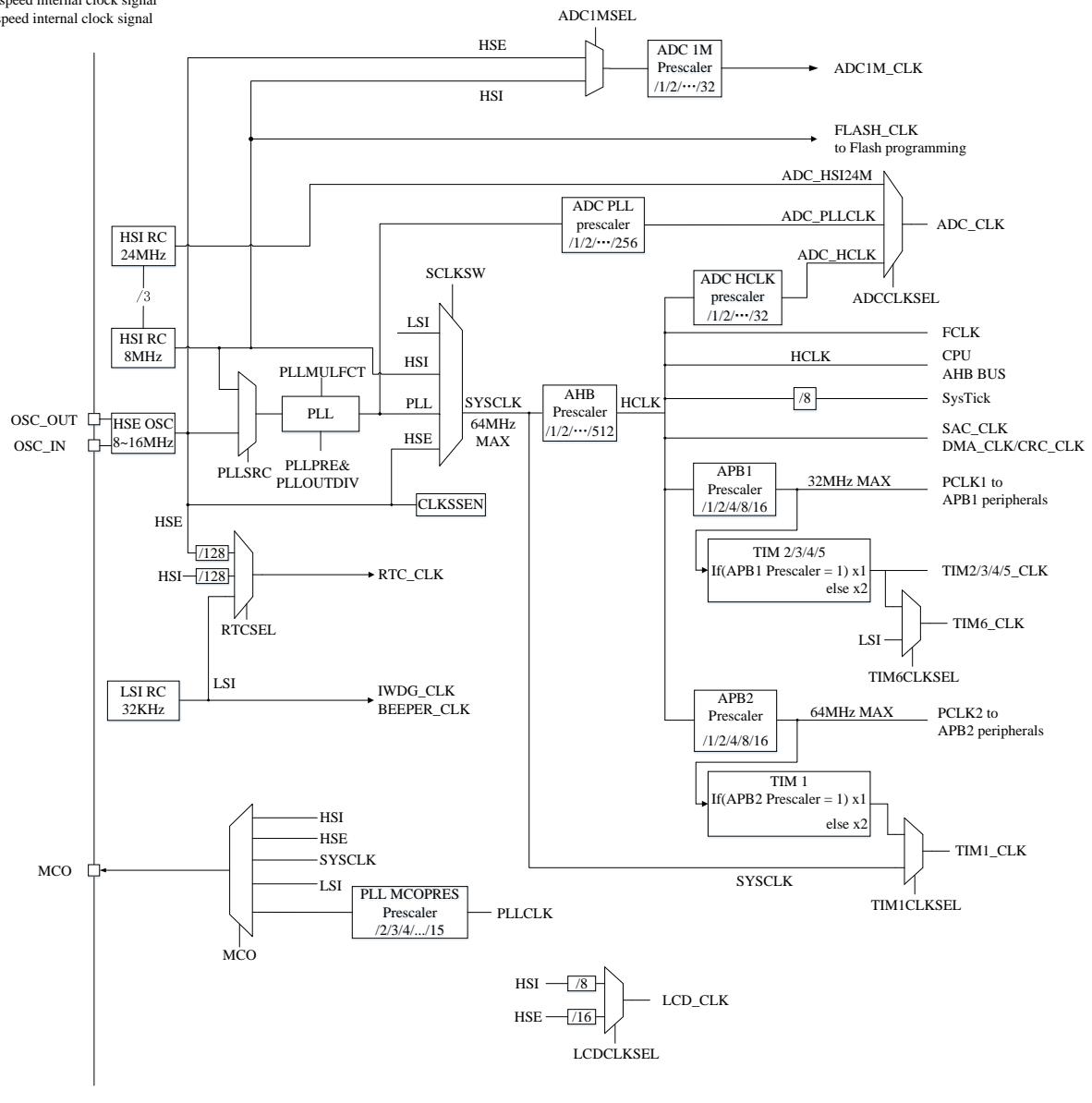
During reset, the internal HSI clock is set as the default CPU clock, and then the user can choose the external HSE clock with failure monitoring function. When HSE failure is detected, it will be isolated, the system will automatically switch to HSI, and if interrupts are enabled, the software can receive the corresponding interrupt. Also, security interrupt management of the PLL clock can be adopted when needed (such as when an indirectly used external oscillator fails).

Multiple prescaler are used to configure the AHB frequency, high speed APB (APB2) and low speed APB (APB1) regions. AHB has a maximum frequency of 64MHz, APB2 has a maximum frequency of 64MHz and APB1 has a maximum frequency of 32MHz.

Figure 2-2 Clock Tree

Clock Tree

Legend:
 HSE = High-speed external clock signal
 HSI = High-speed internal clock signal
 LSI = Low-speed internal clock signal



2.5 Boot mode

At BOOT time, the BOOT mode after reset can be selected with the **BOOT0** pin and option byte **BOOT** configuration (**USER2**).

- Boot from program FLASH Memory
- Boot from System Memory
- Boot from internal SRAM

The Bootloader is stored in the system memory and can program the flash memory through USART1 interface.

2.6 Boot Swap

This function can be used to update the secondary boot, to avoid directly updating the secondary boot because of temporary power failure or other reasons leading to the failure of updating the code of the secondary boot area, and the loss of the original secondary boot code leads to the program can not work properly, boot swap function can effectively avoid this problem.

2.7 Power supply scheme

- VDD area: The voltage input range is 2.0V~5.5V, which mainly provides power input for Main Regulator, IO and clock reset system.
- VDDD area: The voltage regulator supplies power for the CPU, AHB, APB, SRAM, FLASH and most digital peripheral interfaces.

PWR is the power control module of the entire device, its main function is to control N32G052 to enter different power modes and can be awakened by other events or interrupts. N32G052 supports RUN, SLEEP, STOP and PD modes.

2.8 Programmable voltage detector

The power-on reset (POR) and power-down reset (PDR) circuits are integrated internally. This part of the circuit is always in working condition to ensure that the system works normally when the power supply voltage exceeds 2.0V.

When V_{DD} is lower than the set threshold ($V_{POR/PDR}$), the device remains in the reset state.

The device has a programmable voltage detector (PWD), which monitors the V_{DD} power supply and compares it with the threshold V_{PWD} . When V_{DD} is lower or higher than the threshold V_{PWD} , it will generate an interrupt. The PWD function is turned on by software.

The device has a programmable voltage detector (LVR), which monitors the V_{DD} power supply and compares it with the threshold V_{LVR} . When V_{DD} is lower or higher than the threshold V_{LVR} , it will generate Reset. The LVR function is turned on by software.

Table 4-6 is the value reference of $V_{POR/PDR}$ and $V_{PWD/LVR}$.

2.9 Low power mode

N32G052 is in RUN mode after system reset or power-on reset. When the CPU does not need to run, you can choose to enter a low power mode to save power.

N32G052 has the following four low power modes:

- SLEEP mode (the core is stopped, all peripherals including Cortex®-M0 core peripherals (such as NVIC, SysTick) are still running)
- STOP mode (most of the clocks are turned off, the voltage regulator is still running in low power mode)
- PD mode (V_{DDD} power down mode, V_{DD} retention, 2 WAKEUP IO and NRST can wake up)
- In addition, the following methods can also reduce the power consumption in RUN mode:
 - ◆ Reduce the system clock frequency
 - ◆ Turn off the unused peripheral clocks on the APB and AHB buses

2.10 DMA

The device integrates a flexible general-purpose DMA controller that supports 5 DMA channels to manage data transfers from memory to memory, peripherals to memory, and memory to peripherals.

Each channel has dedicated hardware DMA request logic, and each channel can be triggered by software. The transmission length, source address and destination address of each channel can be set separately by software.

DMA can be used with major peripherals: SPI, I2C, UART, TIMx (Advanced/General/Basic Timer), DAC, ADC.

2.11 Real time clock (RTC)

The RTC is a set of continuously running counters with a built-in calendar clock module that provides perpetual calendar functionality, as well as an alarm interrupt and periodic interrupt (minimum 2 clock cycles).

The RTC will not be reset by a system reset, nor will it be reset when woken up from STOP mode.

The RTC's drive clock can be selected from any of the clock sources: an internal low-power 32KHz RC oscillator, a high-speed internal clock divided by 128, or a high-speed external clock divided by 128. The RTC drive clock can be selected from an internal low-power 32KHz RC oscillator, a high-speed internal clock divided by 128, or a high-speed external clock divided by 128.

To compensate for clock deviations, the RTC clock can be calibrated by outputting a 256 Hz signal. The RTC has a 22-bit prescaler for the time base clock, which generates a 1-second long time reference. Additionally the RTC can be used to trigger a wake-up in a low-power state.

2.12 Timer and watch dog

Up to 1 advanced control timers, 4 general-purpose timers and 1 basic timers, 2 watchdog timers and 1 system tick timer.

The following table compares the functions of advanced control timer, general-purpose timer, basic timer and low power timer:

Table 2-1 Timer function comparison

| Timer | Counter resolution | Counter type | Prescaler | Capture/Compare channel | Complementary output |
|----------------|--------------------|-----------------------|-----------------------------|-------------------------|----------------------|
| TIM1 | 16-bit | Up Down Up/Down | Any integer between 1~65536 | 5 | support |
| TIM2 ~ TIM5 | 16-bit | Up Down Up/Down | Any integer between 1~65536 | 4 | Unsupported |
| TIM6 | 16-bit | Up | Any integer between 1~65536 | 0 | Unsupported |

2.12.1 Advanced-control timers (TIM1)

The advanced control timers (TIM1 and TIM8) is mainly used in the following occasions: counting the input signal, measuring the pulse width of the input signal and generating the output waveform, etc.

Advanced timers have complementary output function with dead-time insertion and brake function. Suitable for motor control.

- 16-bit auto-reload counters. (It can realize up-counting, down-counting, up/down counting).
- 16-bit programmable prescaler. (The frequency division factor can be configured with any value between 1 and 65536)
- Programmable Repetition Counter
- TIM1 up to 5 channels
- 4 capture/compare channels, the working modes are PWM output, Output compare, One-pulse mode output, Input capture

- The events that generate the interrupt/DMA are as follows:
 - ◆ Update event
 - ◆ Trigger event
 - ◆ Input capture
 - ◆ Output compare
 - ◆ Break input
- Complementary outputs with adjustable dead-time
 - ◆ For TIM1, channel 1,2,3,4 support this feature
- TIM1_CC5 COMP blanking
- Supports PWM-triggered ADC sampling
- Timer can be controlled by external signal
- Repeat counter that allows the timer register to be updated after a specified number of counter cycles

2.12.2 General-purpose timer (TIMx)

The general-purpose timers (TIM2/TIM3/TIM4/TIM5) is mainly used in the following occasions: counting the input signal, measuring the pulse width of the input signal and generating the output waveform, etc.

- 16-bit auto-reload counters. (It can realize up-counting, down-counting, up/down counting)
- 16-bit programmable prescaler. (The frequency division factor can be configured with any value between 1 and 65536)
- TIMx up to 4 channels
- Channel's working modes: PWM output, ouput compare, one-pulse mode output, input capture.
- The events that generate the interrupt/DMA are as follows:
 - ◆ Update event
 - ◆ Trigger event
 - ◆ Input capture
 - ◆ Output compare
- Timer can be controlled by external signal
- Supports incremental (quadrature) encoder and Hall sensor circuits for positioning
- TIM2 support for internal capture HSE, HSI_8M, LSI
- Input channels support digital filtering

2.12.3 Basic timer -TIM6

The basic timer contains a 16-bit counter.

- 16-bit auto-reload up-counting counters.
- 16-bit programmable prescaler. (The frequency division factor can be configured with any value between 1 and 65536)
- The events that generate the interrupt/DMA are as follows:
 - ◆ Update event
- Supports STOP mode wake-up: when the clock source is configured as LSI, STOP mode can be woken up by updating the interrupt (linked to EXTI20)

2.12.4 Systick timer (Systick)

This timer is dedicated to real-time operating systems and can also be used as a standard decrement counter.

It has the following characteristics:

- 24 bit decrement counter
- Automatic reloading function
- A maskable system interrupt is generated when the counter is 0
- Programmable clock source

2.12.5 Watchdog (WDG)

Support for two watchdog independent watchdog (IWDG) and window watchdog (WWDG). Two watchdogs provide increased security, time accuracy, and flexibility in use.

Independent Watchdog (IWDG)

The independent watchdog is based on a 12-bit decrepit counter and an 3-bit predivider. It is driven by a separate low-speed RC oscillator that remains active even if the master clock fails and operates in STOP modes. Once activated, if the dog is not fed (clears the watchdog counter) within the set time, the IWDG generates a reset when the counter counts to 0x000. It can be used to reset the entire system in the event of an application problem, or as a free timer to provide time-out management for applications. The option byte can be configured to start the watchdog software or hardware. Reset and low power wake up are available.

Window Watchdog (WWDG)

A window watchdog is usually used to detect software failures caused by an application deviating from the normal running sequence due to external interference or unforeseen logical conditions. Unless the decline counter value is flushed before the T6 bit becomes zero, the watchdog circuit generates an MCU reset when the preset time period is reached. If the 14-bit decrement counter value (in the control register) is flushed before the decrement counter reaches the window register value, then an MCU reset will also occur. This indicates that the decrement counter needs to be refreshed in a finite time window.

Main features:

- WWDG is driven by the clock generated after the APB1 clock is divided.
- Programmable free-running decrement counter.
- Conditional reset:
 - ◆ When the decrement counter is less than 0x40, a reset occurs (if the watchdog is started);
 - ◆ A reset occurs when the decrement counter is reloaded outside the window (if the watchdog is started);
- If the watchdog is enabled and interrupts are allowed, an early wake up interrupt (EWINT) occurs when the decrement counter equals 0x40, which can be used to reload the counter to avoid WWDG reset.

2.13 I2C bus interface (I2C)

The device integrates up to 2 independent I2C bus interfaces, which provide multi-host function and control all I2C bus-specific timing, protocol, arbitration and timeout. Supports multiple communication rate modes (up to 1MHz), supports DMA operations and is compatible with SMBus 2.0. The I2C module provides multiple functions, including CRC generation and verification, System Management Bus (SMBus), and Power Management Bus (PMBus).

The functions of the I2C interface are described as follows:

- This module can be used as master device or slave device;
- I2C master device function:
 - ◆ Generate a clock;
 - ◆ Generate start and stop signals;

- Function of I2C slave device
 - ◆ Programmable address detection;
 - ◆ The I2C interface supports 7-bit or 10-bit addressing and dual-slave address response capability in 7-bit slave mode.
 - ◆ Stop bit detection;
- Generate and detect 7-bit / 10-bit addresses and broadcast calls;
- Support different communication speeds;
 - ◆ Standard speed (up to 100 kHz);
 - ◆ Fast (up to 400 kHz);
 - ◆ Fast + (up to 1MHz);
- Status flags:
 - ◆ Transmitter/receiver mode flag;
 - ◆ Byte transmit complete flag;
 - ◆ I2C bus busy flag;
- Error flags:
 - ◆ Arbitration is missing in Master Mode.
 - ◆ Acknowledge (ACK) error after address/data transfer;
 - ◆ Error start or stop condition detected
 - ◆ Overrun or underrun when disable extend clock function;
- Supported interrupt vectors: event interrupts and error interrupts
- Optional extend clock function
- Supports digital and analog filtering
- Generation or verification of configurable PEC(Packet error detection)
 - ◆ In transmit mode, the PEC value can be transmitted as the last byte
 - ◆ PEC error check for the last received byte
- SMBus 2.0 compatible
 - ◆ Timeout delay for 25 ms clock low
 - ◆ 10 ms accumulates low clock extension time of master device
 - ◆ 25 ms accumulates low clock extension time of slave device
 - ◆ PEC generation/verification of hardware with ACK control
 - ◆ Support address resolution protocol (ARP)
- Compatible with the PMBus

2.14 Universal asynchronous transceiver (UART)

N32G052 series products integrate up to 5 universal asynchronous transceivers (UART1 / UART2 / UART3 / UART4 / UART5).

UART interface sends and receives at configurable baud rates and also supports continuous communication via DMA. UART supports multiprocessor communication, LIN mode, single-wire half-duplex communication, and IrDA SIR ENDEC functions.

Main features of UART are as follows:

- Full duplex, asynchronous communication
- Supports single-wire half-duplex communication
- Baud rate is configurable, up to 4Mbit/s
- Programmable data word length (8 or 9 bits)
- Configurable stop bit, supporting 1 or 2 stop bits
- Hardware generated parity bit and parity bit checking
- DMA sending and receiving
- Multiprocessor communication: if the address does not match, it enters silent mode, which can be awakened by idle bus detection or address identification.
- Serial Infrared Protocol (IrDA SIR) encoding and decoding, and provides two modes of operation: normal and low power consumption.
- supports LIN mode
- Multiple error detection: data overflow error, frame error, noise error, check error.
- Multiple interrupt requests: send data register empty, send complete, data received, data overflow, bus idle, check error, LIN mode break frame detection, and noise flag/overflow error/frame error in multi-buffer communication.

Mode configuration:

| UART modes | UART1 | UART2 | UART3 | UART4 | UART5 |
|--------------------------------|---------|---------|---------|---------|---------|
| Asynchronous mode | support | support | support | support | support |
| Multiprocessor communication | support | support | support | support | support |
| Half duplex (single wire mode) | support | support | support | support | support |
| IrDA | support | support | support | support | support |
| LIN | support | support | support | support | support |

2.15 Serial peripheral interface (SPI)

3x SPI interfaces. SPI allow the chip to communicate with peripheral devices in a half/full duplex, synchronous, serial manner. This interface can be configured in master mode and provides a communication clock (SCLK) for external slave devices. Interfaces can also work in a multi-master configuration. It can be used for a variety of purposes, including two-wire simplex synchronous transmission using a bidirectional data wire.

The main functions of SPI interfaces are as follows:

- 3-wire full-duplex synchronous transmission;
- two-wire simplex synchronous transmission with or without a third bidirectional data wire;
- 8 or 16 bit transmission frame format selection;
- Master or slave operations;
- Support multi-master mode;
- 8 master mode baud rate prescaling factors (up to $f_{PCLK}/2$);
- Slave mode frequency (max. $f_{PCLK}/2$);
- Fast communication between master mode and slave mode;
- NSS can be managed by software or hardware in both master and slave modes: dynamic change of master/slave

modes;

- Programmable clock polarity and phase;
- Programmable data order, MSB before or LSB before;
- Dedicated send and receive flags that trigger interrupts;
- SPI bus busy flag;
- Hardware CRC for reliable communication;
 - ◆ In send mode, the CRC value can be sent as the last byte;
 - ◆ In full-duplex mode, CRC is automatically performed on the last byte received.
- Master mode failures, overloads, and CRC error flags that trigger interrupts
- Single-byte send and receive buffer with DMA capability: generates send and receive requests
- Maximum interface speed: 16Mbps

2.16 Controller area network (CAN)

1x CAN bus interface compatible with 2.0A and 2.0B (active) specifications, with bit rates up to 1Mbps. It can receive and send standard frames with 11-bit identifiers, as well as extended frames with 29-bit identifiers.

Main features:

- Support CAN protocol 2.0A and 2.0B active mode;
- Baud rate up to 1Mbps;
- Supports time-triggered communication
- Send
 - ◆ Three sending mailboxes
 - ◆ The priority of sent packets can be configured by software
 - ◆ Records the timestamp of the time when the SOF was sent
- Receive
 - ◆ Level 3 depth of 2 receiving FIFO
 - ◆ Variable filter group:
 - ◆ There are 14 filter groups
 - ◆ Identifier list
 - ◆ The FIFO overflow processing mode is configurable
 - ◆ Record the time stamp of the receipt of the SOF
- Time-triggered communication mode
 - ◆ Disable automatic retransmission mode
 - ◆ 16-bit free run timer
 - ◆ Timestamp can be sent in the last 2 bytes of data
- Management
 - ◆ Interrupt masking
 - ◆ The mailbox occupies a separate address space to improve software efficiency

2.17 General purpose input/output (GPIO)

Up to 61 GPIO, divided into 4 groups (GPIOA/GPIOB/GPIOC/ GPIOF), GPIOA/ GPIOB/GPIOC have 16 pins, GPIOD has 13 pins. Each GPIO pin can be configured by software as output (push-pull or open drain), input (with or without pull-up or pull-down) or alternate peripheral function ports (output/input), most GPIO pins are shared with digital or analog reuse peripherals, some IO pins are also reused with clock pins. Except for ports with analog input function, all GPIO pins have the ability to pass through a large current.

GPIO ports have the following characteristics:

- Each GPIO port can be individually configured into multiple modes by software
 - ◆ Input floating
 - ◆ Input pull-up
 - ◆ Input pull-down
 - ◆ Analog function
 - ◆ Open drain output and pull-up/pull-down can be configured
 - ◆ Push-pull output and pull-up/pull-down can be configured
 - ◆ Push-pull alternate function and pull-up/pull-down can be configured
 - ◆ Open-drain alternate function and pull-up/pull-down can be configured
- Individual bit set or bit clear function
- All IO supports external interrupt function
- All IO supports low power mode wake-up, rising or falling edge configurable
 - ◆ 16 EXTI can be used to wake up from SLEEP or STOP mode, and all I/Os can be reused as EXTI
 - ◆ NRST/PA0/ PA2 three wake-up IO can be used for PD mode wake-up, the maximum I/O filter time is 1us
- Support software remapping I/O alternate function
- Support GPIO lock mechanism, reset the lock state to clear

Each I/O port bit can be programmed arbitrarily, but I/O port registers must be accessed as 32-bit words (16-bit half-word or 8-bit byte access is not allowed). The following figure shows the basic structure of an I/O port.

2.18 Analog/digital converter (ADC)

The 12-bit ADC is a high-speed analog-to-digital converter using successive approximation. There are a total of 17 channels that can measure 15 external and 2 internal signal sources. The A/D conversion channels of each channel can be executed in single, continuous, and sweep modes. The ADC conversion values are stored (left-aligned/right-aligned) in 16-bit data registers. An analog watchdog can be used to detect if the input voltage is within the user-defined high/low thresholds and the ADC's input clock has a maximum frequency of 24 MHz.

The main features of the ADC are described below:

- Supports 1 ADC, supports single-ended inputs, and can measure up to 15 external and 2 internal signal sources
- Supports 12-bit resolution and a maximum sampling rate of 1MSPS
- ADC clock source is divided into working clock source and timing clock source
 - ◆ HSI, PLL, AHB as ADC_CLK working clock source, up to 24M
 - ◆ HSI or HSE as ADC_1MCLK timing clock source, used for internal timing function, frequency must be configured to 1MHz
- Timer-triggered sampling support
- Interrupt can be triggered when conversion is completed or analog watchdog event.

- Conversion mode
 - ◆ Single conversion
 - ◆ Continuous conversion
 - ◆ Scan mode
- Scan mode supports up to any 5 channels, each with a separate result data register.
- Sampling intervals can be programmed uniformly for all channels.
- Can be externally triggered for rule-based conversion.
- The ADC operates with voltages between 2.4V and 5.5V.
- ADC supports conversion between 0 and V_{DD}.
- ADC supports DMA operation

2.19 Digital/Analog converter (DAC)

DAC is a digital/analog converter, mainly digital input, voltage output. DAC data has two modes, 8bit or 12bit, and supports DMA function. When the DAC is configured in 12bit mode, the DAC data can be left-aligned or right-aligned; when the DAC is configured in 8bit mode, the DAC data can be right-aligned. There are 1 DAC output channels with independent converters. AVREFP(PB2) is input through the pins as the DAC reference voltage, which makes the converted data of the DAC more accurate.

- 1 independent DAC converter corresponding to 1 output channel
- Monotonic output
- Supports 8-bit or 12-bit output, with right-aligned and left-aligned data in 12-bit mode.
- Synchronized update
- Support DMA function
- Noise wave and triangle waveform generation
- Input reference voltage AVREFP
- External event triggered conversion

2.20 Analog comparator (COMP)

Embedded with 4 comparators, it can be used as a stand-alone device (all ports of comparators lead to I/O) or combined with timers, which can be used in motor control applications to form cycle-by-cycle current control in conjunction with the PWM output from timers.

The main functions of the comparator are as follows:

- Shares the internal reference inputs of two independent 6bit DACs
- Supports filtered clock, filtered reset
- Configurable high and low output polarity.
- Hysteresis configuration configurable none, low, medium, high
- Comparison results can be output to I/O ports or trigger timers for capturing events, OCREF_CLR events, braking events, generating interrupts
- Input channels can be re-selected for I/O ports, dedicated 6bit DAC, channel outputs for general purpose 12bit DACs
- Read-only or read-write configurable, requires reset to unlock in case of locking.
- Blanking support, Blanking source can be configured to generate Blanking.

- COMP1/COMP2, COMP3/COMP4 can form a window comparator.
- Wake up the system from Sleep mode by generating an interrupt.
- Configurable filter window size
- Configurable filter threshold size

2.21 Segment LCD Driver (Segment LCD)

The LCD controller is suitable for monochrome passive segmented liquid crystal displays (Segment LCD) with up to 8 common terminals (COM) and 32 segment terminals (SEG), the exact number of terminals depends on the pinout of the different packages, which can be referred to in the datasheet. The Segment LCD consists of a number of segments, which can be either illuminated or extinguished. Each segment contains a layer of liquid crystal molecules aligned between two electrodes. When a voltage above the threshold voltage is applied to the liquid crystal, the corresponding segment is visible. To avoid electrophoretic effects in the liquid crystal, the zone voltage must be AC.

Key Features:

- Frame rate is configurable.
- Duty Cycle Configurable: Supports static, 1/2, 1/3, 1/4 and 1/8 duty cycles.
- Voltage bias is configurable: supports static, 1/2, 1/3, and 1/4 bias.
- Double buffering mechanism allows the user to update the data in the display memory registers (pixel active/inactive information) at any time.
- LCD clock source selectable: HSE/16 or HSI_8M/8.
- Two contrast control methods: Adjust the dead time of up to 7 phase cycles between frames; Adjust the VLCD to vary in the range of VLCDmin~VLCDmax (only when using the internal boost converter).
- Built-in resistor network is used to generate LCD intermediate voltage, which can be configured via software to match capacitive loads on the LCD panel.
- Built-in voltage output buffer
- Built-in phase inversion to reduce electromagnetic interference (EMI) and power consumption.
- Supports blinking function: 1, 2, 3, 4, 8 or all pixels can be configured to blink at a specified frequency (0.5Hz, 1Hz, 2Hz or 4Hz)
- Pins used for SEG and COM functions should be configured as corresponding AFIOs.

2.22 Temperature Sensors (TS)

The temperature sensor produces a voltage that varies linearly with temperature over a conversion range of 2.4V < VDDA < 5.5V. The temperature sensor is internally connected to the input channel of ADC_IN15, which is used to convert the output of the temperature sensor to a digital value.

2.23 BEEPER

The BEEPER module supports complementary outputs that can generate periodic signals to drive an external passive buzzer. It is used to generate beeps or alarm audible sounds.

2.24 Cyclic redundancy check calculation unit (CRC)

Integrating the CRC16 function, the cyclic redundancy check (CRC) computation unit is based on a fixed generating polynomial to get the result of any CRC computation. In numerous applications, CRC-based techniques are used to verify the consistency of data transmission or storage.

The main properties of CRC are as follows:

- CRC16: supports polynomials $X^{16}+X^{15}+X^2+X^0$
- CRC16 calculation time: 1 AHB clock cycle (HCLK)
- Initial value of cyclic redundancy calculation is configurable
- Supports DMA mode

2.25 Unique device serial number (UID)

The N32G052 series products have two built-in unique device serial numbers of different lengths, the 96-bit UID (Unique device ID) and the 128-bit UCID (Unique Customer ID), which are stored in the system configuration block of the flash memory, and the information they contain is written at the factory and is guaranteed to be unique to N32G052 series any one microcontroller in any case is unique, the user application or external devices can be read through the CPU or SWD interface, can not be modified.

UID is 96 bits, usually used as a serial number or as a password, when writing flash memory, this unique identifier is combined with software encryption and decryption algorithms to further improve the security of the code within the flash memory.

The UCID is 128 bits and complies with the National Technical Chip Serial Number Definition, which contains chip production and version related information.

2.26 Serial wire SWD debug port (SWD)

Embedded Arm SWD Interface.

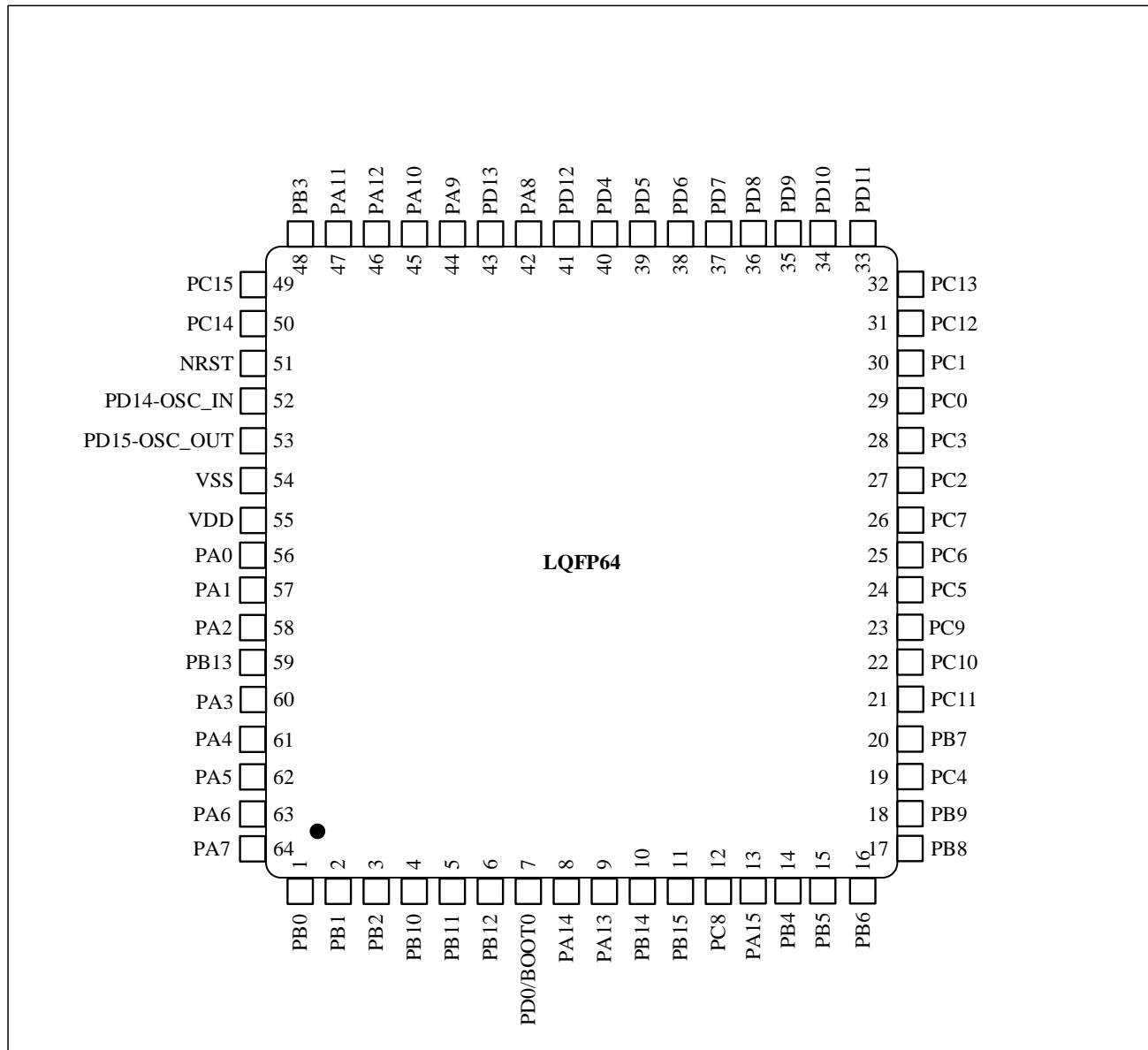
3 Pin descriptions

3.1 Pinouts

3.1.1 LQFP64

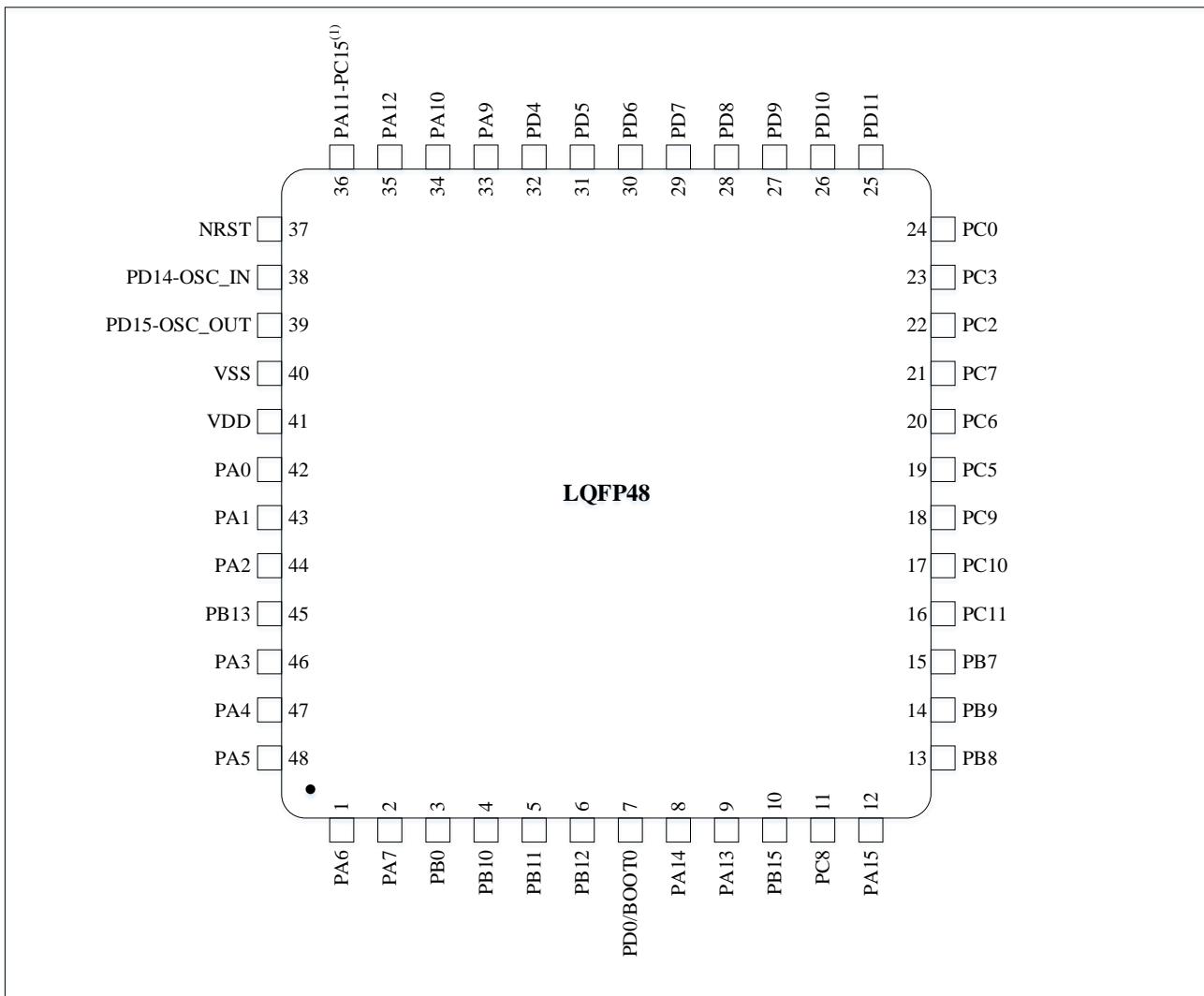
N32G052RBL7/ N32G052RBL7B/ N32G052RBL7C pin ordering is the same.

Figure 3-1 N32G052 Series LQFP64 pinouts



3.1.2 LQFP48

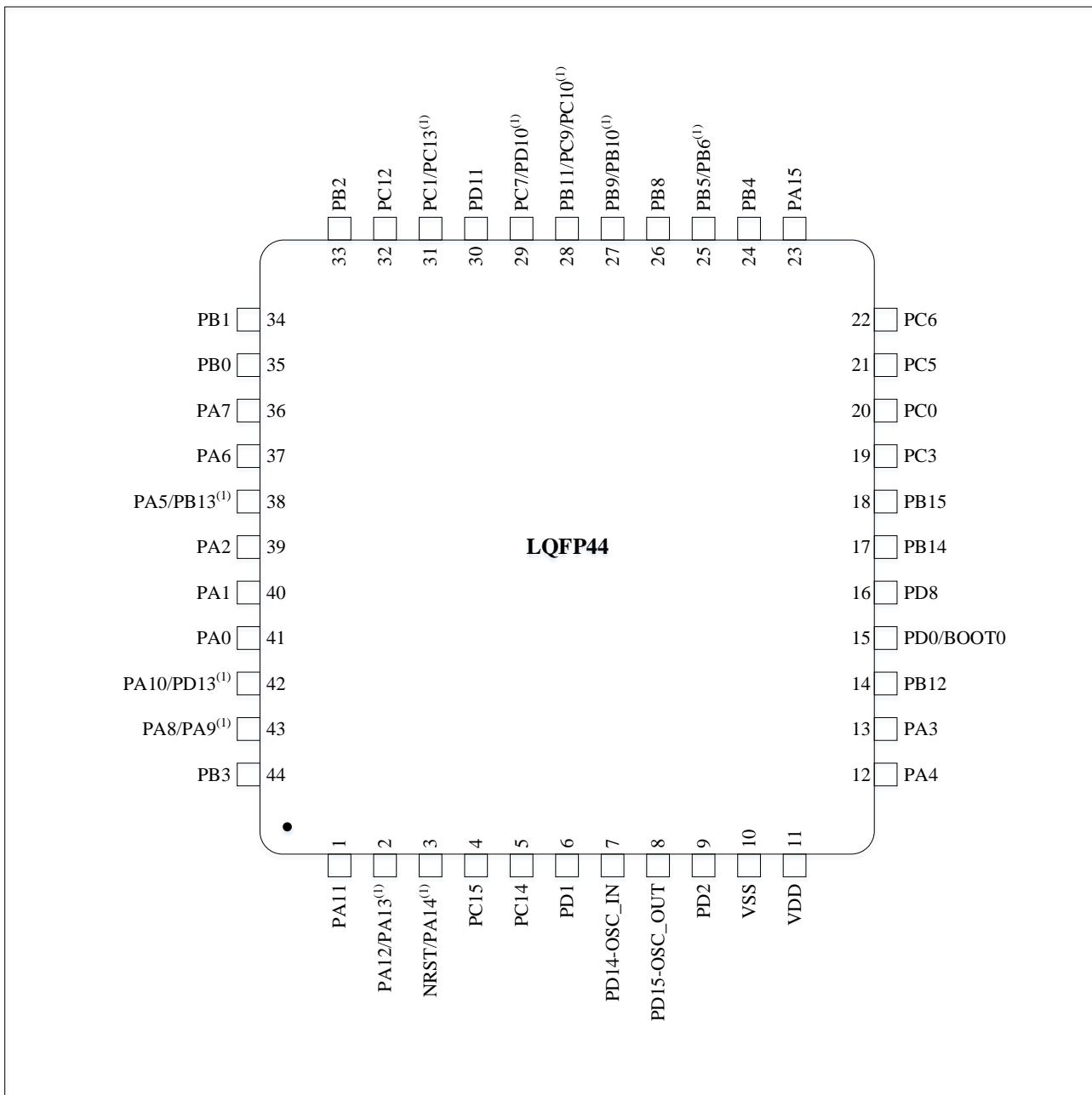
Figure 3-2 N32G052 Series LQFP48 pinouts



1. 36pin is a combination IO, which is a combination of PA11 and PC15; Only one IO can be used simultaneously, and other IOs on the same pin must be configured in analog mode to avoid affecting the IO being used.

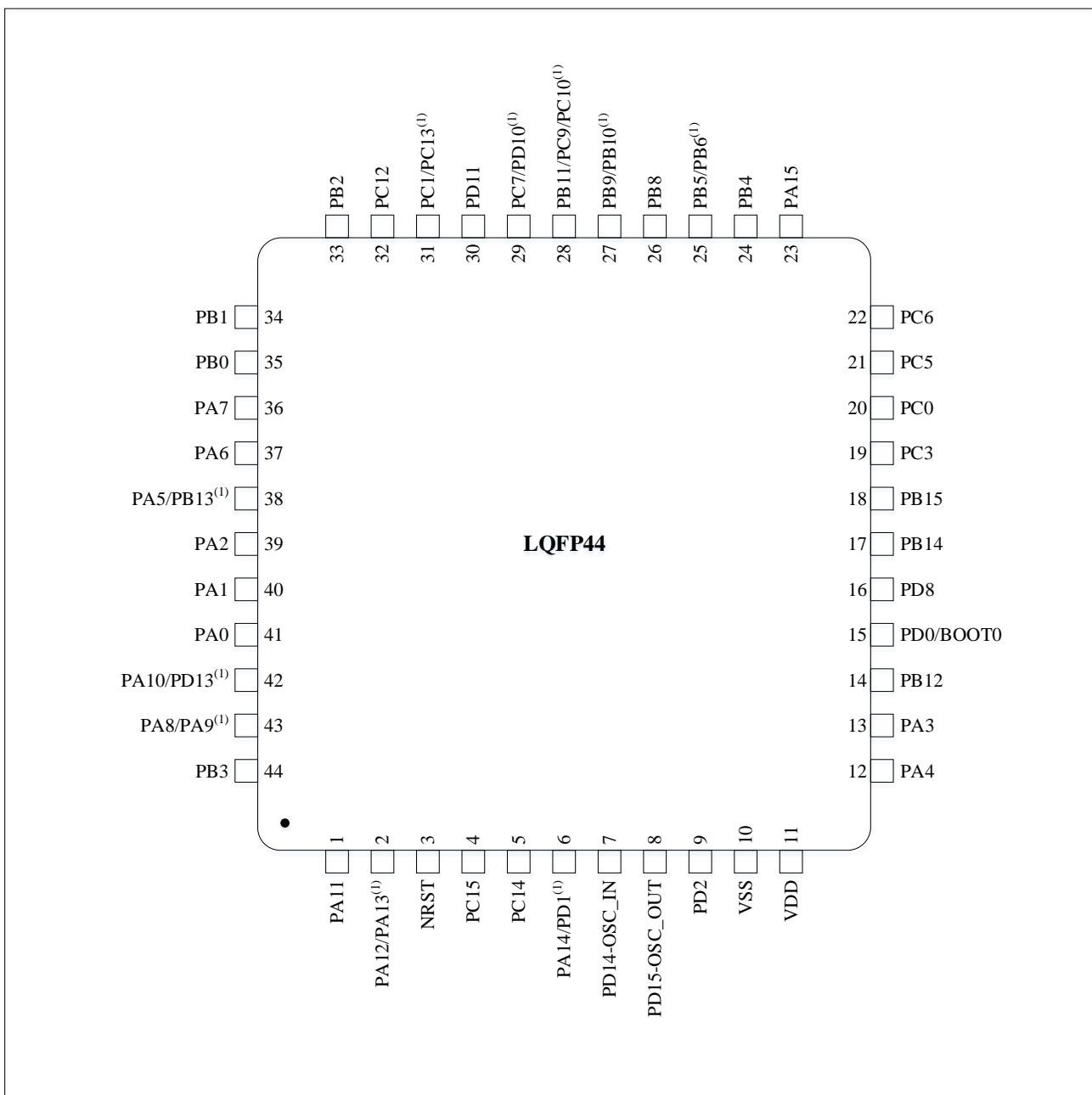
3.1.3 LQFP44

Figure 3-3 N32G052 Series LQFP44 pinouts 1



1. 2pin, 3pin, 25pin, 27pin, 28pin, 29pin, 31pin, 38pin, 42pin, and 43pin are combined IO, where the 2pin is a combination of PA12 and PA13, where the 3pin is a combination of NRST and PA14 (PA14 is only used for debugging and is not recommended for production design), where the 25pin is a combination of PB5 and PB6, where the 27pin is a combination of PB9 and PB10, where the 28pin is a combination of PB11, PC9, and PC10, where the 29pin is a combination of PC1 and PC13, where the 31pin is a combination of PC1 and PC13, where the 38pin is a combination of PA5 and PB13 , where the 42pin is a combination of PA10 and PD13, and the 43pin is a combination of PA8 and PA9; Only one IO can be used simultaneously, and other IOs on the same pin must be configured in analog mode to avoid affecting the IO being used.

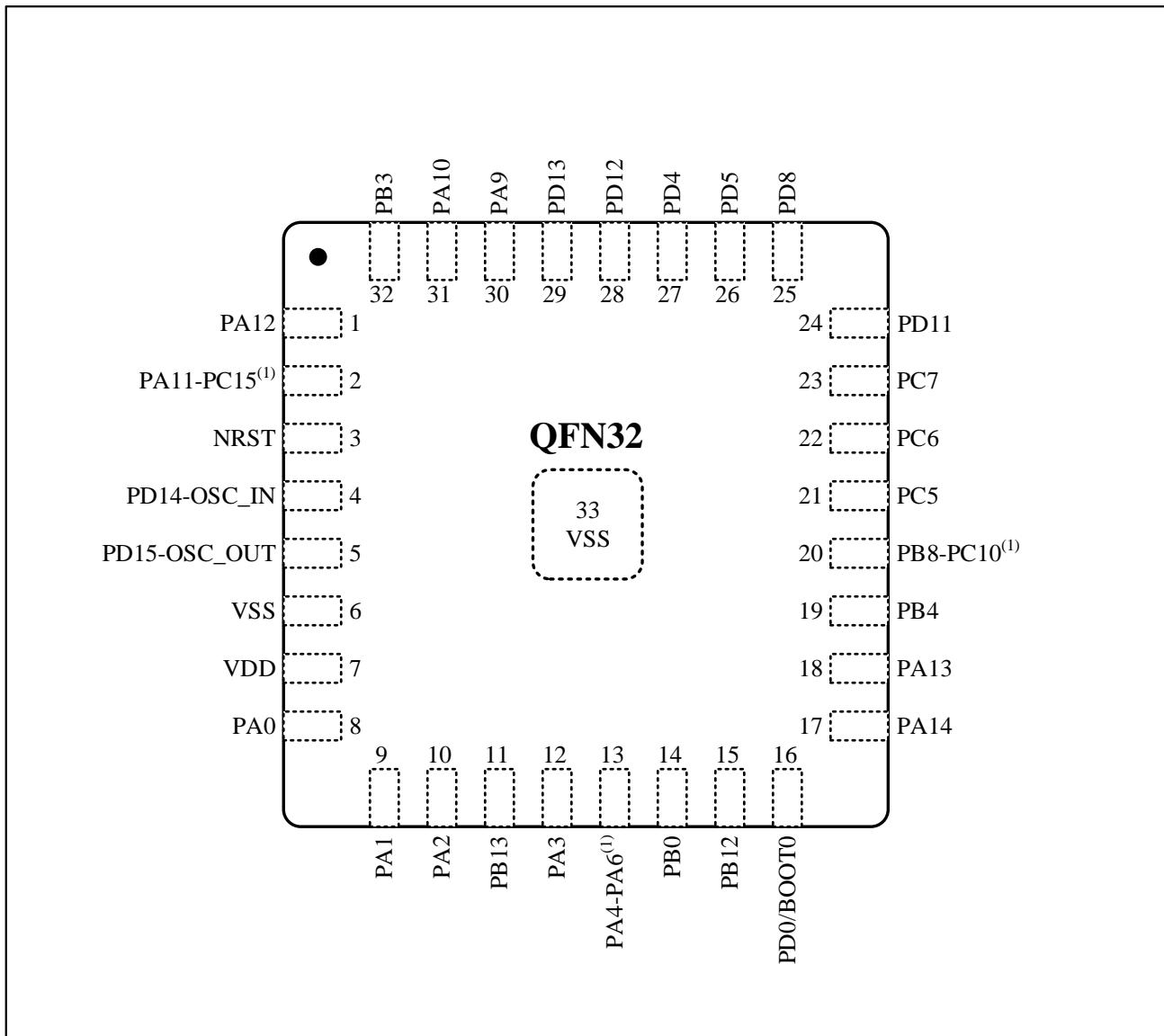
Figure 3-4 N32G052 Series LQFP44 pinouts 2



1. 2pin, 6pin, 25pin, 27pin, 28pin, 29pin, 31pin, 38pin, 42pin, and 43pin are combined IO, where the 2pin is a combination of PA12 and PA13, where the 6pin is a combination of PD1 and PA14, where the 25pin is a combination of PB5 and PB6, where the 27pin is a combination of PB9 and PB10, where the 28pin is a combination of PB11, PC9, and PC10, where the 29pin is a combination of PC7 and PD10, where the 31pin is a combination of PC1 and PC13, where the 38pin is a combination of PA5 and PB13 , where the 42pin is a combination of PA10 and PD13, and the 43pin is a combination of PA8 and PA9; Only one IO can be used simultaneously, and other IOs on the same pin must be configured in analog mode to avoid affecting the IO being used.

3.1.4 QFN32

Figure 3-5 N32G052 Series QFN32 pinouts



1. pin-2, pin-13 and pin-20 are combination IOs, where pin-2 is a combination of PA11 and PC15, where pin-13 is a combination of PA4 and PA6, and where pin-20 is a combination of PB8 and PC10; Only one of the IOs can be used at the same time, and other IOs on the same pin must be configured in analogue mode, so as not to affect the IOs being used. IOs in use.

3.2 Pin definitions

For details of alternate functions for IO, please refer to the "Alternate function" section within the "GPIO and AFIO" chapter of the User Manual.

Table 3-1 Pin definitions

| Package | | | | | Pin name (function after reset) | Type ⁽¹⁾ | IO ⁽²⁾ | Fail- safe ⁽⁴⁾ | Alternate functions ⁽³⁾ | |
|-----------|-------------------|-------------------|------------|------------|--|---------------------|-------------------|------------------------------|--|-----------------------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 14 | 35 | 35 | 3 | 1 | PB0 | I/O | TC | N | LCD SEG0 TIM2_CH1 EVENTOUT | ADC_IN8 COMP1_INM |
| - | 34 | 34 | - | 2 | PB1 | I/O | TC | N | LCD SEG1 | ADC_IN9 COMP1_INP |
| - | 33 | 33 | - | 3 | PB2 | I/O | TC | N | LCD SEG2 | ADC_IN10 COMP2_INM |
| - | 27 ⁽⁵⁾ | 27 ⁽⁵⁾ | 4 | 4 | PB10 | I/O | TC | N | LCD SEG3 I2C1_SCL I2C2_SCL SPI1_SCK SPI1_MOSI SPI2_SCK SPI3_SCK UART1_TX EVENTOUT | ADC_IN11 COMP2_INP |
| - | 28 ⁽⁵⁾ | 28 ⁽⁵⁾ | 5 | 5 | PB11 | I/O | TC | N | LCD SEG4 I2C1_SDA I2C2_SDA SPI1_MISO SPI1_MOSI SPI2_MOSI SPI3_MOSI UART1_RX UART2_RX | ADC_IN12 |
| 15 | 14 | 14 | 6 | 6 | PB12 | I/O | TC | N | LCD SEG5 TIM1_CH4N TIM2_CH3 SPI1_SCK SPI1_MISO SPI2_MISO SPI3_MISO UART2_TX EVENTOUT | ADC_IN13 |
| 16 | 15 | 15 | 7 | 7 | PD0 | I/O | TC | N | LCD SEG6 TIM2_CH2 SPI1_NSS BOOT0 | - |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-----------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|---|------------------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 17 | 3 ⁽⁵⁾ | 6 ⁽⁵⁾ | 8 | 8 | PA14 | I/O | TC | N | LCD SEG7 TIM1 ETR TIM1 CH4N TIM2 CH1 UART4 TX SWCLK | - |
| 18 | 2 ⁽⁵⁾ | 2 ⁽⁵⁾ | 9 | 9 | PA13 | I/O | TC | N | LCD SEG8 TIM1 CH4 TIM2 CH4 I2C2 SMBA UART4 RX SWDIO Beeper OUT MCO | - |
| - | 17 | 17 | - | 10 | PB14 | I/O | TC | N | LCD SEG9 TIM1 CH2N TIM2 CH2 UART5 TX Beeper OUT MCO | - |
| - | 18 | 18 | 10 | 11 | PB15 | I/O | TC | N | LCD SEG10 TIM1 CH3N UART5 RX | RTC_REFCL KIN |
| - | - | - | 11 | 12 | PC8 | I/O | TC | N | LCD SEG11 TIM3 CH3 TIM5 ETR TIM5 CH3 TIM5 CH4 I2C2 SMBA | - |
| - | 23 | 23 | 12 | 13 | PA15 | I/O | TC | N | LCD SEG12 TIM1 ETR TIM5 ETR TIM5 CH1 TIM5 CH2 EVENTOUT | - |
| 19 | 24 | 24 | - | 14 | PB4 | I/O | TC | N | LCD SEG13 TIM5 CH4 TIM5 CH3 UART2 TX EVENTOUT | COMP3 OUT |
| - | 25 ⁽⁵⁾ | 25 ⁽⁵⁾ | - | 15 | PB5 | I/O | TC | N | LCD SEG14 TIM5 CH1 TIM5 CH2 UART2 RX | - |
| - | 25 ⁽⁵⁾ | 25 ⁽⁵⁾ | - | 16 | PB6 | I/O | TC | N | LCD SEG15 TIM2 CH4 TIM4 CH1 | COMP1 OUT |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-------------------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|---|-----------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 20 ⁽⁵⁾ | 26 | 26 | 13 | 17 | PB8 | I/O | TC | N | LCD SEG16 TIM4_CH4 TIM4_CH3 I2C1_SCL I2C2_SCL UART3_TX UART5_TX RTC_TAMP3 | COMP1_OUT |
| - | 27 ⁽⁵⁾ | 27 ⁽⁵⁾ | 14 | 18 | PB9 | I/O | TC | N | LCD SEG17 TIM2_ETR TIM4_CH4 I2C1_SDA I2C2_SDA SPI1_NSS SPI2_NSS UART3_RX UART5_RX EVENTOUT | COMP2_OUT |
| - | - | - | - | 19 | PC4 | I/O | TC | N | LCD SEG18 TIM4_ETR I2C1_SMBA SPI2_NSS EVENTOUT | - |
| - | - | - | 15 | 20 | PB7 | I/O | TC | N | LCD SEG19 TIM4_CH2 TIM4_CH3 I2C1_SMBA | - |
| - | - | - | 16 | 21 | PC11 | I/O | TC | N | LCD SEG20 TIM3_CH1 TIM3_CH2 I2C2_SDA Beeper_OUT | - |
| 20 ⁽⁵⁾ | 28 ⁽⁵⁾ | 28 ⁽⁵⁾ | 17 | 22 | PC10 | I/O | TC | N | LCD SEG21 I2C2_SCL UART3_TX | COMP4_OUT |
| - | 28 ⁽⁵⁾ | 28 ⁽⁵⁾ | 18 | 23 | PC9 | I/O | TC | N | LCD SEG22 TIM3_CH4 I2C2_SMBA UART3_RX | - |
| 21 | 21 | 21 | 19 | 24 | PC5 | I/O | TC | N | LCD SEG23 TIM3_ETR I2C1_SCL I2C2_SCL SPI1_SCK SPI2_SCK SPI3_SCK | COMP4_OUT |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-----------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|---|--------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 22 | 22 | 22 | 20 | 25 | PC6 | I/O | TC | N | LCD SEG24 TIM3_CH1 I2C1_SCL I2C2_SCL I2C1_SDA I2C2_SDA SPI1_MOSI SPI2_MOSI SPI3_MOSI | - |
| 23 | 29 ⁽⁵⁾ | 29 ⁽⁵⁾ | 21 | 26 | PC7 | I/O | TC | N | LCD SEG25 TIM3_CH2 I2C1_SDA I2C2_SDA SPI1_MISO SPI2_MISO SPI3_MISO | - |
| - | - | - | 22 | 27 | PC2 | I/O | TC | N | LCD SEG26 SPI2_MOSI SPI1_MISO SPI2_MISO SPI3_MISO UART2_TX EVENTOUT | - |
| - | 19 | 19 | 23 | 28 | PC3 | I/O | TC | N | LCD SEG27 I2C1_SDA I2C2_SDA SPI2_MISO SPI1_MOSI SPI2_MOSI SPI3_MOSI UART2_RX EVENTOUT | - |
| - | 20 | 20 | 24 | 29 | PC0 | I/O | TC | N | LCD SEG28 I2C1_SCL I2C2_SCL SPI1_SCK SPI2_SCK SPI3_SCK EVENTOUT | - |
| - | 31 ⁽⁵⁾ | 31 ⁽⁵⁾ | - | 30 | PC1 | I/O | TC | N | LCD SEG29 TIM4_CH1 TIM4_CH2 SPI2_NSS SPI3_NSS EVENTOUT | - |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-----------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|--|-----------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| - | 32 | 32 | - | 31 | PC12 | I/O | TC | N | LCD SEG30 TIM1_CH1 TIM1_CH2 TIM4_ETR UART5_TX | - |
| - | 31 ⁽⁵⁾ | 31 ⁽⁵⁾ | - | 32 | PC13 | I/O | TC | N | LCD SEG31 TIM3_ETR I2C1_SCL I2C2_SCL SPI2_SCK RTC_OUT RTC_TAMP1 | - |
| 24 | 30 | 30 | 25 | 33 | PD11 | I/O | TC | N | LCD COM7 LCD SEG32 TIM4_CH1 I2C1_SDA I2C2_SDA SPI2_MOSI UART1_RX UART4_RX | - |
| - | 29 ⁽⁵⁾ | 29 ⁽⁵⁾ | 26 | 34 | PD10 | I/O | TC | N | LCD COM6 LCD SEG33 TIM3_CH1 SPI2_MISO UART1_TX UART4_TX | - |
| - | - | - | 27 | 35 | PD9 | I/O | TC | N | LCD COM5 LCD SEG34 TIM1_CH3N UART5_RX CAN_TX | - |
| 25 | 16 | 16 | 28 | 36 | PD8 | I/O | TC | N | LCD COM4 LCD SEG35 TIM1_CH3 UART5_TX CAN_RX | - |
| - | - | - | 29 | 37 | PD7 | I/O | TC | N | LCD COM3 LCD SEG36 TIM1_CH2N SPI1_NSS | COMP3_INP |
| - | - | - | 30 | 38 | PD6 | I/O | TC | N | LCD COM2 TIM1_CH2 SPI1_SCK | COMP3_INM |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-----------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|---|-----------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 26 | - | - | 31 | 39 | PD5 | I/O | TC | N | LCD_COM1 TIM1_CH1N TIM3_CH3 TIM3_CH4 SPI1_MISO UART4_TX UART5_RX EVENTOUT | COMP4_INP |
| 27 | - | - | 32 | 40 | PD4 | I/O | TC | N | LCD_COM0 TIM1_CH1 TIM1_CH3 TIM1_CH4 I2C1_SMBA SPI1_MOSI UART4_RX EVENTOUT | COMP4_INM |
| 28 | - | - | - | 41 | PD12 | I/O | TC | N | TIM1_CH4N TIM3_CH3 TIM3_CH4 I2C1_SCL I2C2_SCL SPI3_NSS | - |
| - | 43 ⁽⁵⁾ | 43 ⁽⁵⁾ | - | 42 | PA8 | I/O | TC | N | TIM3_CH1 TIM3_CH2 I2C1_SCL I2C2_SCL I2C1_SDA I2C2_SDA SPI3_SCK UART3_RX | - |
| 29 | 42 ⁽⁵⁾ | 42 ⁽⁵⁾ | - | 43 | PD13 | I/O | TC | N | TIM4_CH3 TIM5_CH3 TIM5_CH4 I2C1_SDA I2C2_SDA SPI3_MISO UART3_TX UART3_RX | - |
| 30 | 43 ⁽⁵⁾ | 43 ⁽⁵⁾ | 33 | 44 | PA9 | I/O | TC | N | TIM1_CH1 TIM1_CH2 TIM1_CH3N SPI1_MISO SPI3_MOSI UART3_TX UART1_TX UART4_TX | COMP3_INM |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|------------------|-------------------|-------------------|-------------------|------------|--|--------------------------|------------------------|-----------------------------------|---|------------------------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 31 | 42 ⁽⁵⁾ | 42 ⁽⁵⁾ | 34 | 45 | PA10 | I/O | TC | N | TIM1_CH4 TIM2_CH1 TIM4_CH1 TIM4_CH2 I2C1_SDA I2C2_SDA SPI1_MOSI UART1_RX UART4_RX | COMP3_INP COMP3_OUT |
| 1 | 2 | 2 | 35 | 46 | PA12 | I/O | TC | N | TIM1_ETR TIM2_CH3 TIM5_CH1 TIM5_CH2 I2C1_SCL I2C2_SCL SPI1_SCK CAN_RX EVENTOUT | COMP4_INP |
| 2 ⁽⁵⁾ | 1 | 1 | 36 ⁽⁵⁾ | 47 | PA11 | I/O | TC | N | TIM1_BKIN TIM1_CH3 TIM1_CH4N TIM2_CH2 CAN_TX EVENTOUT | COMP4_INM |
| 32 | 44 | 44 | - | 48 | PB3 | I/O | TC | N | CAN_TX EVENTOUT MCO | ADC_IN14 |
| 2 ⁽⁵⁾ | 4 | 4 | 36 ⁽⁵⁾ | 49 | PC15 | I/O | TC | N | - | - |
| - | 5 | 5 | - | 50 | PC14 | I/O | TC | N | TIM2_CH3 | - |
| 3 | 3 ⁽⁵⁾ | 3 | 37 | 51 | NRST | I/O | RS T | N | NRST | - |
| 4 | 7 | 7 | 38 | 52 | PD14- OSC_IN | I/O | TC | N | TIM2_CH4 TIM4_CH4 I2C1_SDA | OSC_IN |
| 5 | 8 | 8 | 39 | 53 | PD15- OSC_O UT | I/O | TC | N | I2C1_SCL | OSC_OUT |
| - | 6 | 6 ⁽⁵⁾ | - | - | PD1 | I/O | TC | N | - | - |
| - | 9 | 9 | - | - | PD2 | I/O | TC | N | SPI3_NSS | - |
| 6 | 10 | 10 | 40 | 54 | VSS | S | TC | - | - | VSS |
| 7 | 11 | 11 | 41 | 55 | VDD | S | TC | - | - | VDD |
| 8 | 41 | 41 | 42 | 56 | PA0 | I/O | TC | N | TIM5_CH1 SPI3_MOSI RTC_TAMP2 WAKUP0 | ADC_IN0 |

| Package | | | | | Pin name (function after reset) | Type ^(1) | IO ^(2) | Fail- safe ^(4) | Alternate functions ⁽³⁾ | |
|-------------------|-------------------|-------------------|------------|------------|--|--------------------------|------------------------|-----------------------------------|---|-----------------------------------|
| QFN3 2 | LQFP 44 | LQFP4 4-A | LQFP 48 | LQFP 64 | | | | | Digital | Analog |
| 9 | 40 | 40 | 43 | 57 | PA1 | I/O | TC | N | TIM1_BKIN TIM5_CH2 SPI3_MISO RTC_REFCL KIN EVENTOUT | ADC_IN1 |
| 10 | 39 | 39 | 44 | 58 | PA2 | I/O | TC | N | TIM5_CH3 I2C1_SMBA UART1_TX WAKUP1 | ADC_IN2 COMP1_INP COMP1_INM |
| 11 | 38 | 38 | 45 | 59 | PB13 | I/O | TC | N | TIM1_CH1N I2C2_SMBA | DAC_OUT |
| 12 | 13 | 13 | 46 | 60 | PA3 | I/O | TC | N | TIM5_CH4 I2C1_SDA UART1_RX CAN_RX | ADC_IN3 COMP1_INP COMP2_INM |
| 13 ⁽⁵⁾ | 12 | 12 | 47 | 61 | PA4 | I/O | TC | N | TIM1_CH1 TIM1_CH3N I2C1_SCL CAN_TX | ADC_IN4 COMP2_INM |
| - | 38 ⁽⁵⁾ | 38 ⁽⁵⁾ | 48 | 62 | PA5 | I/O | TC | N | TIM1_BKIN TIM1_CH1N TIM2_ETR | ADC_IN5 COMP1_INM COMP2_INP |
| 13 ⁽⁵⁾ | 37 | 37 | 1 | 63 | PA6 | I/O | TC | N | TIM1_CH2 TIM1_CH2N UART2_TX EVENTOUT | ADC_IN6 COMP2_INP |
| - | 36 | 36 | 2 | 64 | PA7 | I/O | TC | N | TIM1_CH1N TIM1_CH2N SPI3 NSS SPI3_MISO UART2_RX EVENTOUT | ADC_IN7 COMP2_OUT |

1. *I = Input, O = Output, S = Power, HiZ = High Resistance*
2. *TC: Standard 5V I/O, RST: Bi-directional reset pin with embedded weak pull-up resistor.*
3. *This type of multiplexing function can be configured to other pins by software (if the corresponding package model has this pin), please refer to the Multiplexing I/O section and Debug Settings section of the N32G05x series User's Manual for more details.*
4. *Fail-safe refers to adding input high level on IO when there is no power input to the chip, there will be no input high level poured into the chip, which will lead to a certain voltage on the power supply and consume current.*
5. *Combined IO, only one of the IO functions can be used at the same time, and other IOs on the same pin must be configured in analogue mode so as not to affect the IO being used.*

6. *The 3pin is a combination of NRST and PA14 (PA14 is only used for debugging and is not recommended for production design).*

4 Electrical characteristics

4.1 Parameter conditions

All voltages are based on V_{SS} unless otherwise specified.

4.1.1 Minimum and maximum values

Unless otherwise specified, all minimum and maximum values will be guaranteed at the worst ambient temperature, supply voltage and clock frequency conditions by testing performed on the production line with 100% of the product at an ambient temperature of T_A = 25 °C.

Data stated in the notes below each table as having been obtained by characterization, design simulation and/or process characterization will not be tested on the production line; on the basis of characterization tests, minimum and maximum values are obtained by taking the average of the sample tests and adding or subtracting three times the standard distribution (mean $\pm 3\sigma$).

4.1.2 Typical numerical values

Typical data is based on T_A = 25 °C and V_{DD} = 3.3V/5.0V (2.0V ≤ V_{DD} ≤ 5.5V voltage range) unless otherwise noted. These data are for design guidance only and have not been tested.

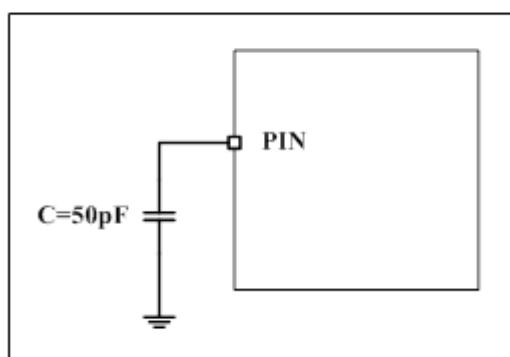
4.1.3 Typical curves

Typical curves are for design guidance only and are untested unless otherwise noted.

4.1.4 Loading capacitor

The load conditions when measuring the pin parameters are shown in Figure 4-1.

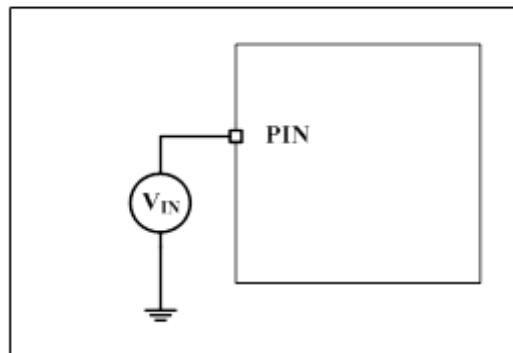
Figure 4-1 pin loading conditions



4.1.5 Pin input voltage

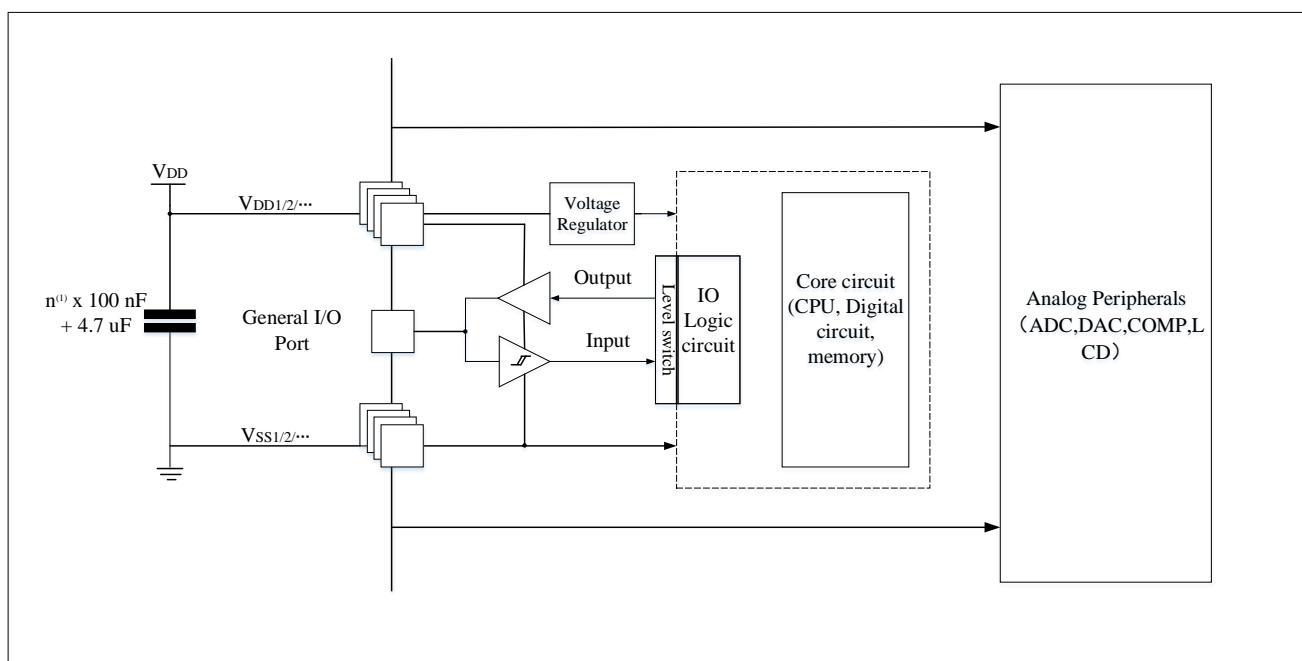
The measurement method of the input voltage on the pin is shown in Figure 4-2.

Figure 4-2 Pin input voltage



4.1.6 Power supply scheme

Figure 4-3 Power supply scheme

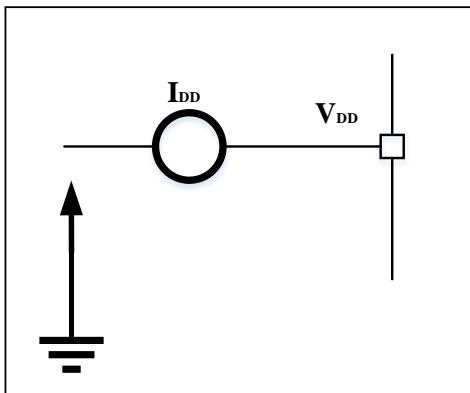


1. n is the number of VDDs.
2. When PB2 is multiplexed into the AVREFP function, an external 100nF+1uF capacitor is recommended.

Note: Refer to the hardware design guide for capacitor connections

4.1.7 Current consumption measurement

Figure 4-4 Current consumption measurement



4.2 Absolute maximum ratings

Loads applied to the device in excess of the values given in the "Absolute Maximum Ratings" list (Table 4 1, Table 4 2, Table 4 3) may cause permanent damage to the device. The maximum loads that can be withstood are given here and do not imply that the functional operation of the device under these conditions is error-free. Prolonged operation of the device under maximum conditions will affect the reliability of the device.

Table 4-1 Voltage characteristics

| Symbol | Parameter | Min | Max | Unit |
|------------------------------------|---|----------------------|-----|------|
| V _{DD} - V _{SS} | External mains supply voltage (V _{DD}) ⁽¹⁾ | -0.3 | 5.5 | V |
| V _{IN} | Input voltage on arbitrary I/O and control pins | V _{SS} -0.3 | 5.5 | |
| ΔV _{DDx} | Voltage difference between different supply pins | - | 50 | mV |
| V _{SSx} - V _{SS} | Voltage difference between different ground pins | - | 50 | |
| V _{ESD(HBM)} | ESD Electrostatic Discharge Voltage (Human Body Model) | See section 4.3.11 | | |

1. All power (V_{DD}) and ground (V_{SS}) pins must always be connected to an external permissible range power supply system.

Table 4-2 Current characteristics

| Symbol | Parameter | Max | Unit |
|---|--|-------|------|
| I _{VDD} | Total current through V _{DD} power line (supply current) ⁽¹⁾ | 200 | mA |
| I _{VSS} | Total current through V _{SS} ground (outgoing current) ⁽¹⁾ | 200 | |
| I _{IO} | Output potting current on arbitrary I/O and control pins | 16 | |
| | Output current on arbitrary I/O and control pins | -16 | |
| I _{INJ(PIN)} ⁽²⁾⁽³⁾ | Injection current at the NRST pin | 0/-5 | |
| | Injection current on other pins ⁽⁴⁾ | +/-5 | |
| ΣI _{INJ(PIN)} ⁽²⁾ | Total injected current on all I/O and control pins ⁽⁴⁾ | +/-16 | |

1. All power (V_{DD}) and ground (V_{SS}) pins must always be connected to the external permissible range of the power supply system.
2. The I_{INJ (PIN)} must never exceed its limit, i.e., it is guaranteed that V_{IN} does not exceed its maximum value. If it is not possible to guarantee that V_{IN} does not exceed its maximum value, also ensure that I_{INJ(PIN)} is externally limited to not exceed its maximum value. There is a forward injection current when V_{IN}>V_{DD} and a reverse injection current

when $V_{IN} < V_{SS}$.

3. The reverse injection current interferes with the analog performance of the device. Refer to Section 4.3.19.
4. When several I/O ports have injected currents at the same time, the maximum value of $\sum I_{INJ(PIN)}$ is the sum of the immediate absolute values of the forward injection current and the reverse injection current.

Table 4-3 Temperature characteristics

| Symbol | Parameter | Value | Unit |
|-----------|------------------------------|-------------|------|
| T_{STG} | Storage temperature range | -40 ~ + 150 | °C |
| T_J | Maximum junction temperature | 125 | °C |

4.3 Operating conditions

4.3.1 General operating conditions

Table 4-4 General operating conditions

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-------------|--|------------------|------|-----|------|
| f_{HCLK} | Internal AHB clock frequency | - | - | 64 | MHz |
| f_{PCLK1} | Internal APB1 clock frequency | - | - | 32 | |
| f_{PCLK2} | Internal APB2 clock frequency | - | - | 64 | |
| V_{DD} | Standard operating voltage | - | 2.0 | 5.5 | V |
| | Operating voltage when using ADC, COMP section | - | 2.4 | 5.5 | V |
| | Operating voltage when using DAC section | - | 2.97 | 5.5 | V |
| | Operating voltage when using LED/LCD section | - | 4.5 | 5.5 | V |
| T_A | Ambient Temperature | Suffix version 7 | -40 | 105 | °C |
| T_J | Junction temperature range | Suffix version 7 | -40 | 125 | °C |

4.3.2 Operating conditions at power-up and power-down

The parameters given in the following table are based on testing under the ambient temperature listed in Table 4-4.

Table 4-5 Operating conditions at power-up and power-down

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------|----------------------------|--------------------|-----|----------|-----------|
| t_{VDD} | V_{DD} rising time rate | From 0 to V_{DD} | 20 | ∞ | $\mu s/V$ |
| | V_{DD} falling time rate | From V_{DD} to 0 | 50 | ∞ | $\mu s/V$ |

4.3.3 Reset and power control module features

The parameters given in the following table are based on tests at ambient temperature and V_{DD} supply voltage listed in Table 4-4.

Table 4-6 Reset and power control module features

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-----------|-----------|--------------|---------|------|------|------|
| V_{PVD} | Rising | $PVD[3:0]=0$ | Reserve | | | V |
| | Falling | $PVD[3:0]=0$ | | | | |
| | Rising | $PVD[3:0]=1$ | 2 | 2.08 | 2.16 | |
| | Falling | $PVD[3:0]=1$ | 1.9 | 1.98 | 2.06 | |

| | | | | | | |
|-------------------------------------|----------------|-------------|---------|------|------|------|
| | Rising | PVD[3:0]=2 | 2.2 | 2.28 | 2.36 | |
| | Falling | PVD[3:0]=2 | 2.1 | 2.18 | 2.26 | |
| | Rising | PVD[3:0]=3 | 2.4 | 2.48 | 2.56 | |
| | Falling | PVD[3:0]=3 | 2.3 | 2.38 | 2.46 | |
| | Rising | PVD[3:0]=4 | 2.6 | 2.68 | 2.76 | |
| | Falling | PVD[3:0]=4 | 2.5 | 2.58 | 2.66 | |
| | Rising | PVD[3:0]=5 | 2.8 | 2.88 | 2.96 | |
| | Falling | PVD[3:0]=5 | 2.7 | 2.78 | 2.86 | |
| | Rising | PVD[3:0]=6 | 3 | 3.08 | 3.16 | |
| | Falling | PVD[3:0]=6 | 2.9 | 2.98 | 3.06 | |
| | Rising | PVD[3:0]=7 | 3.2 | 3.28 | 3.36 | |
| | Falling | PVD[3:0]=7 | 3.1 | 3.18 | 3.26 | |
| | Rising | PVD[3:0]=8 | 3.4 | 3.48 | 3.56 | |
| | Falling | PVD[3:0]=8 | 3.3 | 3.38 | 3.46 | |
| | Rising | PVD[3:0]=9 | 3.6 | 3.68 | 3.76 | |
| | Falling | PVD[3:0]=9 | 3.5 | 3.58 | 3.66 | |
| | Rising | PVD[3:0]=10 | 3.8 | 3.88 | 3.96 | |
| | Falling | PVD[3:0]=10 | 3.7 | 3.78 | 3.86 | |
| | Rising | PVD[3:0]=11 | 4 | 4.08 | 4.16 | |
| | Falling | PVD[3:0]=11 | 3.9 | 3.98 | 4.06 | |
| | Rising | PVD[3:0]=12 | 4.2 | 4.28 | 4.36 | |
| | Falling | PVD[3:0]=12 | 4.1 | 4.18 | 4.26 | |
| | Rising | PVD[3:0]=13 | 4.4 | 4.48 | 4.56 | |
| | Falling | PVD[3:0]=13 | 4.3 | 4.38 | 4.46 | |
| | Rising | PVD[3:0]=14 | 4.6 | 4.68 | 4.76 | |
| | Falling | PVD[3:0]=14 | 4.5 | 4.58 | 4.66 | |
| | Rising | PVD[3:0]=15 | 4.8 | 4.88 | 4.96 | |
| | Falling | PVD[3:0]=15 | 4.7 | 4.78 | 4.86 | |
| V _{PVDhyst} ⁽¹⁾ | PVD hysteresis | - | 80 | 100 | 125 | mV |
| V _{LVR} | Rising | LVR[3:0]=0 | Reserve | | | |
| | Falling | LVR[3:0]=0 | V | | | |
| | Rising | LVR[3:0]=1 | | 2 | 2.08 | 2.16 |
| | Falling | LVR[3:0]=1 | | 1.9 | 1.98 | 2.06 |
| | Rising | LVR[3:0]=2 | | 2.2 | 2.28 | 2.36 |
| | Falling | LVR[3:0]=2 | | 2.1 | 2.18 | 2.26 |
| | Rising | LVR[3:0]=3 | | 2.4 | 2.48 | 2.56 |
| | Falling | LVR[3:0]=3 | | 2.3 | 2.38 | 2.46 |
| | Rising | LVR[3:0]=4 | | 2.6 | 2.68 | 2.76 |
| | Falling | LVR[3:0]=4 | | 2.5 | 2.58 | 2.66 |
| | Rising | LVR[3:0]=5 | | 2.8 | 2.88 | 2.96 |
| | Falling | LVR[3:0]=5 | | 2.7 | 2.78 | 2.86 |
| | Rising | LVR[3:0]=6 | | 3 | 3.08 | 3.16 |
| | Falling | LVR[3:0]=6 | | 2.9 | 2.98 | 3.06 |

| | | | | | | |
|---|------------------------------------|--------------|-----|------|------|----|
| | Rising | LVR[3:0]=7 | 3.2 | 3.28 | 3.36 | |
| | Falling | LVR[3:0]=7 | 3.1 | 3.18 | 3.26 | |
| | Rising | LVR[3:0]=8 | 3.4 | 3.48 | 3.56 | |
| | Falling | LVR[3:0]=8 | 3.3 | 3.38 | 3.46 | |
| | Rising | LVR[3:0]=9 | 3.6 | 3.68 | 3.76 | |
| | Falling | LVR[3:0]=9 | 3.5 | 3.58 | 3.66 | |
| | Rising | LVR[3:0]=10 | 3.8 | 3.88 | 3.96 | |
| | Falling | LVR[3:0]=10 | 3.7 | 3.78 | 3.86 | |
| | Rising | LVR[3:0]=11 | 4 | 4.08 | 4.16 | |
| | Falling | LVR[3:0]=11 | 3.9 | 3.98 | 4.06 | |
| | Rising | LVR[3:0]=12 | 4.2 | 4.28 | 4.36 | |
| | Falling | LVR[3:0]=12 | 4.1 | 4.18 | 4.26 | |
| | Rising | LVR[3:0]=13 | 4.4 | 4.48 | 4.56 | |
| | Falling | LVR[3:0]=13 | 4.3 | 4.38 | 4.46 | |
| | Rising | LVR[3:0]=14 | 4.6 | 4.68 | 4.76 | |
| | Falling | LVR[3:0]=14 | 4.5 | 4.58 | 4.66 | |
| | Rising | LVR[3:0]=15 | 4.8 | 4.88 | 4.96 | |
| | Falling | LVR[3:0]=15 | 4.7 | 4.78 | 4.86 | |
| V _{LVRhyst} ⁽¹⁾ | LVR hysteresis | - | 80 | 100 | 125 | mV |
| V _{POR/PDR} | VDD power-up/down reset thresholds | Falling edge | - | 1.7 | - | V |
| | | Rising edge | - | 1.8 | - | V |
| V _{PDR/PORhyst} ⁽¹⁾ | POR/PDR hysteresis voltage | - | - | 100 | - | mV |
| T _{_RSTTEMPO} ⁽¹⁾ | Reset Duration | - | - | 150 | - | us |

- Guaranteed by design, not tested in production.

4.3.4 Internal reference voltage

The parameters given in the following table are based on tests at ambient temperature and V_{DD} supply voltage listed in Table 4-4.

Table 4-7 Internal reference voltage

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---------------------------------------|---|---|---------------------|-----|---------------------|------|
| V _{REFINT} | Internal reference voltage | -40°C < T _A < +105°C | 1.16 ⁽²⁾ | 1.2 | 1.26 ⁽²⁾ | V |
| T _{S_vrefint} ⁽¹⁾ | When reading the internal reference voltage, the sampling time of the ADC | PLS[2:0]=001 (Rising edge) f _{ADC_CLK} =24M | 15.8 ⁽³⁾ | - | - | μs |

- The shortest sampling time is obtained by multiple cycles in the application.
- Guaranteed by design, not tested in production.
- Converted to ADC sampling period of 380 cycles.

4.3.5 Power supply current characteristics

Current consumption is a combination of a number of parameters and factors that include operating voltage, ambient temperature, load on I/O pins, software configuration of the product, operating frequency, flip-flop rate of I/O pins, location of the program in memory, and code executed.

The current consumption measurements are described in detail in Figure 4-4.

All current consumption measurements given in this section for all modes of operation execute a condensed set of code.

4.3.5.1 Maximum current consumption

The microcontroller is in the following conditions:

- All I/O pins are in input mode and connected to a static level - V_{DD} or V_{SS} (no load).
- All peripherals are off unless otherwise noted.
- Flash memory access time is adjusted to the frequency of f_{HCLK} (0 wait cycles for 0 to 24 MHz, 1 wait cycle for 24 to 48 MHz, and 2 wait cycles above 48 MHz).
- Instruction prefetch is on (Hint: this parameter must be set before setting the clock and bus divider).
- When peripheral is turned on: f_{PCLK1} = f_{HCLK}/2, f_{PCLK2} = f_{HCLK}.
- V_{DD} = 5.5V, ambient temperature equal to 105 °C.

The parameters given in Table 4-8 and Table 4-9 are based on tests at ambient temperature and VDD supply voltage listed in Table 4-4.

Table 4-8 Typical current consumption in run mode with data processing code running from internal flash memory

| Symbol | Parameter | Conditions | f _{HCLK} | Typ ⁽¹⁾ | | Unit |
|-----------------|----------------------------------|---|-------------------|---|--|------|
| | | | | V _{DD} =5.5V, T _A = 105°C | | |
| I _{DD} | Supply current in operation mode | External clock. Enable all peripherals | 64MHz | 17.94 | | mA |
| | | | 32MHz | 9.97 | | |
| | | | 16MHz | 5.94 | | |
| | | | 8MHz | 3.57 | | |
| | | External clock. Turn off all peripherals | 64MHz | 11.23 | | |
| | | | 32MHz | 6.48 | | |
| | | | 16MHz | 4.09 | | |
| | | | 8MHz | 2.55 | | |
| I _{DD} | Supply current in operation mode | Internal clock. Enable all peripherals | 64MHz | 16.89 | | mA |
| | | | 32MHz | 8.99 | | |
| | | | 16MHz | 4.99 | | |
| | | | 8MHz | 2.64 | | |
| | | Internal clock. Turn off all peripherals | 64MHz | 10.24 | | |
| | | | 32MHz | 5.53 | | |
| | | | 16MHz | 3.15 | | |
| | | | 8MHz | 1.62 | | |

- Guaranteed by design and comprehensive evaluation, not tested in production.

Table 4-9 Typical current consumption in sleep mode

| Symbol | Parameter | Conditions | f _{HCLK} | Typ ⁽¹⁾ | | Unit |
|-----------------|------------------------------|---|-------------------|---|--|------|
| | | | | V _{DD} =5.5V, T _A = 105°C | | |
| I _{DD} | Supply current in sleep mode | External clock. Enable all peripherals | 64MHz | 15.78 | | mA |
| | | | 32MHz | 8.89 | | |
| | | | 16MHz | 5.4 | | |
| | | | 8MHz | 3.31 | | |
| | | External clock. Turn off all peripherals | 64MHz | 8.39 | | |
| | | | 32MHz | 5.06 | | |
| | | | 16MHz | 3.38 | | |

| | | | | | |
|-----------------|------------------------------|---|-------|-------|----|
| | | | 8MHz | 2.2 | |
| I _{DD} | Supply current in sleep mode | Internal clock. Enable all peripherals | 64MHz | 14.74 | mA |
| | | | 32MHz | 7.9 | |
| | | | 16MHz | 4.44 | |
| | | | 8MHz | 2.37 | |
| | | Internal clock. Turn off all peripherals | 64MHz | 7.41 | |
| | | | 32MHz | 4.1 | |
| | | | 16MHz | 2.44 | |
| | | | 8MHz | 1.26 | |

1. Guaranteed by design and comprehensive evaluation, Tested in production with maximal V_{DD} and maximal f_{HCLK}.

4.3.5.2 Typical current consumption

The chip test conditions are as follows:

- All I/O pins are in input mode and connected to a static level-V_{DD} or V_{SS} (no load).
- All peripherals are off unless otherwise noted.
- Flash memory access time is adjusted to the frequency of f_{HCLK} (0 wait cycle for 0 to 24 MHz, 1 wait cycle for 24 to 48 MHz, and 2 wait cycles above 48 MHz).
- Ambient temperature and V_{DD} supply voltage conditions are listed in Table 4-4.
- Instruction prefetch is on (Hint: This parameter must be set before setting the clock and bus divider).
- When the peripheral is turned on: f_{PCLK1} = f_{HCLK}/2, f_{PCLK2} = f_{HCLK}.

The parameter test conditions in the following table are based on Table 4-4.

Table 4-10 Typical current consumption in run mode with data processing code running from internal flash memory
(T_A=25 °C, V_{DD}=5.0V)

| Symbol | Parameter | Conditions | f _{HCLK} | Typ | | Unit |
|-----------------|----------------------------------|---------------------------|-------------------|------------------------|--------------------------|------|
| | | | | Enable all peripherals | Turn off all peripherals | |
| I _{DD} | Supply current in operation mode | External High Speed Clock | 64MHz | 17.79 | 11.04 | mA |
| | | | 32MHz | 9.76 | 6.25 | |
| | | | 16MHz | 5.71 | 3.84 | |
| | | | 8MHz | 3.33 | 2.29 | |
| I _{DD} | Supply current in operation mode | Internal high-speed clock | 64MHz | 17.11 | 10.32 | mA |
| | | | 32MHz | 9.06 | 5.57 | |
| | | | 16MHz | 5.02 | 3.15 | |
| | | | 8MHz | 2.64 | 1.6 | |

Table 4-11 Typical current consumption in run mode with data processing code running from internal flash memory
(T_A=25°C, V_{DD}=3.3V)

| Symbol | Parameter | Conditions | f _{HCLK} | Typ | | Unit |
|-----------------|----------------------------------|---------------------------|-------------------|------------------------|--------------------------|------|
| | | | | Enable all peripherals | Turn off all peripherals | |
| I _{DD} | Supply current in operation mode | External High Speed Clock | 64MHz | 17.56 | 10.82 | mA |
| | | | 32MHz | 9.57 | 6.08 | |
| | | | 16MHz | 5.54 | 3.68 | |
| | | | 8MHz | 3.17 | 2.14 | |
| I _{DD} | Supply current in operation mode | Internal high-speed clock | 64MHz | 16.96 | 10.25 | mA |
| | | | 32MHz | 9.01 | 5.51 | |

| | | | | | | |
|--|--|--|-------|------|------|--|
| | | | 16MHz | 4.98 | 3.13 | |
| | | | 8MHz | 2.62 | 1.59 | |

Table 4-12 Typical current consumption in sleep mode ($T_A=25^\circ\text{C}$ 、 $V_{DD}=5.0\text{V}$)

| Symbol | Parameter | Conditions | f_{HCLK} | Typ | | Max | Unit |
|--------|------------------------------|---------------------------|------------|------------------------|--------------------------|-----|------|
| | | | | Enable all peripherals | Turn off all peripherals | | |
| IDD | Supply current in sleep mode | External High Speed Clock | 64MHz | 15.63 | 8.16 | - | mA |
| | | | 32MHz | 8.67 | 4.81 | - | |
| | | | 16MHz | 5.16 | 3.12 | - | |
| | | | 8MHz | 3.05 | 1.93 | - | |
| IDD | Supply current in sleep mode | Internal high-speed clock | 64MHz | 14.93 | 7.47 | 10 | mA |
| | | | 32MHz | 7.98 | 4.12 | - | |
| | | | 16MHz | 4.47 | 2.43 | - | |
| | | | 8MHz | 2.36 | 1.24 | - | |

Table 4-13 Typical current consumption in sleep mode ($T_A=25^\circ\text{C}$ 、 $V_{DD}=3.3\text{V}$)

| Symbol | Parameter | Conditions | f_{HCLK} | Typ | | Unit |
|--------|------------------------------|---------------------------|------------|------------------------|--------------------------|------|
| | | | | Enable all peripherals | Turn off all peripherals | |
| IDD | Supply current in sleep mode | External High Speed Clock | 64MHz | 15.4 | 7.98 | mA |
| | | | 32MHz | 8.48 | 4.64 | |
| | | | 16MHz | 4.99 | 2.96 | |
| | | | 8MHz | 2.89 | 1.79 | |
| IDD | Supply current in sleep mode | Internal high-speed clock | 64MHz | 14.81 | 7.41 | mA |
| | | | 32MHz | 7.91 | 4.09 | |
| | | | 16MHz | 4.43 | 2.41 | |
| | | | 8MHz | 2.34 | 1.23 | |

4.3.5.3 Low Power Current Consumption

The microcontroller is in the following conditions:

- All I/O pins are in input mode and connected to a static level-VDD or VSS (no load).
- All peripherals are off unless otherwise noted.

Table 4-14 Typical consumption in stop and power-down mode ($T_A=25^\circ\text{C}$ 、 $V_{DD}=3.3\text{V}$)

| Symbol | Parameter | Conditions | Typ | Max | Unit |
|----------|----------------------|--|------|-----|------|
| IDD_STOP | Current in STOP mode | SRAM hold, all I/O status hold, BS TIM, independent watchdog off | 3.04 | - | uA |
| IDD_PD | Current in PD mode | All power supplies are turned off, only the wake-up pin, NRST required circuits are retained for operation | 0.97 | - | uA |

Table 4-15 Typical consumption in stop and power-down mode ($T_A=25^\circ\text{C}$ 、 $V_{DD}=5.0\text{V}$)

| Symbol | Parameter | Conditions | Typ | Max | Unit |
|--------|-----------|------------|-----|-----|------|
| | | | | | |

| | | | | | |
|----------------------|----------------------|--|------|----|----|
| I _{DD_STOP} | Current in STOP mode | SRAM hold, all I/O status hold, BS TIM, independent watchdog off | 4.14 | 10 | uA |
| I _{DD_PD} | Current in PD mode | All power supplies are turned off, only the wake-up pin, NRST required circuits are retained for operation | 1.86 | 3 | uA |

4.3.6 External clock source characteristics

4.3.6.1 High-speed external clock generated by external oscillator

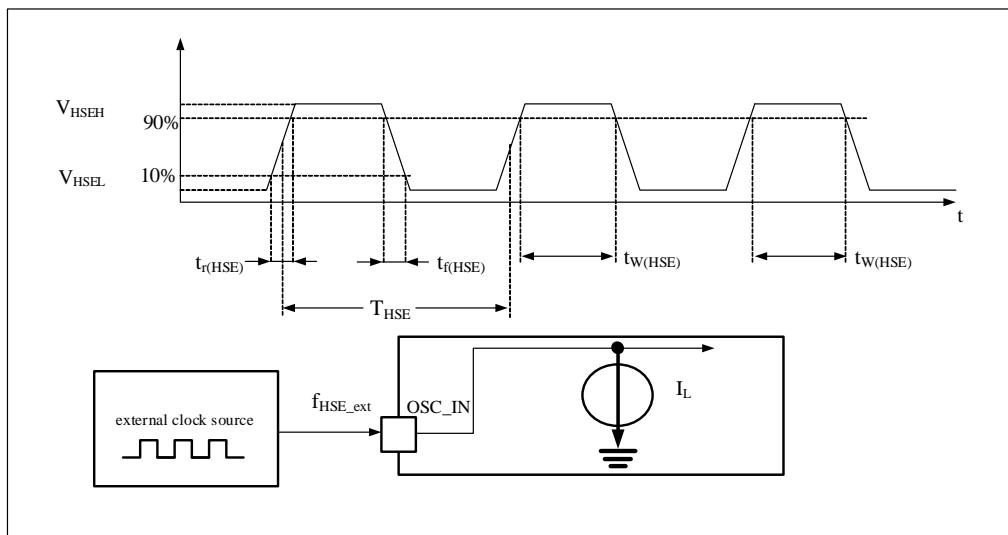
The characteristic parameters given in the following table were measured using ambient temperatures and supply voltages in accordance with Table 4-4.

Table 4-16 High-speed external clock characteristics⁽¹⁾

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|----------------------|--|---|--------------------|-----|--------------------|------|
| f _{HSE_ext} | User External Clock Frequency ⁽¹⁾ | T _A =25°C | 1 | 8 | 16 | MHz |
| V _{HSEH} | OSC_IN input pin high level voltage | | 0.7V _{DD} | - | V _{DD} | V |
| V _{HSEL} | OSC_IN input pin low voltage | | V _{SS} | - | 0.3V _{DD} | |
| t _{w(HSE)} | OSC_IN high or low time ⁽¹⁾ | | 16 | - | - | ns |
| t _{w(HSE)} | OSC_IN rise or fall time ⁽¹⁾ | | - | - | 20 | |
| C _{in(HSE)} | OSC_IN input tolerance ⁽¹⁾ | | - | 5 | - | pF |
| DuCy(HSE) | Duty cycle | | 45 | - | 55 | % |
| I _L | OSC_IN input leakage current | V _{SS} ≤V _{IN} ≤V _{DD} | - | - | ±1 | μA |

1. Guaranteed by design and comprehensive evaluation, not tested in production.

Figure 4-5 AC timing diagram of external high-speed clock source



High-Speed External Clock Generation Using a Crystal/Ceramic Resonator

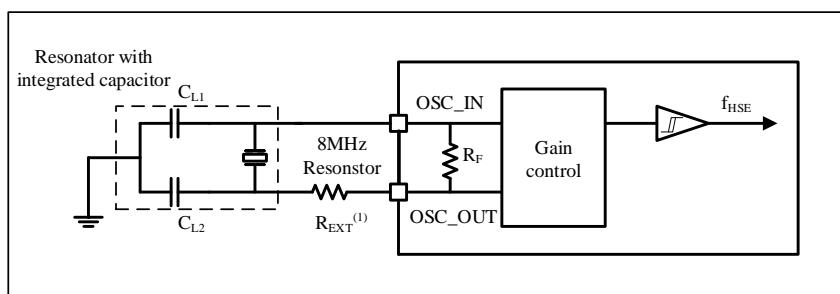
High-speed external clocks (HSE) can be generated using an oscillator consisting of a crystal/ceramic resonator from 8 to 16 MHz. The information given in this section is based on a comprehensive characterization using typical external components listed in the table below. In the application, the resonator and load capacitance must be placed as close as possible to the oscillator pins to minimize output distortion and stabilization time at startup. For detailed parameters (frequency, package, accuracy, etc.) of the crystal resonator, please consult the appropriate manufacturer. (The crystal resonator mentioned here is what we usually refer to as passive crystal oscillator)

Table 4-17 HSE 8~16MHz Oscillator Characteristics⁽¹⁾⁽²⁾

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-------------------------|--|------------------|-----|-----|-----|------|
| f_{OSC_IN} | oscillator frequency | - | 8 | 8 | 16 | MHz |
| C_{L1} $C_{L2(3)}$ | Recommended load capacitance with corresponding crystal serial impedance (R_s) | $R_s = 30\Omega$ | - | 12 | 25 | pF |
| $t_{SU(HSE)}^{(3)}$ | Start-up time (8M crystal) | VDD is stable | - | 3 | - | ms |

1. Resonator characteristics are given by the crystal/ceramic resonator manufacturer.
2. Guaranteed by design, not tested in production.
3. $t_{SU(HSE)}$ is the start-up time, which is measured from the time the software enables HSE until a stable 8MHz oscillation is obtained. This value is measured on a standard crystal resonator, and it may vary greatly depending on the crystal manufacturer.

Figure 4-6 Typical application using 8MHz crystal



1. R_{EXT} value is determined by the characteristics of the crystal.

4.3.7 Internal clock source characteristics

The characteristics given in the following table were measured using ambient temperatures and supply voltages in accordance with Table 4-4.

4.3.7.1 High-speed internal (HSI) RC oscillator

Table 4-18 HSI Oscillator characteristics⁽¹⁾⁽²⁾

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--------------------|--|--|----------------------|-----|----------------------|------|
| f_{HSI_8M} | Frequency | VDD=5.0V, $T_A = 25^\circ C$, post-calibration | 7.96 ⁽³⁾ | 8 | 8.04 ⁽³⁾ | MHz |
| f_{HSI_24M} | Frequency | VDD=5.0V, $T_A = 25^\circ C$, post-calibration | 23.88 ⁽³⁾ | 24 | 24.12 ⁽³⁾ | MHz |
| ACC _{HSI} | Temperature drift of HSI oscillator ⁽⁴⁾ | VDD=5.0V, $T_A = -40\sim105^\circ C$, Temperature drift | -2 | - | 2 | % |
| | | VDD=5.0V, $T_A = -20\sim85^\circ C$, Temperature drift | -1.5 | - | 1.5 | % |
| | | VDD=5.0V, $T_A = 0\sim70^\circ C$, Temperature drift | -1 | - | 1 | % |
| $t_{SU(HSI)}$ | HSI oscillator startup time | - | - | 6 | - | μs |
| $I_{DD(HSI)}$ | HSI oscillator power consumption | - | - | 250 | - | μA |

1. $V_{DD} = 5.0V$, $T_A = -40$ to $105^\circ C$ unless otherwise noted.
2. Guaranteed by design, not tested in production.
3. Production calibration accuracy, not including soldering effects. Frequency deviation due to soldering ranges from approximately $\pm 1\%$.
4. Frequency deviation including soldering effects, data from sample testing, not tested in production.

4.3.7.2 Low-speed internal (LSI) RC oscillator

Table 4-19 LSI Oscillator characteristics⁽¹⁾

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-------------------------------------|----------------------------------|---|------|-----|------|------|
| f _{LSI} ⁽²⁾ | output frequency | 25 °C Calibration, V _{DD} =5.0V | 31 | 32 | 33 | KHz |
| | | V _{DD} = 2.0V ~ 5.5V, T _A = -40 ~ 105°C Real-time calibration based on temperature changes via software | 28.8 | 32 | 35.2 | KHz |
| t _{SU(LSI)} ⁽²⁾ | LSI Oscillator Startup Time | - | - | 30 | 80 | μs |
| I _{DD(LSI)} ⁽²⁾ | LSI oscillator power consumption | - | - | 0.3 | - | μA |

1. V_{DD} = 5.0V, T_A = -40 to 105 °C unless otherwise noted.

2. Guaranteed by design, not tested in production.

4.3.8 Low-power mode wake-up time

The wake-up times listed in Table 4-20 were measured during the wake-up phase of an 8MHz HSI RC oscillator. The clock source used for wake-up depends on the current operating mode:

- STOP/PD mode: the clock source is the RC oscillator
- Sleep mode: the clock source is the clock used when entering sleep mode

All times are measured using the ambient temperature and supply voltage in accordance with Table 4-4.

Table 4-20 Low-power mode wake-up time

| Symbol | Parameter | Typ | Max | Unit |
|-------------------------------------|-------------------------------|-----|-----|------|
| t _{WUSLEEP} ⁽¹⁾ | Wake-up from SLEEP mode | - | 16 | HCLK |
| t _{WUSTOP} ⁽¹⁾ | Fast wake-up from STOP mode | 31 | 62 | us |
| | Normal wake-up from STOP mode | 41 | 82 | |
| t _{WUPD} ⁽¹⁾ | Wake-up from PD mode | 100 | 200 | |

1. Wake-up time is measured from the start of the wake-up event until the user program reads the first instruction.

4.3.9 PLL characteristics

The parameters listed in Table 4-20 are measured using ambient temperature and supply voltage in accordance with Table 4-4.

Table 4-21 PLL characteristics

| Symbol | Parameter | Num | | | Unit |
|-----------------------|--|-----|-----|--------------------|------|
| | | Min | Typ | Max ⁽¹⁾ | |
| f _{PLL_IN} | PLL Input Clock | 4 | 8 | 16 | MHz |
| | PLL input clock duty cycle | 40 | - | 60 | % |
| f _{PLL_IN/N} | PLL input clock after N-division | 4 | - | 16 | MHz |
| f _{PLL_OUT} | PLL multiplier output clock ⁽²⁾ | 48 | - | 72 | MHz |
| t _{LOCK} | PLL Ready indication signal output time | - | - | 20 | μs |
| Jitter | TIE RMS Jitter | - | 40 | - | pS |

| | | | | | |
|------------------|---|---|-----|-----|----|
| I _{PLL} | Operating Current of PLL @64MHz VCO frequency. ⁽¹⁾ | - | 300 | 500 | uA |
|------------------|---|---|-----|-----|----|

- Guaranteed by design, not tested in production.
- Care needs to be taken to use the correct multiplication factor so that f_{PLL_OUT} is within the allowable range based on the PLL input clock frequency.

4.3.10 FLASH characteristics

All characterization parameters were obtained at TA = -40~105 °C unless otherwise stated.

Table 4-22 FLASH characteristics

| Symbol | Parameter | Conditions | Min ⁽¹⁾ | Typ ⁽¹⁾ | Max ⁽¹⁾ | Unit |
|--------------------|-------------------------------|---|--------------------|--------------------|--------------------|------|
| t _{PROG} | 64-bit programming time | TA = -40~105°C | - | 175 | - | μs |
| t _{ERASE} | Page (512 bytes) erase time | TA = -40~105°C | - | 3 | - | ms |
| t _{ME} | Mass erase time | TA = -40~105°C | - | 35 | - | ms |
| I _{DD} | Supply current ⁽¹⁾ | Reading mode, f _{HCLK} =64MHz, V _{DD} =5.0V | - | 4.5 | 6.0 | mA |
| | | Write mode, f _{HCLK} =64MHz, V _{DD} =5.0V | - | - | 2 | mA |
| | | Erase mode, f _{HCLK} =64MHz, V _{DD} =5.0V | - | - | 1.5 | mA |
| | | PD/STOP mode, V _{DD} =2.0~5.0V | - | 0.3 | 15 ⁽²⁾ | μA |

- Guaranteed by design and comprehensive evaluation, not tested in production.
- Tested at TA = 85 °C.

Table 4-23 Flash memory life and data retention period

| Symbol | Parameter | Conditions | Min ⁽¹⁾ | Unit |
|------------------|----------------|--|--------------------|---------|
| N _{END} | Endurance | TA = -40~105 °C | 100 | kcycles |
| t _{RET} | Data retention | TA = 105 °C, after 1000 erasing cycle ⁽¹⁾ | 10 | years |

- Derived from characterization tests, not tested in production.

4.3.11 Absolute maximum value (electrical sensitivity)

Based on three different tests (ESD, LU), the chip is tested for strength to determine its performance in terms of electrical sensitivity, using specific measurement methods.

Electrostatic discharge (ESD)

Electrostatic discharge (a positive pulse followed by a negative pulse one second later) was applied to all pins of all samples.

Table 4-24 ESD Absolute Maximum

| Symbol | Parameter | Conditions | Class | Max ⁽¹⁾ | Unit |
|-----------------------|--|---|-------|--------------------|------|
| V _{ESD(HBM)} | Electrostatic discharge voltage (human body model) | TA = +25 °C, Complies with MIL-STD-883K Method 3015.9. | 3A | 4000 | V |
| V _{ESD(CDM)} | Electrostatic discharge voltage (charging equipment model) | TA = +25 °C, Complies with ESDA/JEDEC JS-002-2018 | C3 | 1500 | |

- Derived from characterization tests, not tested in production.

Static Peg-Lock

To evaluate bolting performance, 2 complementary static bolting tests on 6 samples are required:

- For each power supply pin, provide a supply voltage that exceeds the limit.

- Injects current on each input, output, and configurable I/O pin.

This test complies with the EIA/JESD78E IC bolting standard.

Table 4-25 Electrical sensitivity

| Symbol | Parameter | Conditions | Class |
|--------|------------------------|--|------------|
| LU | Static bolts and locks | T _A = +105 °C, complies with JESD78E standard | II level A |

4.3.12 I/O port characteristics

Generalized Input/Output Characteristics

Unless otherwise noted, the parameters listed in the following table were measured under the conditions of Table 4-4. All I/O ports are CMOS and TTL compatible.

Table 4-26 I/O static characteristics

| Symbol | Parameter | VDD | Conditions | Min | Max | Unit |
|---------------------------------|---|-----------|--|----------|---------|------|
| V _{IL} | Input Low Level Voltage | 5 | - | - | 0.3×VDD | V |
| | | 3.3 | - | - | 0.8 | |
| | | 2.0 | - | - | 0.2×VDD | |
| V _{IH} | Input High Level Voltage | 5 | - | 0.7×VDD | - | V |
| | | 3.3 | - | 2.037 | - | |
| | | 2.0 | - | 0.8×VDD | - | |
| V _{hys} | Schmitt trigger voltage hysteresis ⁽¹⁾ | 5/3.3/2.0 | - | 0.1×VDD | - | V |
| I _{lkg} ⁽²⁾ | Input leakage current IIH | 5/3.3/2.0 | - | - | 1 | μA |
| | Input leakage current IIL | 5/3.3/2.0 | - | 1 | - | |
| V _{OH} | Output high level voltage | 5 | High driving I _{min} =16mA low driving I _{min} =8mA | VDD-0.8 | - | V |
| | | 3.3 | High driving I _{min} =8mA low driving I _{min} =4mA | 2.4 | - | |
| | | 2.0 | High driving I _{min} =4mA low driving I _{min} =2mA | VDD-0.45 | - | |
| V _{OL} | Output Low Voltage | 5 | High driving I _{min} =16mA low driving I _{min} =8mA | - | 0.7 | V |
| | | 3.3 | High driving I _{min} =8mA low driving I _{min} =4mA | - | 0.45 | |
| | | 2.0 | High driving I _{min} =4mA low driving I _{min} =2mA | - | 0.4 | |
| R _{PU} | Weak pull-up equivalent resistance | 5/3.3/2.0 | - | 37 | 100 | kΩ |
| R _{PD} | Weak pull-down equivalent resistance | 5/3.3/2.0 | - | 61 | 121 | kΩ |
| C _{IO} | Capacitance of I/O pins | 5/3.3/2.0 | - | - | 10 | pF |

1. Hysteresis voltage for Schmitt trigger switching levels. Guaranteed by characterization tests, not tested in production.

2. Leakage current may be higher than maximum if there is reverse current back-up at adjacent pins.

All I/O ports are CMOS and TTL compatible (no software configuration required) and their characteristics take into account most stringent CMOS process or TTL parameters:

Input and output AC characteristics

The definitions and values of the input and output AC characteristics are given in Table 4-4.

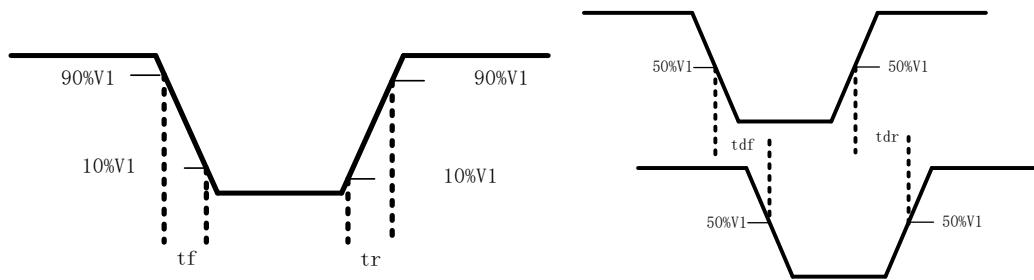
Unless otherwise stated, the parameters are measured using ambient temperatures and supply voltages in accordance with Table 4-4.

Table 4-27 I/O AC Characteristics

| VDD | Conditions | | | Rise/Fall Time (ns) | | | Propagation Delay (ns) | | |
|---------------|----------------|----------------|------------------|---------------------|-------|-------|------------------------|-------|-------|
| | Driving | Slew Rate | CLoading(pf) | Min | Typ | Max | Min | Typ | Max |
| | Strength | Control | | | | | | | |
| 5V(4.5~5.5) | Low (DR=1) | Slow (SR=1) | 25 | 2.493 | 3.509 | 5.393 | 4.351 | 6.296 | 10.13 |
| | | | 50 | 4.109 | 5.81 | 9.086 | 5.289 | 7.597 | 12.11 |
| | | | 100 | 7.498 | 10.65 | 16.63 | 7.036 | 10.04 | 15.83 |
| | | Fast (SR=0) | 25 | 2.173 | 3.062 | 4.793 | 3.751 | 5.486 | 8.93 |
| | | | 50 | 3.865 | 5.427 | 8.521 | 4.615 | 6.698 | 10.78 |
| | | | 100 | 7.295 | 10.34 | 16.12 | 6.331 | 9.1 | 14.43 |
| | High (DR=0) | Slow (SR=1) | 25 | 1.627 | 2.276 | 3.513 | 3.855 | 5.623 | 9.126 |
| | | | 50 | 2.454 | 3.442 | 5.349 | 4.421 | 6.405 | 10.32 |
| | | | 100 | 4.095 | 5.779 | 8.891 | 5.375 | 7.728 | 12.33 |
| | | Fast (SR=0) | 25 | 1.344 | 1.892 | 2.957 | 3.356 | 4.943 | 8.115 |
| | | | 50 | 2.157 | 3.023 | 4.721 | 3.825 | 5.6 | 9.126 |
| | | | 100 | 3.833 | 5.372 | 8.369 | 4.698 | 6.82 | 10.99 |
| 3.3V(2.7~3.6) | Low (DR=1) | Slow (SR=1) | 25 | 3.215 | 4.727 | 8.585 | 5.309 | 7.923 | 14.38 |
| | | | 50 | 5.357 | 7.964 | 14.47 | 6.524 | 9.695 | 17.54 |
| | | | 100 | 9.718 | 14.47 | 26.42 | 8.8 | 13.03 | 23.5 |
| | | Fast (SR=0) | 25 | 2.819 | 4.168 | 7.648 | 4.522 | 6.811 | 12.43 |
| | | | 50 | 5.008 | 7.455 | 13.54 | 5.646 | 8.46 | 15.39 |
| | | | 100 | 9.49 | 14.05 | 25.86 | 7.875 | 11.74 | 21.25 |
| | High (DR=0) | Slow (SR=1) | 25 | 2.095 | 3.063 | 5.522 | 4.67 | 7.017 | 12.8 |
| | | | 50 | 3.176 | 4.66 | 8.4 | 5.403 | 8.075 | 14.67 |
| | | | 100 | 5.311 | 7.816 | 14.12 | 6.636 | 9.868 | 17.88 |
| | | Fast (SR=0) | 25 | 1.729 | 2.546 | 4.659 | 3.999 | 6.059 | 11.12 |
| | | | 50 | 2.784 | 4.124 | 7.503 | 4.612 | 6.956 | 12.73 |
| | | | 100 | 4.97 | 7.338 | 13.33 | 5.75 | 8.623 | 15.73 |
| 2V(1.8~2.2) | Low (DR=1) | Slow (SR=1) | 25 | 5.641 | 9.338 | 16.84 | 9.428 | 15.96 | 28.85 |
| | | | 50 | 9.431 | 15.81 | 28.57 | 11.66 | 19.58 | 35.32 |
| | | | 100 | 17.25 | 28.99 | 52.5 | 15.78 | 26.51 | 47.71 |
| | | Fast (SR=0) | 25 | 5.027 | 8.341 | 15.1 | 8.015 | 13.6 | 24.73 |
| | | | 50 | 8.92 | 14.98 | 27.03 | 10.06 | 17.03 | 30.88 |
| | | | 100 | 16.9 | 28.5 | 51.08 | 14.13 | 23.89 | 43.09 |
| | High (DR=0) | Slow (SR=1) | 25 | 3.642 | 6.019 | 10.83 | 8.458 | 14.31 | 25.88 |
| | | | 50 | 5.54 | 9.139 | 16.52 | 9.741 | 16.42 | 29.64 |
| | | | 100 | 9.372 | 15.49 | 28.08 | 11.94 | 20.07 | 36.18 |
| | | Fast (SR=0) | 25 | 3.044 | 5.064 | 9.218 | 7.162 | 12.21 | 22.24 |
| | | | 50 | 4.941 | 8.194 | 14.88 | 8.272 | 14.05 | 25.55 |
| | | | 100 | 8.829 | 14.62 | 26.53 | 10.34 | 17.51 | 31.74 |

1. Guaranteed by design, not tested in production

Figure 4-7 I/O AC characteristic definition



4.3.13 NRST pin characteristics

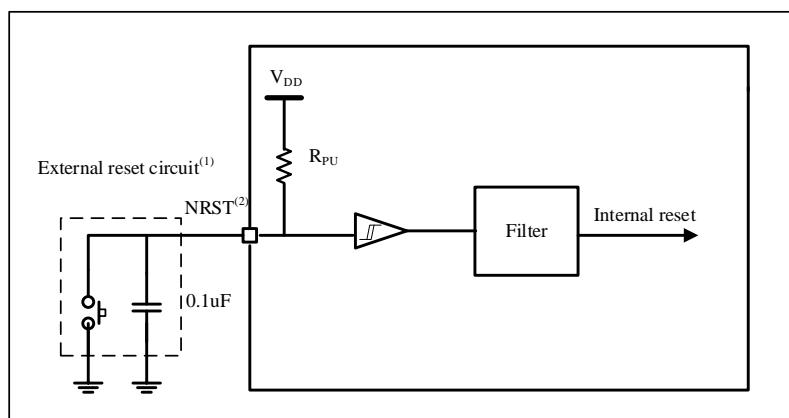
The NRST pin has an internal integrated pull-up resistor, and the parameters are measured using ambient temperature and supply voltage in accordance with Table 4-4, unless otherwise noted.

Table 4-28 NRST pin characteristics

| Symbol | Parameter | VDD | Min | Typ | Max | Unit |
|----------------------|---|-----------|--------|-----|--------|------|
| $V_{IL(NRST)}^{(1)}$ | NRST input low level voltage | 2.0V~5.5V | - | - | 0.3VDD | V |
| $V_{IH(NRST)}^{(1)}$ | NRST input high voltage | 2.0V~5.5V | 0.7VDD | - | - | |
| $V_{hys(NRST)}$ | NRST Schmitt trigger voltage hysteresis | 2.0V~5.5V | 115 | 220 | 315 | mV |
| R_{PU} | Weak pull-up equivalent resistance ⁽²⁾ | 2.0V~5.5V | 30 | 40 | 50 | kΩ |
| $V_{F(NRST)}^{(1)}$ | NRST input filter pulse | 2.0V~2.2V | - | - | 196 | ns |
| | | 3V~3.6V | - | - | 115 | |
| | | 4.5V~5.5V | - | - | 81 | |
| $V_{NF(NRST)}^{(1)}$ | NRST input unfiltered pulse | 2.0V~2.2V | 540 | - | - | ns |
| | | 3V~3.6V | 287 | - | - | |
| | | 4.5V~5.5V | 191 | - | - | |

- Guaranteed by design, not tested in production.
- The pull-up resistor is designed as a real resistor in series with a non-switchable PMOS implementation. The resistance of this PMOS switch is very small (about 10%).

Figure 4-8 Recommended NRST Pin Protection



- The reset network is to prevent parasitic reset.
- The user must ensure that the potential of the NRST pin can be below the maximum $V_{IL(NRST)}$, otherwise the MCU cannot get reset.

4.3.14 TIM characteristics

The parameters listed are guaranteed by design

Table 4-29 TIM characteristics

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|---|----------------------|----------|----------------|--------------|
| $t_{res(TIM)}$ | Timer Resolution Time | - | 1 | - | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 15.625 | - | ns |
| f_{EXT} | Timer external clock frequency for CH1 to CH4 | - | 0 | $f_{TIMCLK}/2$ | MHz |
| | | $f_{TIMCLK} = 64MHz$ | 0 | 32 | MHz |
| RestIM | Timer Resolution | - | - | 16 | bits |
| $t_{COUNTER}$ | 16-bit counter clock period when internal clock is selected | - | 1 | 65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 0.015625 | 1024 | μs |
| t_{MAX_COUNT} | Maximum possible count | - | - | 65536x65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | - | 67.109 | s |

Table 4-30 TIM2/3/4/5 characteristics

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|---|----------------------|----------|----------------|--------------|
| $t_{res(TIM)}$ | Timer Resolution Time | - | 1 | - | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 15.625 | - | ns |
| f_{EXT} | Timer external clock frequency for CH1 to CH4 | - | 0 | $f_{TIMCLK}/2$ | MHz |
| | | $f_{TIMCLK} = 64MHz$ | 0 | 32 | MHz |
| RestIM | Timer Resolution | - | - | 16 | bits |
| $t_{COUNTER}$ | 16-bit counter clock period when internal clock is selected | - | 1 | 65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 0.015625 | 1024 | μs |
| t_{MAX_COUNT} | Maximum possible count | - | - | 65536x65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | - | 67.109 | s |

Table 4-31 TIM6 characteristics

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|---|----------------------|----------|-------------|--------------|
| $t_{res(TIM)}$ | Timer Resolution Time | - | 1 | - | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 15.625 | - | ns |
| RestIM | Timer Resolution | - | - | 16 | bits |
| $t_{COUNTER}$ | 16-bit counter clock period when internal clock is selected | - | 1 | 65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | 0.015625 | 1024 | μs |
| t_{MAX_COUNT} | Maximum possible count | - | - | 65536x65536 | t_{TIMCLK} |
| | | $f_{TIMCLK} = 64MHz$ | - | 67.109 | s |

4.3.15 IWDG characteristics

Table 4-32 IWDG Maximum and minimum count reset times (LSI = 32KHz)

| Prescaler divider | IWDG_PREDIV.PD[2:0] | Min ⁽¹⁾ IWDG_RELV.REL[11:0]=0 | Max ⁽¹⁾ IWDG_RELV.REL[11:0]=0xFFFF | Unit |
|-------------------|---------------------|---|--|------|
| /4 | 000 | 0.125 | 512 | ms |
| /8 | 001 | 0.25 | 1024 | |
| /16 | 010 | 0.5 | 2048 | |

| | | | | |
|------|-----|---|-------|--|
| /32 | 011 | 1 | 4096 | |
| /64 | 100 | 2 | 8192 | |
| /128 | 101 | 4 | 16384 | |
| /256 | 11x | 8 | 32768 | |

1. Guaranteed by design, not tested in production.

4.3.16 WWDG characteristics

Table 4-33 WWDG Maximum and Minimum Count Reset Time (APB1 PCLK1 = 32MHz)

| Prescaler divider | WWDG_CFG.TIMERB[1:0] | Min ⁽¹⁾ WWDG_CFG.W[13:0]=0x3F | Max ⁽¹⁾ WWDG_CFG.W[13:0]=0x3FFF | Unit |
|-------------------|----------------------|---|---|------|
| /1 | 00 | 0.128 | 2089 | ms |
| /2 | 01 | 0.256 | 4178 | |
| /4 | 10 | 0.512 | 8356 | |
| /8 | 11 | 1.024 | 16712 | |

1. Guaranteed by design, not tested in production.

4.3.17 I2C characteristics

Unless otherwise specified, parameters are measured using ambient temperature, fPCLK frequency and VDD supply voltage in accordance with Table 4-4.

The I2C interface of the N32G05x products conforms to the standard I2C communication protocol with the following limitation: SDA and SCL are not "true" open-drain pins, and when configured as open-drain outputs, the PMOS tubes between the pin and VDD are turned off but still present.

The I2C interface characteristics are shown in the table below, and see Section 4.3.12 for details on the characteristics of the input/output multiplexing pins (SDA and SCL).

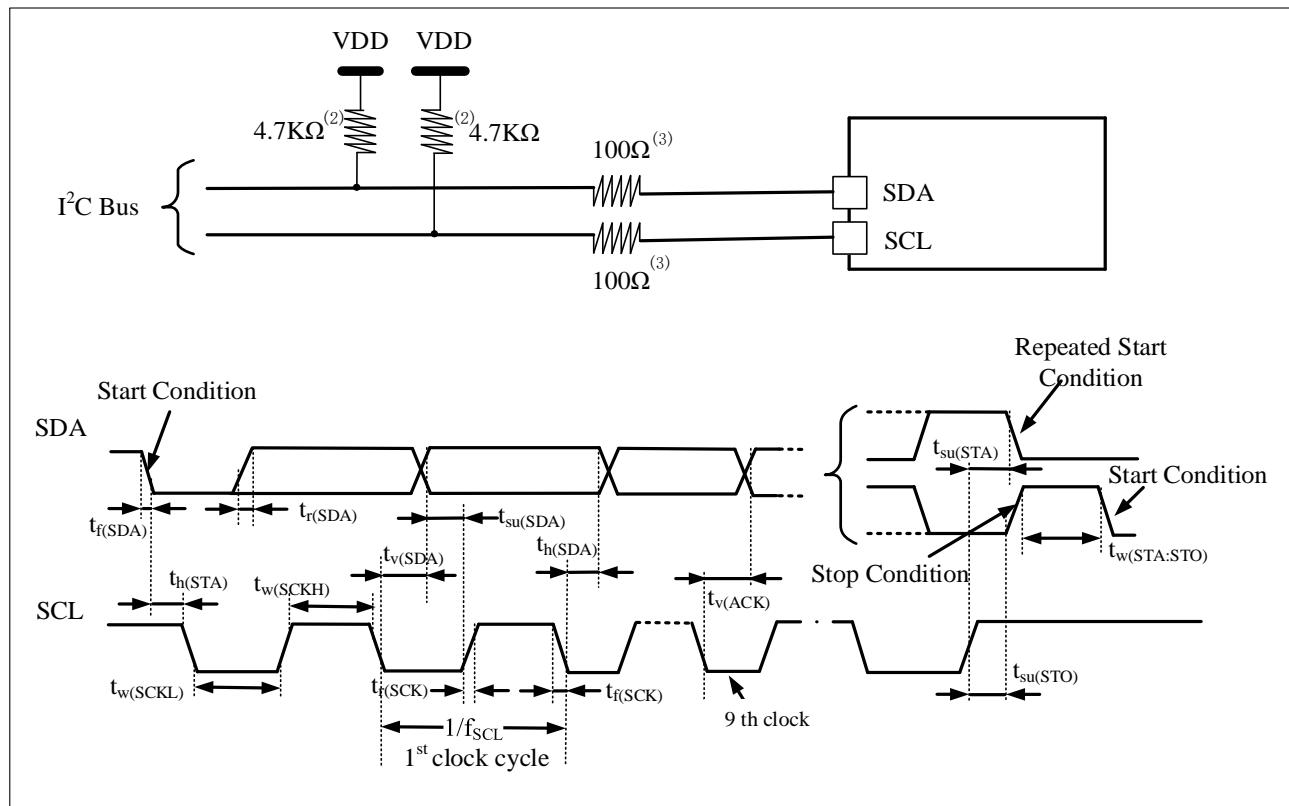
Table 4-34 I2C interface characteristics

| Symbol | Parameter | Standard model | | Fast mode | | Fast+ mode | | Unit |
|--|---|----------------|------|-----------------------|-----|------------|------|------|
| | | Min | Max | Min | Max | Min | Max | |
| f _{SCL} | I2C Interface Frequency | 0.0 | 100 | 0 | 400 | 0 | 1000 | KHz |
| t _{h(STA)} | Start condition hold time | 4.0 | - | 0.6 | - | 0.26 | - | μs |
| t _{w(SCLL)} | SCL clock low time | 4.7 | - | 1.3 | - | 0.50 | - | μs |
| t _{w(SCLH)} | SCL clock high time | 4.0 | - | 0.6 | - | 0.26 | - | μs |
| t _{su(STA)} | Repeat Start Condition Establishment Time | 4.7 | - | 0.6 | - | 0.26 | - | μs |
| t _{h(SDA)} | SDA data hold time | - | 3.45 | - | 0.9 | - | 0.4 | μs |
| t _{su(SDA)} | SDA build-up time | 250 | - | 100 | - | 50 | - | ns |
| t _{r(SDA)} t _{r(SCL)} | SDA and SCL rise time | - | 1000 | 20+0.1 C _b | 300 | - | 120 | ns |
| t _{f(SDA)} t _{f(SCL)} | SDA and SCL fall time | - | 300 | 20+0.1 C _b | 300 | - | 120 | ns |
| t _{su(STO)} | Stop condition establishment time | 4.0 | - | 0.6 | - | 0.26 | - | μs |
| t _{w(STO:STA)} | Stop condition to start condition time (bus idle) | 4.7 | - | 1.3 | - | 0.50 | - | μs |
| C _b | Capacitive load per bus | - | 400 | - | 400 | - | 550 | pf |

| | | | | | | | | |
|--------------|---|---|------|---|-----|---|------|---------|
| t_{SP} | Spike pulse width suppressed by analog filter in standard and fast mode | - | - | 0 | 50 | 0 | 50 | ns |
| $t_{v(SDA)}$ | Data validity time | - | 3.45 | - | 0.9 | - | 0.45 | μs |
| $t_{v(ACK)}$ | Answer validity time | - | 3.45 | - | 0.9 | - | 0.45 | μs |

1. Guaranteed by design, not tested in production.
2. f_{PCLK} must be greater than 2MHz to achieve maximum frequency for standard mode I2C. f_{PCLK} must be greater than 4MHz to achieve maximum frequency for fast mode I2C.

Figure 4-9 I2C bus AC waveform and measurement circuit ⁽¹⁾



1. The measurement points are set at 0.3V_{DD} and 0.7V_{DD}.
2. Pull-up resistor resistance value depends on I²C interface speed.
3. The resistance value depends on the actual electrical characteristics. It is possible to leave the serial resistor unconnected and connect the signal line directly.

4.3.18 SPI characteristics

Unless otherwise noted, SPI parameters are measured using ambient temperature, f_{PCLK} frequency, and V_{DD} supply voltage conforming to the conditions in Table 4-4.

For details on the characteristics of the input-output multiplexing function pins (NSS, SCLK, MOSI, MISO of SPI), see Section 4.3.12.

Table 4-35 SPI characteristics ⁽⁴⁾

| Symbol | Parameter | Conditions | Min | Max | Unit |
|--------|-----------|------------|-----|-----|------|
|--------|-----------|------------|-----|-----|------|

| | | | | | |
|--|----------------------------------|---------------------------------------|-----------------|-----------------|-----|
| f_{SCLK} $1/t_c(SCLK)$ | SPI Clock Frequency | Master Mode | - | 16 | MHz |
| | | Slave Mode | - | 12 | |
| $t_{r(SCLK)}t_{f(SCLK)}$ | SPI clock rise and fall times | load capacitance : $C = 30\text{pF}$ | - | 11 | ns |
| DuCy(SCK) | SPI slave input clock duty cycle | SPI Slave Mode | 35 | 70 | % |
| $t_{su(NSS)}^{(1)}$ | NSS Establishment Time | Slave Mode | $4t_{PCLK}$ | - | ns |
| $t_{h(NSS)}^{(1)}$ | NSS Hold Time | Slave Mode | $2t_{PCLK}$ | - | ns |
| $t_{w(SCLKH)}^{(1)}$ $t_{w(SCLKL)}^{(1)}$ | SCLK high and low time | Master Mode | $t_{PCLK/BR-2}$ | $t_{PCLK/BR+2}$ | ns |
| $t_{su(MI)}^{(1)}$ | Data Input Establishment Time | Master Mode | 5 | - | ns |
| $t_{su(SI)}^{(1)}$ | | Slave Mode | 5 | - | |
| $t_{h(MI)}^{(1)}$ | Data input hold time | Master Mode | 5 | - | ns |
| $t_{h(SI)}^{(1)}$ | | Slave Mode | 6 | - | |
| $t_{a(SO)}^{(1)(2)}$ | Data output access time | Slave Mode, $f_{PCLK} = 20\text{MHz}$ | 0 | $3t_{PCLK}$ | ns |
| $t_{dis(SO)}^{(1)(3)}$ | Data output disable time | Slave Mode | 2 | 10 | ns |
| $t_{v(SO)}^{(1)}$ | Data output valid time | Slave Mode(After enabling edge) | - | 31 | ns |
| $t_{v(MO)}^{(1)}$ | | Master Mode(After enabling edge) | - | 15 | |
| $t_{h(SO)}^{(1)}$ | Data output hold time | Slave Mode(After enabling edge) | 7 | - | ns |
| $t_{h(MO)}^{(1)}$ | | Master Mode(After enabling edge) | 0 | - | |

1. Evaluated from a combination of $VDD=3.3V/5V$, load capacitance $C=20\text{pF}$, not tested in production.
2. Minimum value indicates the minimum time to drive the output, maximum value indicates the maximum time to get the data correctly.
3. Minimum value indicates the minimum time to turn off the output, maximum value indicates the maximum time to place the data line in a high resistance state.

Figure 4-6 SPI sequence diagram - slave mode and CPHA=0

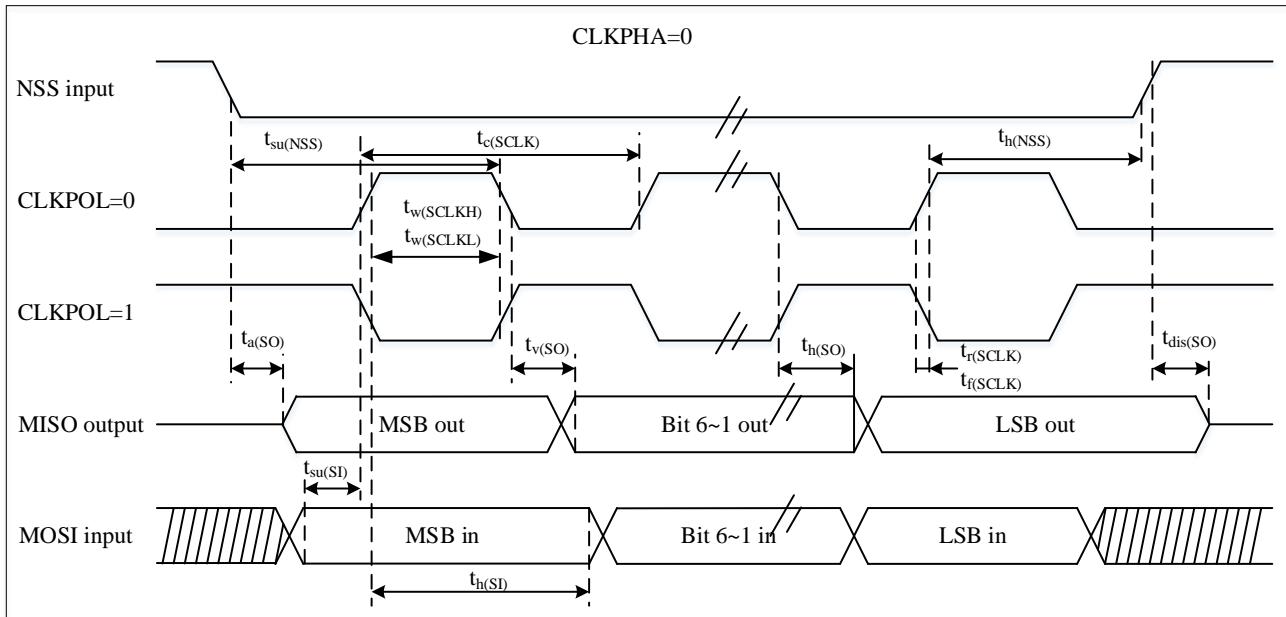
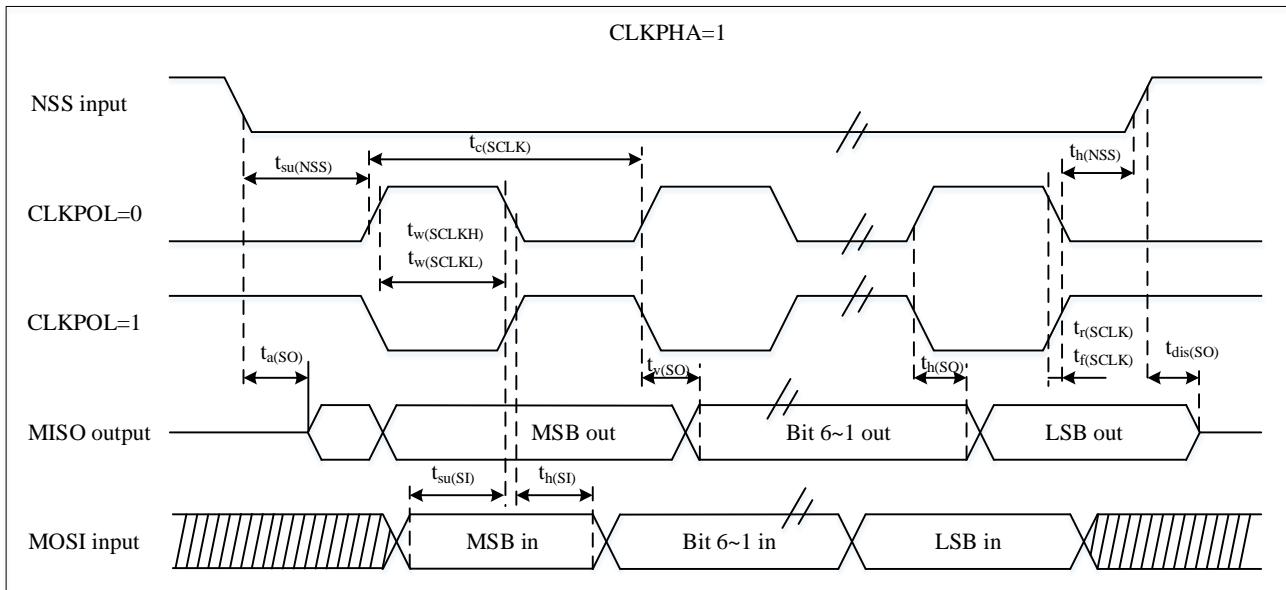
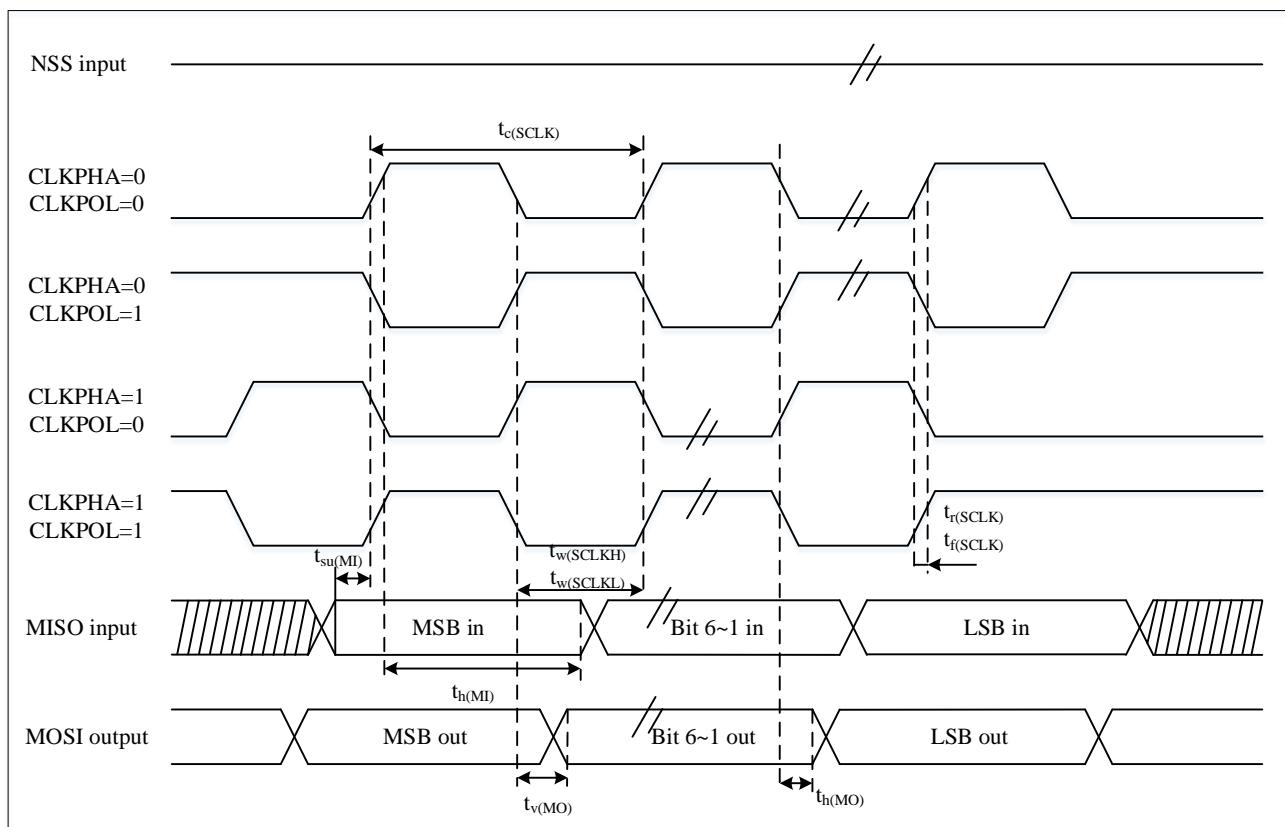


Figure 4-7 SPI sequence diagram - slave mode and CPHA=1⁽¹⁾



1. The measurement points were set at the CMOS level of 0.3 V_{DD} and 0.7 V_{DD}.

Figure 4-8 SPI timing diagram-master mode⁽¹⁾



1. The measurement points are set at CMOS level: 0.3 V_{DD} and 0.7 V_{DD}.

4.3.19 CAN Interface Characteristics

For details on the characteristics of the input/output multiplexing function pins (CAN_TX and CAN_RX), see Section 4.3.12.

4.3.20 12-bit ADC electrical parameters

Unless otherwise noted, the parameters of Table 4-4 are measured using an ambient temperature, f_{HCLK} frequency, and V_{DD} supply voltage that meet the conditions of Table 4-4.

Table 4-36 ADC characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|----------------------------------|--------------------------------------|------------|---|-----------------|-------------------|--------------------|
| V _{DD} ⁽¹⁾ | Supply Voltage | - | 2.4 ⁽²⁾ | - | 5.5 | V |
| V _{REF+} | Positive Reference Voltage | - | | V _{DD} | | V |
| f _{ADC} | ADC Clock Frequency | - | - | - | 24 | MHz |
| f _s ⁽¹⁾ | Sampling Rate | - | 0.03 | - | 1 | Msps |
| V _{AIN} | Conversion Voltage Range | - | 0 (VSSA or VREF-connected to ground) | - | V _{REF+} | V |
| R _{AIN} ⁽¹⁾ | External Input Impedance | - | See formula 1 | | | Ω |
| R _{ADC} ⁽¹⁾ | ADC Input Resistance | VDD=3.3V | - | 750 | - | Ω |
| | | VDD=5.0V | - | 450 | | Ω |
| C _{ADC} ⁽¹⁾ | Internal sample and hold capacitance | - | - | 26 | - | pF |
| SNDR | Signal-to-noise distortion | VDD=3.3V | - | 58.5 | - | dB |
| | | VDD=5.0V | - | 58.9 | - | dB |
| T _S ⁽¹⁾ | Number of Sampling Cycles | - | 6 | - | - | 1/f _{ADC} |
| t _{STAB} ⁽¹⁾ | Power-up time | - | 48 | - | - | 1/f _{ADC} |
| t _{CONV} ⁽¹⁾ | Conversion time | - | | 12 | | 1/f _{ADC} |
| I _{ADC} | ADC current consumption | - | - | 1.47 | - | mA |

- Guaranteed by design, not tested in production.
- ADC performance metrics degrade with 2.4V supply

Formula 1: Maximum R_{AIN} formula

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The above equation (Equation 1) is used to determine the maximum external impedance such that the error can be less than 1/4 LSB. where N=12 (indicating 12-bit resolution).

Table 4-37 ADC sampling time ⁽¹⁾

| Resolution | Rin (kΩ) | Minimum sampling time (ns) |
|------------|----------|----------------------------|
| 12-bit | 0.9 | 500 |
| | 1.2 | 583 |
| | 2.2 | 833 |
| | 3.8 | 1250 |
| | 8.1 | 2333 |
| | 10.8 | 3000 |
| | 18.7 | 5000 |
| | 28.9 | 7583 |
| | 38.5 | 10000 |
| | 61.6 | 15833 |

- Guaranteed by design, not tested in production.

 Table 4-38 ADC accuracy ⁽¹⁾

| Symbol | Parameter | Conditions | Typ | Max ⁽²⁾ | Unit |
|--------|------------------------------|---|-----------|--------------------|------|
| EO | Offset Error | $f_{ADC} = 24 \text{ MHz}$, Sample rate=1M sps, $V_{DDA} = 3.3V$, $T_A = 25^\circ\text{C}$ | ± 2 | - | LSB |
| ED | Differential Linearity Error | | ± 0.6 | ± 5 | |
| EL | Integral Linearity Error | | ± 1.5 | ± 2 | |
| EO | Offset Error | $f_{ADC} = 24 \text{ MHz}$, Sample rate=1M sps, $V_{DDA} = 5.0V$, $T_A = 25^\circ\text{C}$ | ± 2 | - | Bits |
| ED | Differential Linear Error | | ± 0.6 | 1.5 | |
| EL | Integral Linear Error | | ± 1.5 | 2.5 | |
| ENOB | Effective number of bits | $f_{HCLK} = 64\text{MHz}$ (clock source HSI_8M), $f_{ADC} = 24 \text{ MHz}$, sample rate=1M sps, $T_A = 25^\circ\text{C}$ | 9.4 | - | Bits |
| | | $f_{HCLK} = 64\text{MHz}$ (clock source HSE), $f_{ADC} = 16 \text{ MHz}$, sample rate=667K sps, $T_A = 25^\circ\text{C}$ | 10.3 | - | |

- ADC Accuracy vs. Reverse Current Injection: Reverse current injection on any standard analog input pin needs to be avoided, as it can significantly degrade the accuracy of a conversion being performed on another analog input pin. It is recommended that a Schottky diode be added to the standard analog pin (between the pin and ground) where the reverse injection current may be generated.
- Guaranteed by characterization tests, not tested in production.

Figure 4-9 ADC Accuracy Characteristics

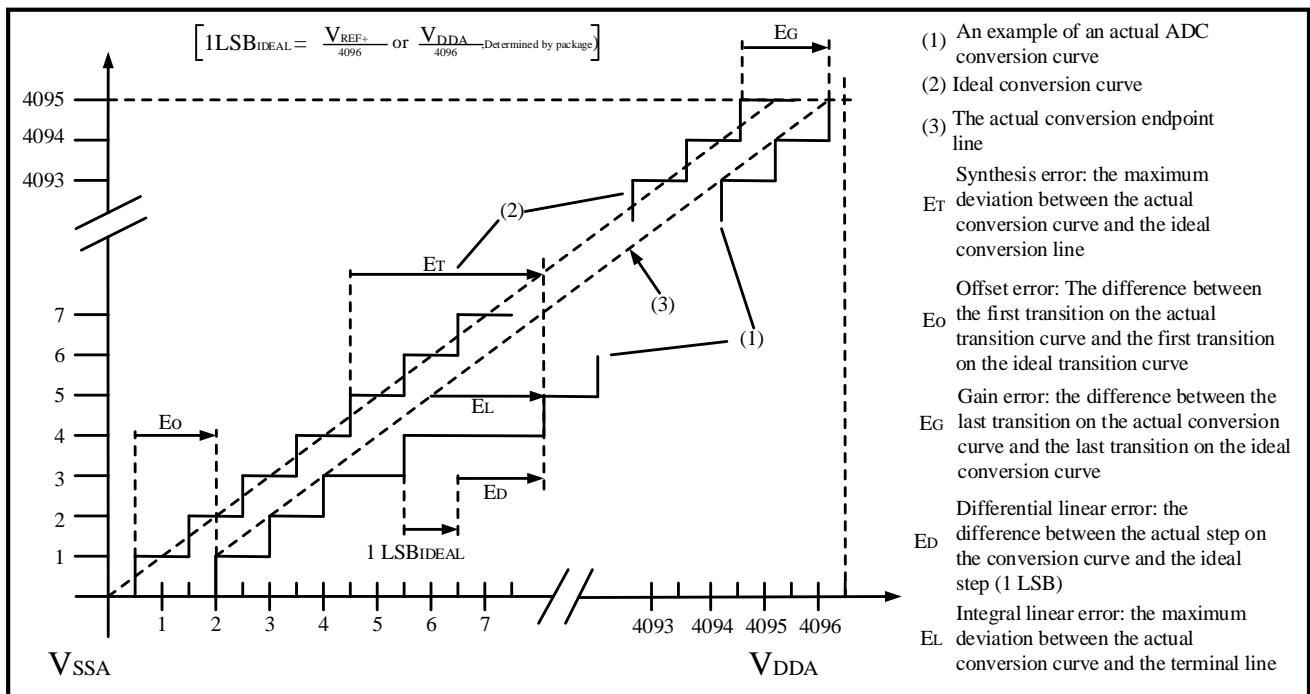
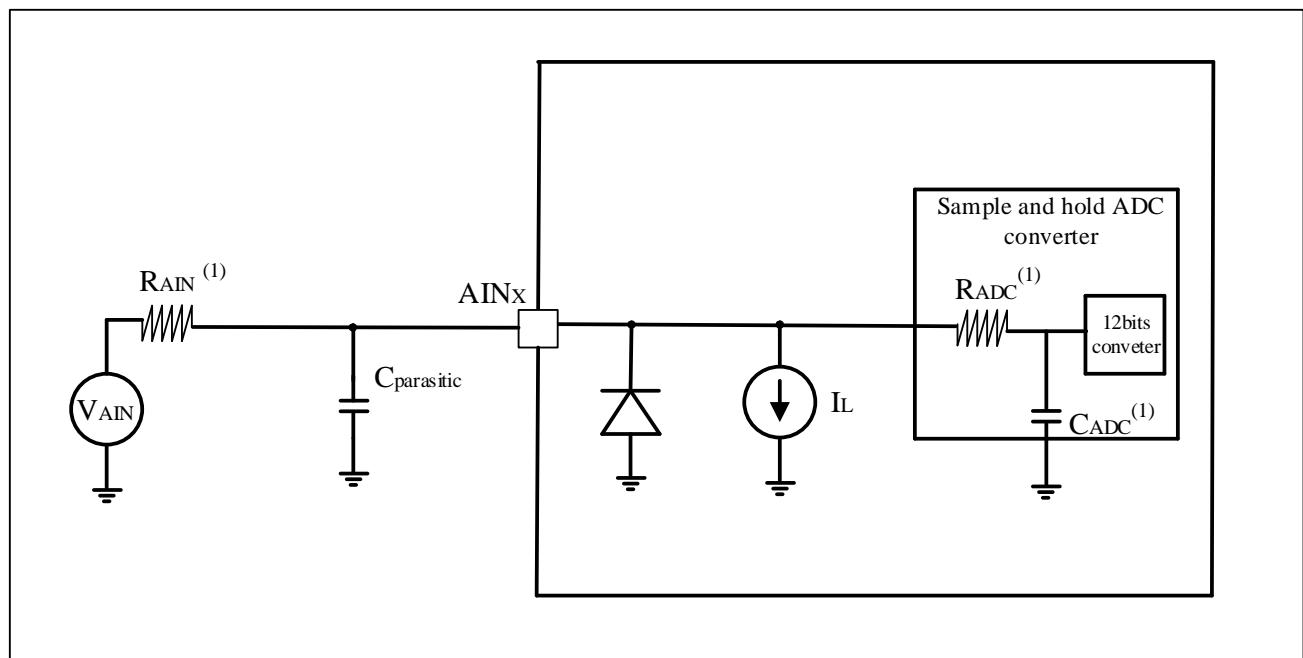


Figure 4-10 ADC typical connection diagram



- See Table 4-36 for R_{AIN} , R_{ADC} , and C_{ADC} values.
- $C_{\text{parasitic}}$ represents the parasitic capacitance (approximately 7pF) on the PCB (related to soldering and PCB layout quality) and pads. Larger values of $C_{\text{parasitic}}$ will reduce the accuracy of the conversion and the solution is to reduce the f_{ADC} .

4.3.21 12-bit DAC Electrical Parameters

Unless otherwise noted, the parameters in Table 4-39 DAC Characteristics are measured using ambient temperature, f_{HCLK} frequency, and V_{DDA} supply voltage that meet the conditions in Table 4-4.

Table 4-39 V_{REFP} characteristics

| Symbol | Parameter | Min | Typ | Max | Unit | marginal notes |
|-------------------|---|------|------|--------------------------|------|--|
| V _{DDA} | Analog Supply Voltage | 2.97 | - | 5.5 | V | - |
| V _{REF+} | Reference Voltage | 2.97 | - | 5.5 | V | V _{REF+} must always be lower than V _{DDA} |
| V _{SSA} | Ground wire | 0 | - | 0 | V | - |
| R _L | Load resistance with buffer on | 5 | - | - | kΩ | Minimum load resistance between DAC_OUT and V _{SSA} |
| C _L | Load capacitance | - | - | 50 | pF | Maximum capacitance on the DAC_OUT pin |
| DAC_OUT Min | DAC_OUT voltage with buffer on | 0.2 | - | - | V | The maximum DAC output span is given When V _{REF+} =5.5V corresponds to 12-bit input values 0x095~0xF6B. |
| DAC_OUT Max | DAC_OUT voltage with buffer on | - | - | V _{REF+} - 0.2 | V | When V _{REF+} =2.97V corresponds to 12-bit input values 0x114~0xEEC. |
| | DAC_OUT voltage when buffer is off | - | - | V _{REF+} - 5LSB | V | |
| I _{DD} | In standstill mode (standby mode) DAC DC consumption (V _{DDD} +V _{DDA} +V _{REF+}) | - | 900 | 1500 | μA | No load, input median 0x800 |
| | | - | 1400 | 1600 | | No load, input maximum when V _{REF+} = 5.5V |
| I _{DDQ} | In power-down mode DAC DC consumption (V _{DDD} +V _{DDA} +V _{REF+}) | - | 10 | 2200 | nA | unloaded |
| | In power-down mode DAC DC consumption (V _{DDA} +V _{REF+}) | - | 10 | 2200 | | |
| DNL | Nonlinear distortion (deviation between 2 consecutive codes) | - | - | ±2.4 | LSB | DAC configured to 10 bits (always B1=B0=0) |
| INL | Nonlinear accumulation (deviation between the value measured at code i and the line between code 0 and code 4095) | - | - | ±6 | LSB | DAC configured for 12-bit |
| misalignment | Offset error (deviation between the measured value at code 0x800 and the ideal value V _{REF+} /2) | - | ±12 | - | mV | DAC configured for 12-bit |
| | | - | ±12 | - | LSB | When V _{REF+} =3.3V, the DAC is configured to 12 bits. |
| gain error | gain error | - | ±0.6 | - | % | DAC configured for 12-bit |
| Amplifier Gain | Amplifier gain with open loop | 50 | 85 | - | dB | 5kΩ load (maximum load) |
| tSETTLING | Setup time (full range: 10-bit input code changes from minimum to maximum value, DAC_OUT reaches ±1 LSB of its final value) | - | 3 | 4 | μs | C _{LOAD} ≤ 50pF R _{LOAD} ≥ 5kΩ |

| | | | | | | |
|--------------|---|---|-----|-----|------|--|
| refresh rate | The maximum frequency of the correct DAC_OUT is obtained when the input code is a small change (from the value i to i+1LSB) | - | - | 1 | MS/s | $C_{LOAD} \leq 50\text{pF}$ $R_{LOAD} \geq 5\text{k}\Omega$ |
| tWAKEUP | Wake-up time from off state (PDV18 changes from 1 to 0) | - | 6.5 | 10 | μs | $C_{LOAD} \leq 50\text{pF}, R_{LOAD} \geq 5\text{k}\Omega$ Input code between minimum and maximum possible values |
| PSRR+ | Supply rejection ratio (relative to VDD33A) (static DC measurement) | - | -60 | -40 | dB | No R_{LOAD} , $C_{LOAD} \leq 50\text{pF}$ |

1. Guaranteed by design, not tested in production.

4.3.22 COMP characteristics

Unless otherwise noted, parameters are measured using ambient temperature, fHCLK frequency, and VDD supply voltage in accordance with the conditions in Table 4-4.

Table 4-40 COMP characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-----------------------------------|---|---|-----|-----|-----|------|
| V _{DD} | Analog supply voltage | normal mode VIN | 2.4 | 3.3 | 5.5 | V |
| V _{IN} | Input Voltage Range | | 0 | - | VDD | |
| t _{START} ⁽¹⁾ | Comparator start-up build-up time | - | - | - | 7 | us |
| t _d | Propagation delay for 200mV step with 100mV overdrive | Falling edge | - | 110 | - | ns |
| | | Rising edge | - | 102 | - | |
| V _{OFFSET} | Comparator Input Offset Error | VIN | - | ±5 | ±20 | mV |
| V _{hys} | Comparison Hysteresis Voltage | No hysteresis | - | 0 | - | mV |
| | | Low hysteresis | - | 7 | - | |
| | | Medium hysteresis | - | 17 | - | |
| | | High hysteresis | - | 32 | - | |
| I _{DD} | Comparator Current Consumption | Static | - | 167 | - | μA |
| | | cmp With 50 kHz ±100 mV overdrive square signal | - | 168 | - | |
| | | cmp static with 1* 6bit dac on | - | 207 | - | |
| | | cmp static with 2* 6bit dac on | - | 247 | - | |

1. Guaranteed by design and comprehensive evaluation, not tested in production.

4.3.23 Segment LCD characteristics

Unless otherwise noted, parameters are measured using ambient temperature, fHCLK frequency, and VDD supply voltage in accordance with the conditions in Table 4-4.

Table 4-41 LCD characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|------------------|--|--|-----|------|-----|------|
| V _{LCD} | LCD external voltage | | - | 5.0 | 5.5 | V |
| I _{LCD} | Supply current from V _{DD} at V _{DD} = 5.0 V | Buffer off + only high resistance on | - | 4.5 | - | μA |
| | | Buffer off + both high and low resistance on | - | 24.7 | - | μA |

| | | | | | | |
|-----------------|--|---------------------------------|----------------------|-------|----|---------|
| IVLCD | Supply current from V_{LCD} ($V_{LCD} = 5.0V$) + high resistance turn on | Buffer on (BUFEN = 1, 1/2 Bias) | - | 7.2 | - | μA |
| | | Buffer on (BUFEN = 1, 1/3 Bias) | - | 12.86 | - | |
| | | Buffer on (BUFEN = 1, 1/4 Bias) | - | 12.86 | - | |
| R _{HN} | Total High Resistance Value of Low Driving Resistor Network | - | 1 | - | MΩ | |
| R _{LN} | Total low resistance value of high driving resistance network | - | 200 | - | KΩ | |
| V ₄₄ | Segment/Common highest level voltage | - | V _{LCD} | - | V | |
| V ₃₄ | Segment/Common 3/4 level voltage | - | 3/4 V _{LCD} | - | | |
| V ₂₃ | Segment/Common 2/3 level voltage | - | 2/3 V _{LCD} | - | | |
| V ₁₂ | Segment/Common 1/2 level voltage | - | 1/2 V _{LCD} | - | | |
| V ₁₃ | Segment/Common 1/3 level voltage | - | 1/3 V _{LCD} | - | | |
| V ₁₄ | Segment/Common 1/4 level voltage | - | 1/4 V _{LCD} | - | | |
| V ₀ | Segment/Common lowest level voltage | - | 0 | - | | |

Table 4-42 LCD Adjustable contrast⁽¹⁾

| gear level | VLCD(HR) | | | VLCD(LR) | | |
|------------|----------|------------|-----|----------|------------|-----|
| | Min | Typ | Max | Min | Typ | Max |
| 0 | - | 1.00 * VCC | - | - | 1.00 * VCC | - |
| 1 | - | 0.97* VCC | - | - | 0.96 * VCC | - |
| 2 | - | 0.94 * VCC | - | - | 0.92* VCC | - |
| 3 | - | 0.9* VCC | - | - | 0.88* VCC | - |
| 4 | - | 0.87* VCC | - | - | 0.84 * VCC | - |
| 5 | - | 0.84* VCC | - | - | 0.8* VCC | - |
| 6 | - | 0.8 * VCC | - | - | 0.76 * VCC | - |
| 7 | - | 0.77* VCC | - | - | 0.73 * VCC | - |
| 8 | - | 0.74 * VCC | - | - | 0.7* VCC | - |
| 9 | - | 0.7* VCC | - | - | 0.66* VCC | - |
| 10 | - | 0.67* VCC | - | - | 0.63 * VCC | - |
| 11 | - | 0.64* VCC | - | - | 0.6 * VCC | - |
| 12 | - | 0.61 * VCC | - | - | 0.57* VCC | - |
| 13 | - | 0.58 * VCC | - | - | 0.53* VCC | - |
| 14 | - | 0.54* VCC | - | - | 0.5* VCC | - |
| 15 | - | 0.5 * VCC | - | - | 0.47 * VCC | - |

1. Guaranteed by design and comprehensive evaluation, not tested in production.

4.3.24 Temperature sensor characteristics

Unless otherwise noted, parameters are measured using ambient temperature, fHCLK frequency, and VDD supply voltage that meet the conditions of Table 4-4.

Table 4-43 Temperature sensor characteristics

| Symbol | Parameter | Min | Typ | Max | Unit |
|--------|-----------|-----|-----|-----|------|
| | | | | | |

| $T_L^{(1)}$ | V _{SENSE} linearity with respect to temperature | - | ± 1 | ± 5 | °C |
|---------------------------------------|--|------|---------|---------|--------|
| Avg_Slope ⁽¹⁾ | Average Slope | -3.7 | -3.9 | -4.3 | mV/ °C |
| $V_{25}^{(1)}$ | Voltage at 25 °C | - | 1.34 | - | V |
| t _{START} ⁽¹⁾ | Build-up time | 4 | - | 10 | μs |
| T _{S_temp} ⁽²⁾⁽³⁾ | ADC sampling time when reading temperature | 8.2 | - | 17.1 | μs |

1. Guaranteed by characterization test results, not tested in production.
2. Guaranteed by design, not tested in production.
3. The shortest sampling time can be determined by the application program through multiple cycles.

5 Package information

5.1 LQFP64 (14x14mm)

Figure 5-1 N32G052RBL7 package outline

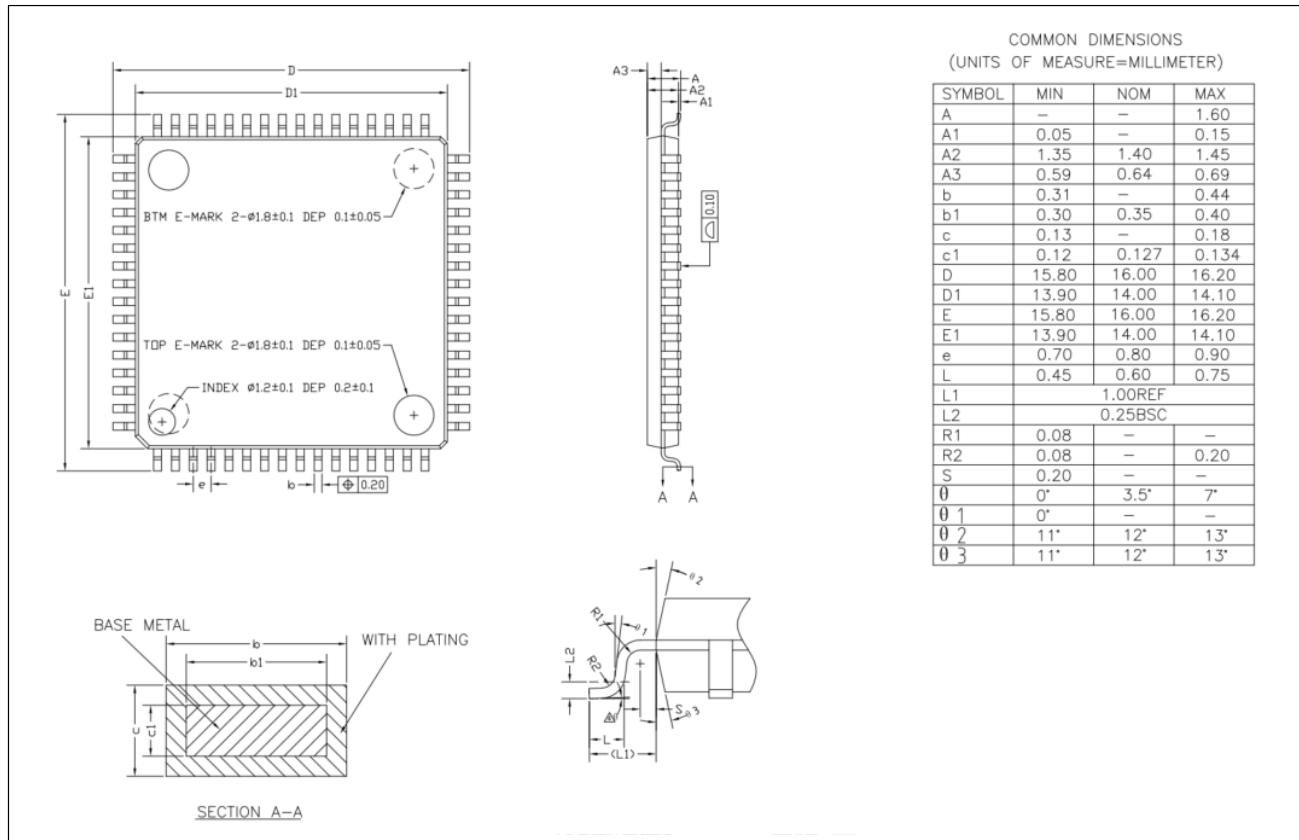
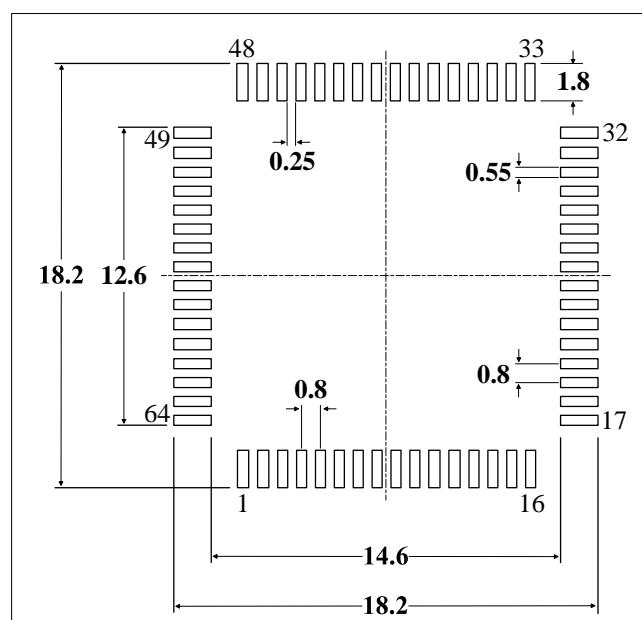


Figure 5-2 Suggestions for LQFP64 (14x14mm) package solder pads⁽¹⁾



1. The unit of measurement is millimeters

5.2 LQFP64 (10x10mm)

Figure 5-3 N32G052RBL7B package outline

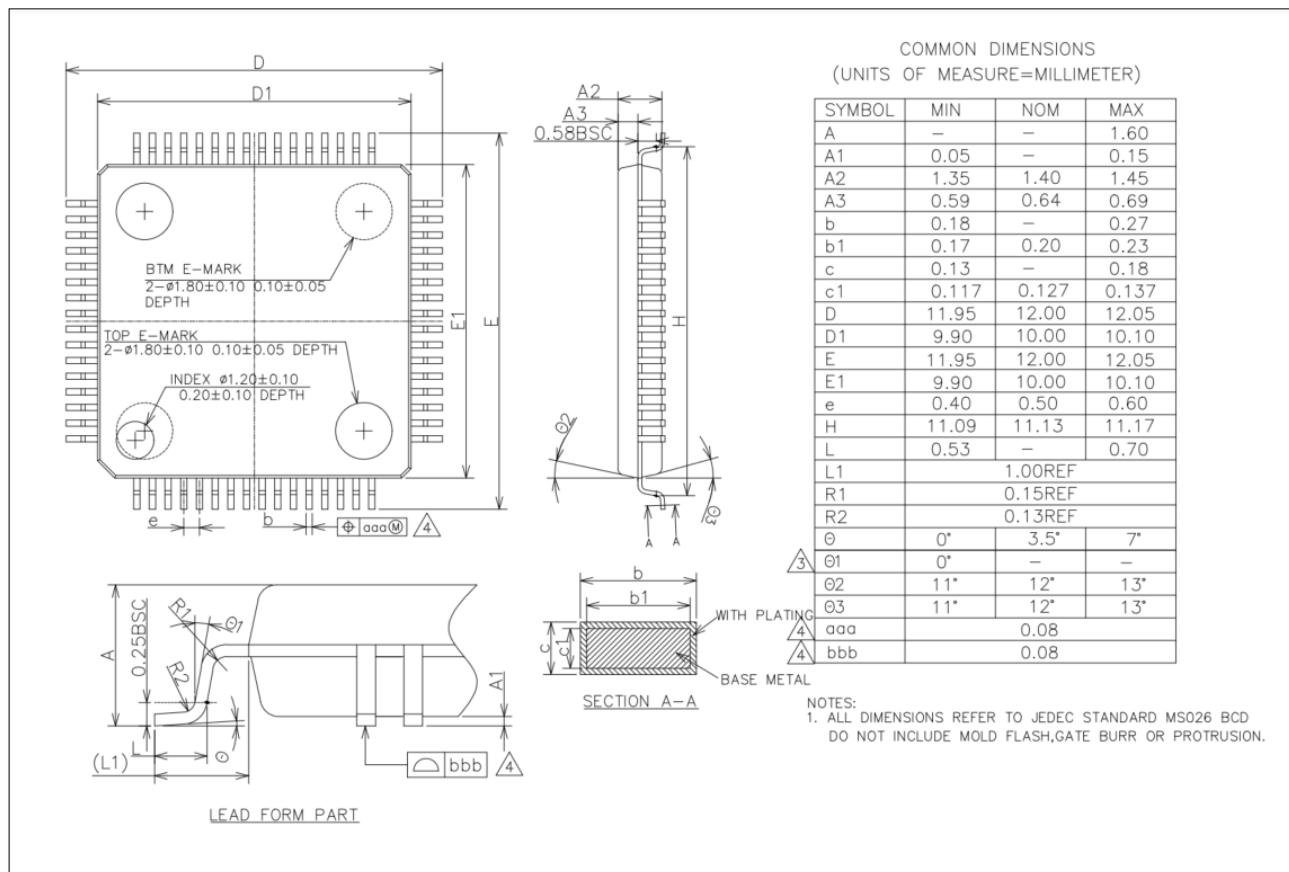
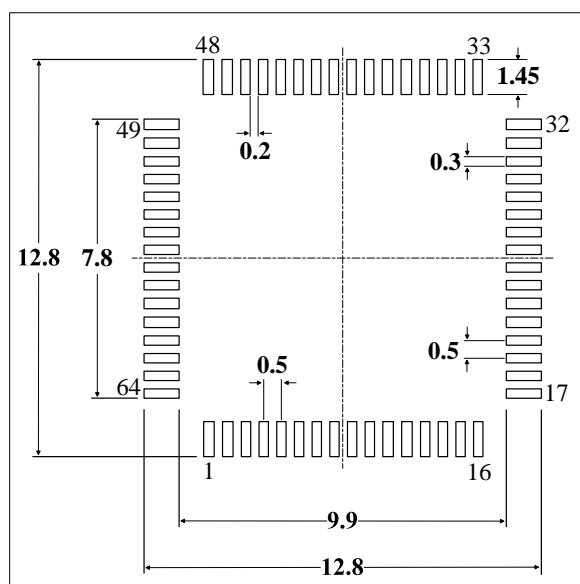


Figure 5-4 Suggestions for LQFP64 (10x10mm) package solder pads⁽¹⁾



1. The unit of measurement is millimeters

5.3 LQFP64 (7x7mm)

Figure 5-5 N32G052RBL7C package outline

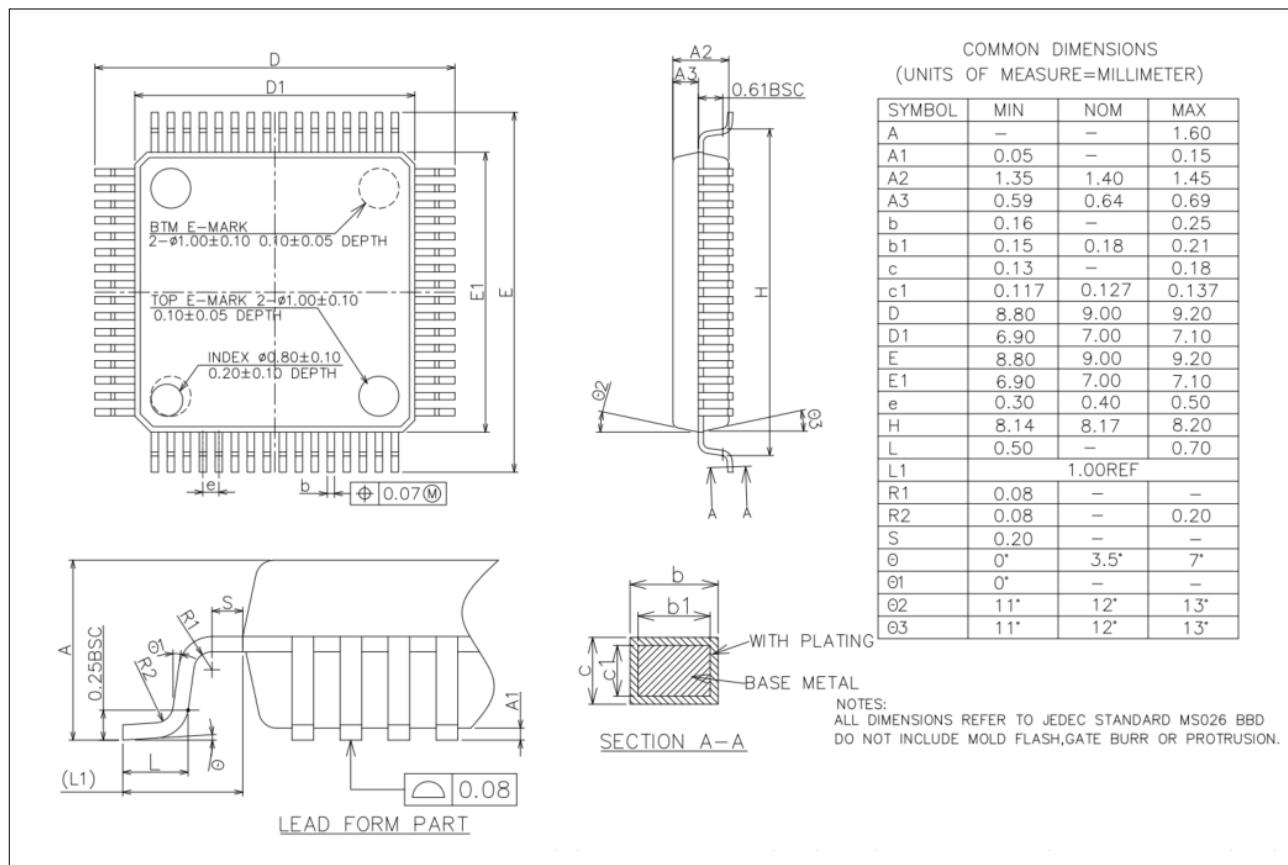
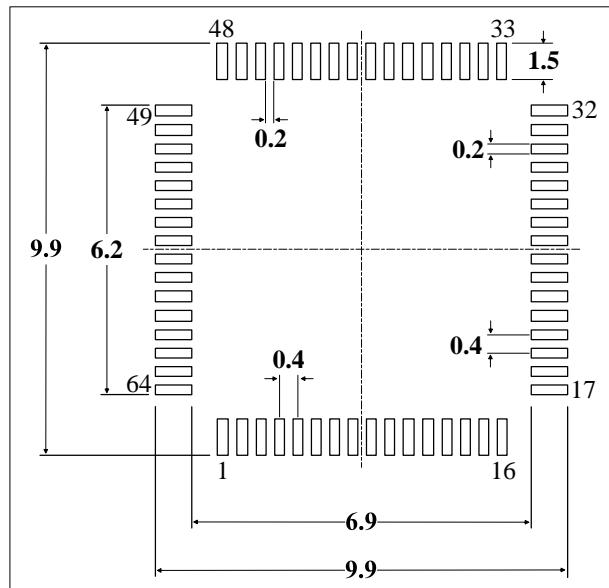


Figure 5-6 Suggestions for LQFP64 (7x7mm) package solder pads⁽¹⁾



1. The unit of measurement is millimeters

5.4 LQFP48 (7x7mm)

Figure 5-7 N32G052CBL7 package outline

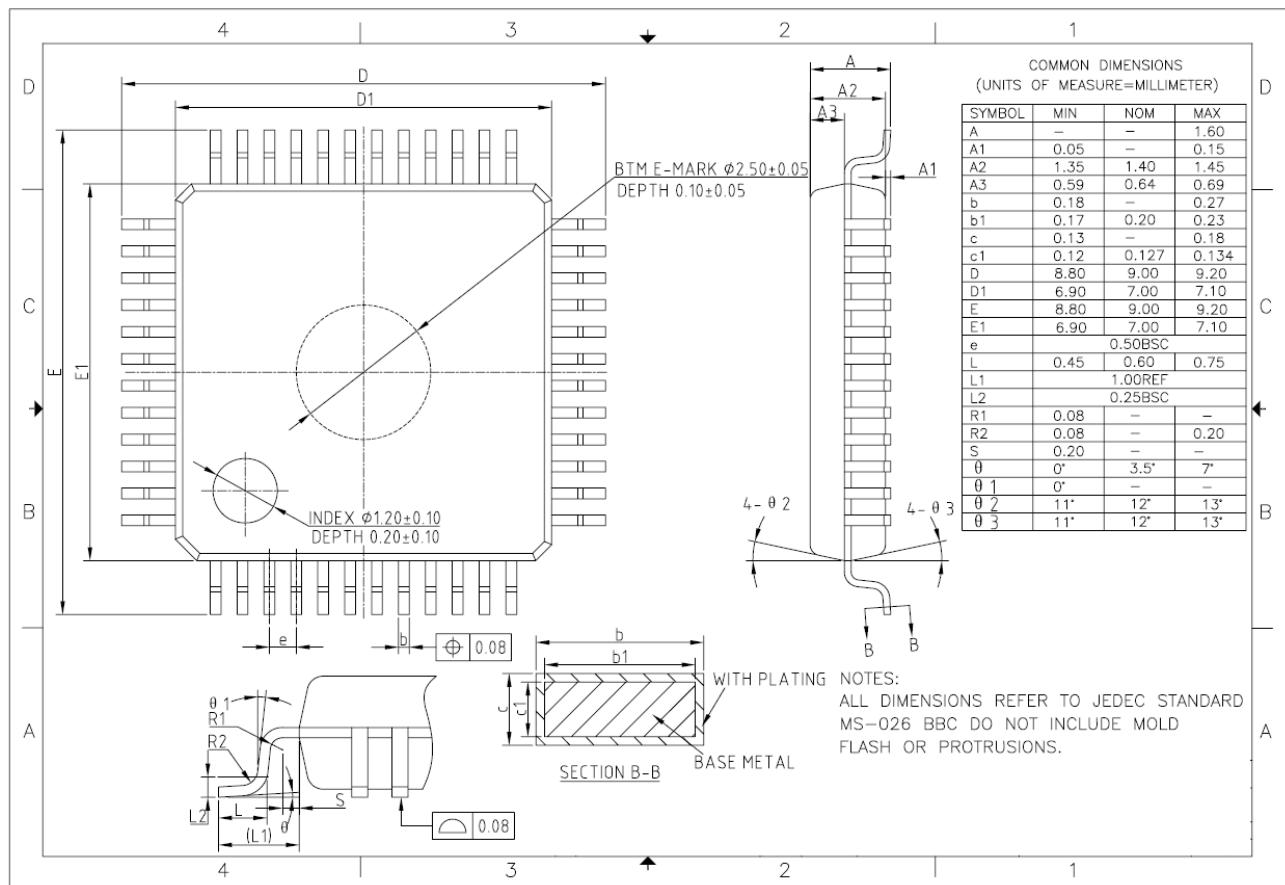
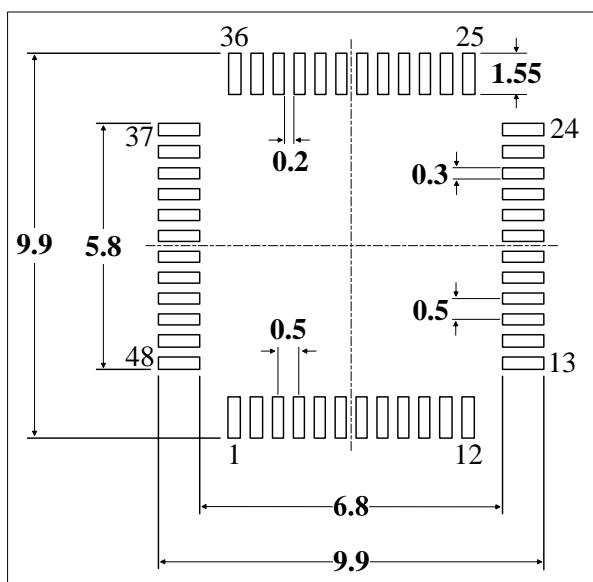


Figure 5-8 Suggestions for LQFP48 (7x7mm) package solder pads⁽¹⁾



1. The unit of measurement is millimeters

5.5 LQFP44 (10x10mm)

Figure 5-9 N32G052SBL7/ N32G052SBL7A package outline

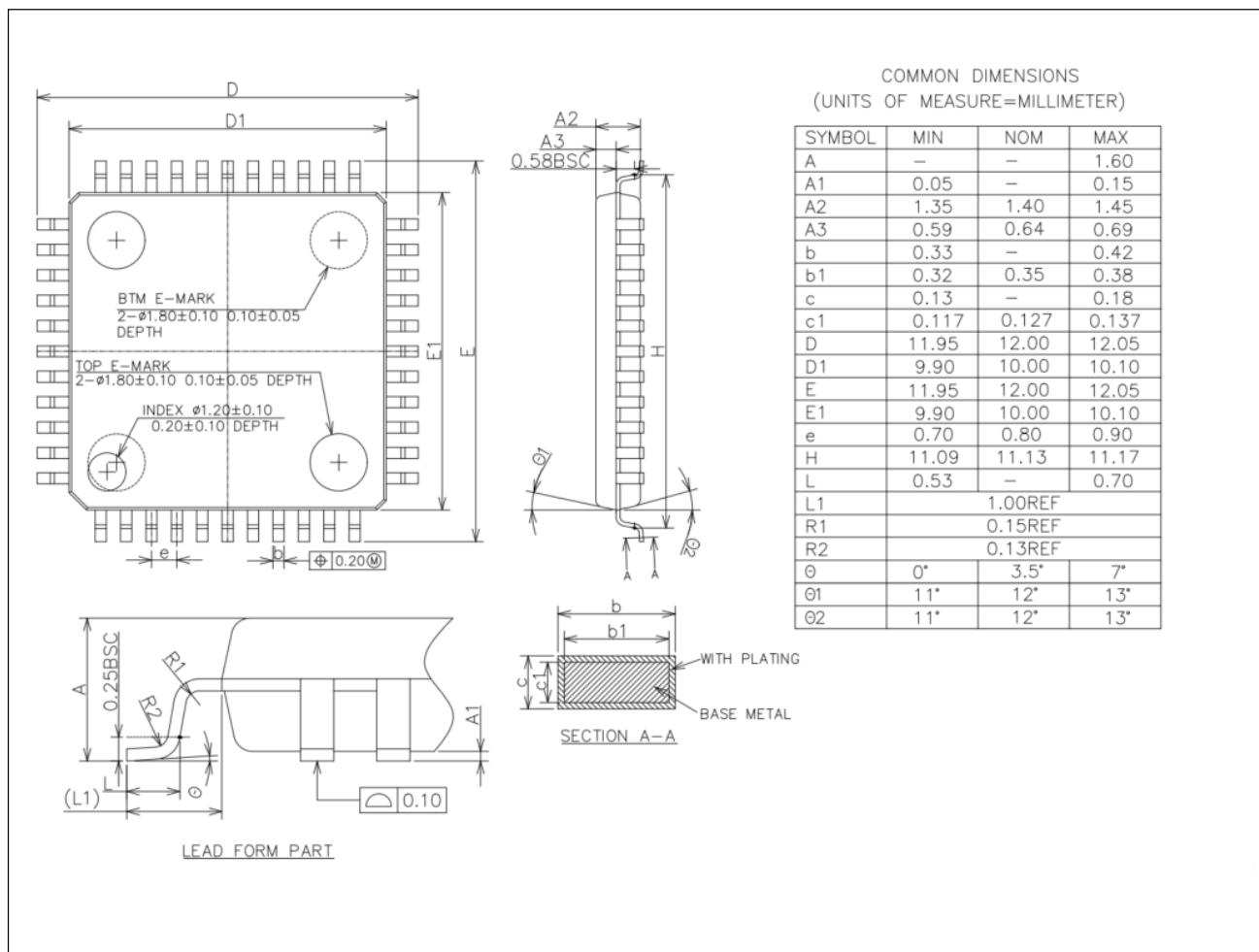
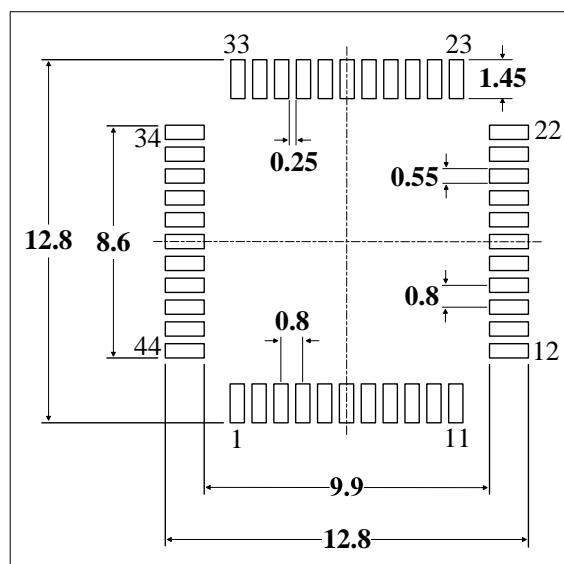


Figure 5-10 Suggestions for LQFP44(10x10mm) package solder pads⁽¹⁾



1. The unit of measurement is millimeters

5.6 QFN32 (5x5mm)

Figure 5-11 N32G052KBQ7 package outline

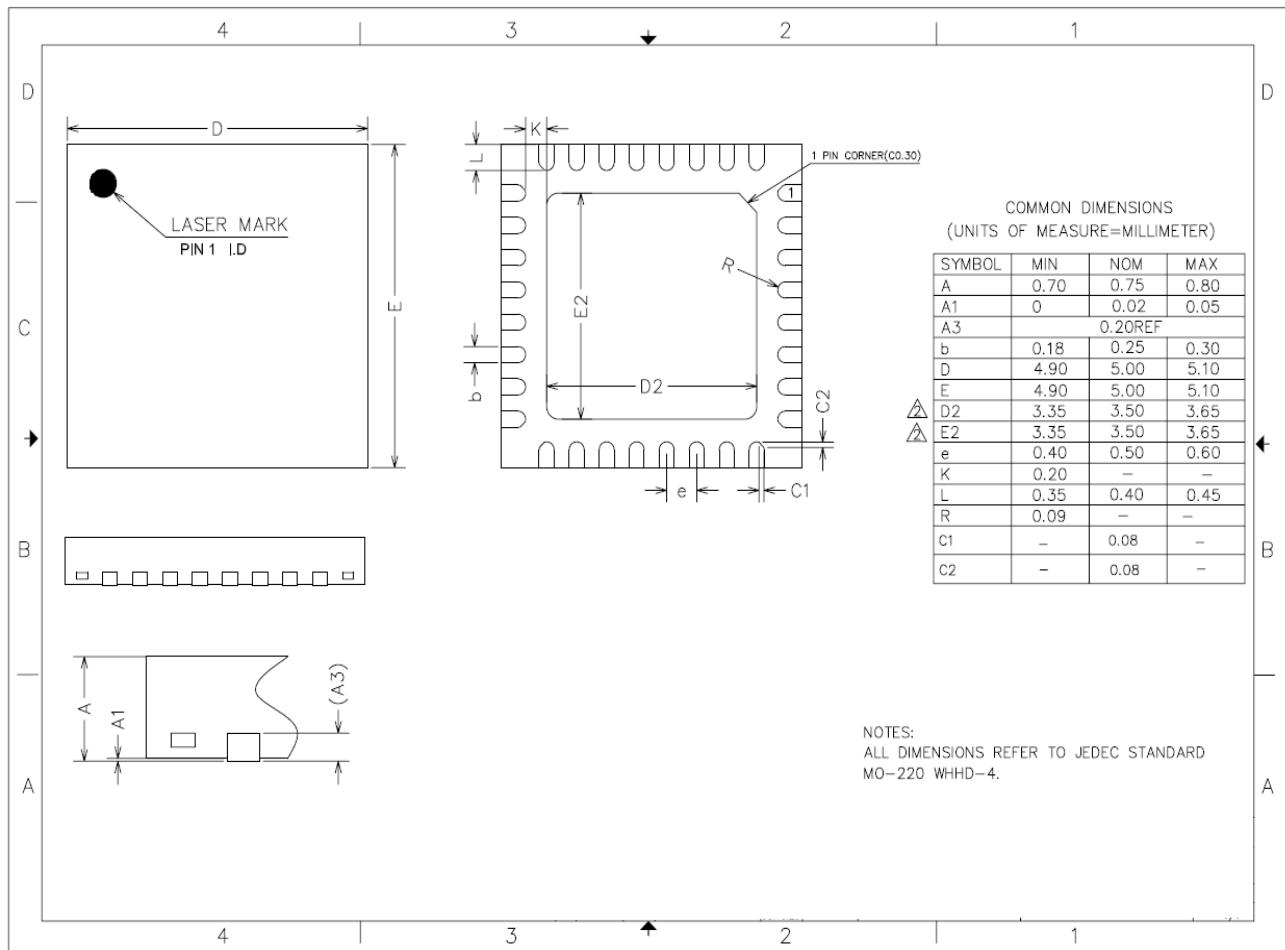
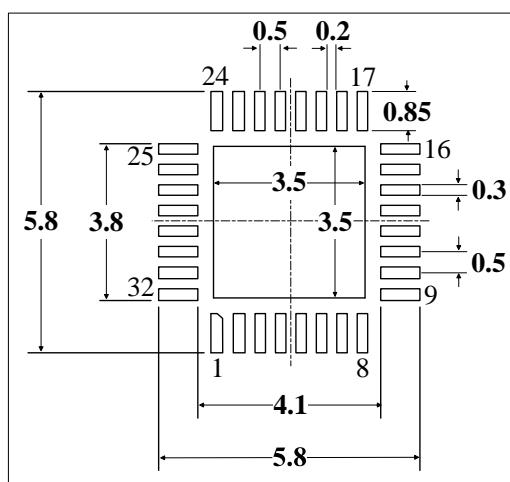


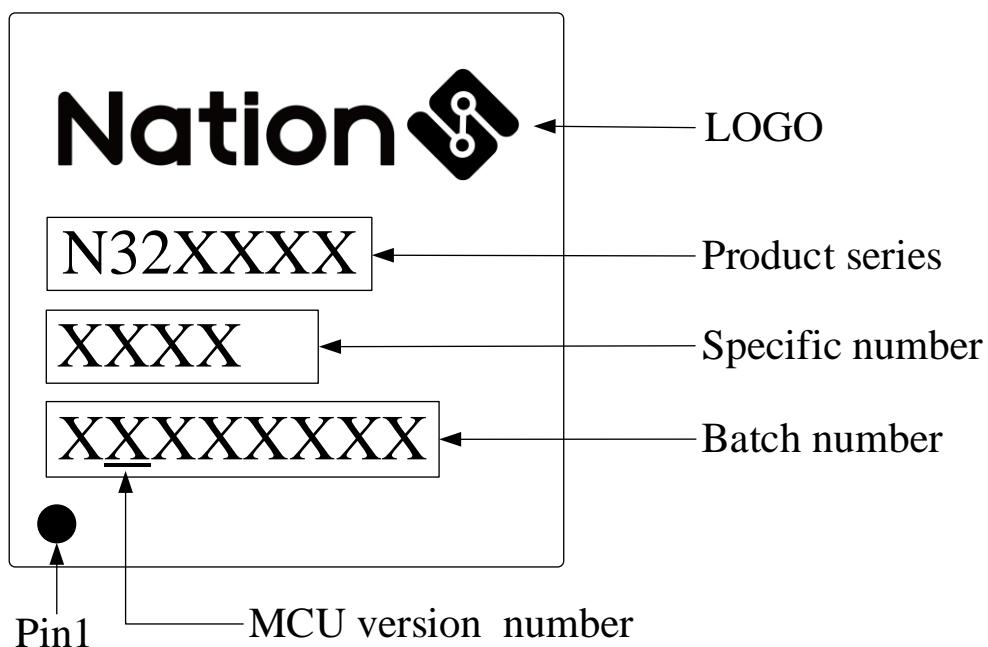
Figure 5-12 Suggestions for QFN32(5x5mm) package solder pads⁽¹⁾



2. The unit of measurement is millimeters

5.7 Marking information

Figure 5-13 Marking information



6 Ordering Information

Figure 6-1 N32G052 series ordering code information diagram

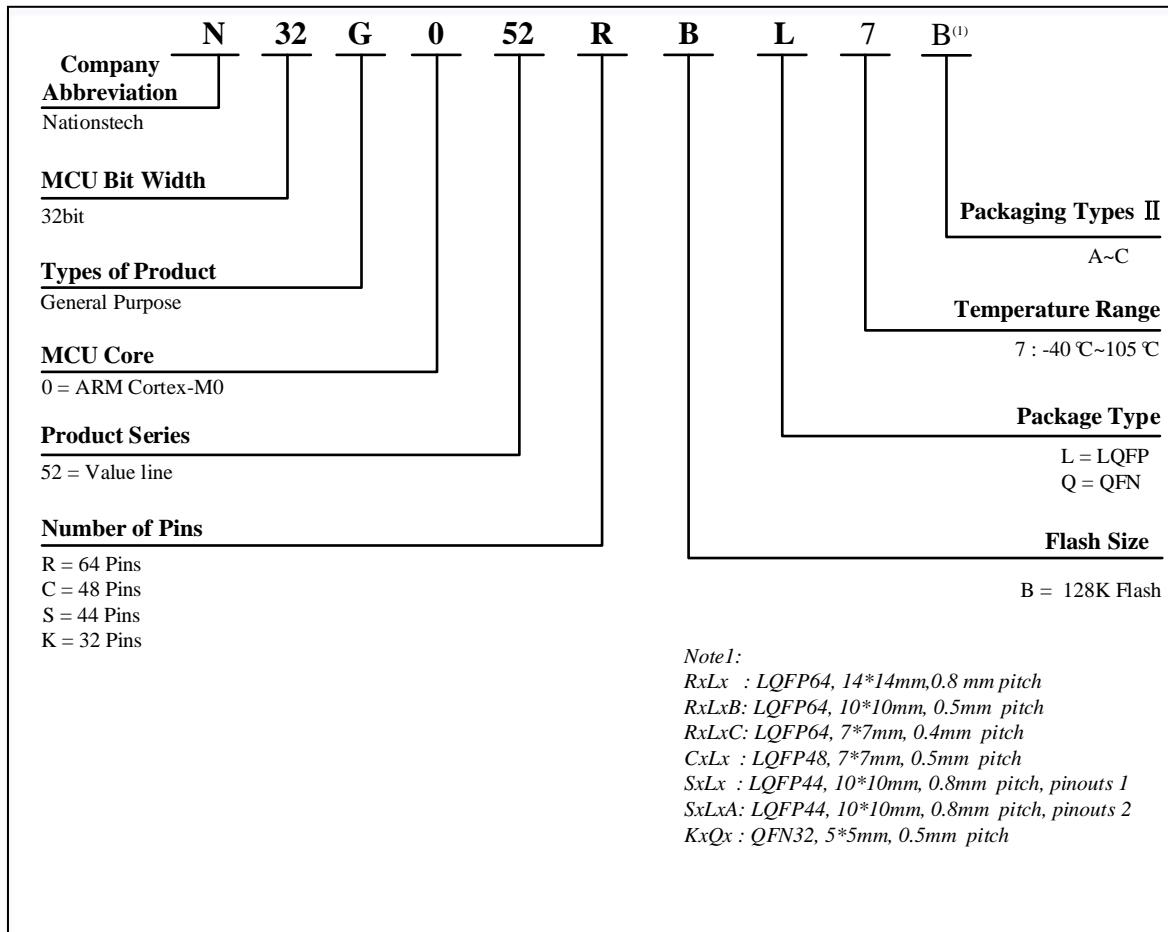


Table 6-1 N32G052 series ordering code information

| Order Code ⁽¹⁾ | Package | Package Size | Packaging ⁽²⁾ | SPQ ⁽³⁾ | temperature range |
|---------------------------|---------|--------------|--------------------------|--------------------|-------------------|
| N32G052RBL7 | LQFP64 | 14*14mm | Tray | 90 | -40°C~105°C |
| N32G052RBL7B | LQFP64 | 10*10mm | Tray | 160 | -40°C~105°C |
| N32G052RBL7C | LQFP64 | 7*7mm | Tray | 250 | -40°C~105°C |
| N32G052CBL7 | LQFP48 | 7*7mm | Tray | 250 | -40°C~105°C |
| N32G052SBL7 | LQFP44 | 10*10mm | Tray | 160 | -40°C~105°C |
| N32G052SBL7A | LQFP44 | 10*10mm | Tray | 160 | -40°C~105°C |
| N32G052KBQ7 | QFN32 | 5*5mm | Tray | 490 | -40°C~105°C |
| | | | Reel | 2500 | |

- For the latest detailed ordering information, please refer to the selection manual.
- This packaging is the basic packaging. If you have any other requirements, please contact National Technology
- Minimum packaging quantity

7 Version history

| Date | Version | Modify |
|------------|---------|--|
| 2024.5.15 | V0.9.0 | Initial Beta version |
| 2024.7.15 | V1.0.0 | Addition of several series of devices |
| 2024.10.21 | V1.1.0 | <ol style="list-style-type: none">1. Two new packaging models for LQFP44 have been added2. Update LQFP48 packaging diagram, add PC15 to 36pin3. Delete all power off descriptions in PD mode4. Add IrDA&LIN mode to UART mode configuration5. Add a section on ordering information, including ordering information and the original naming convention diagram6. Pin multiplex relationship, adding I2C2_SCL/I2C1_SDA/COMP1_INM7. Suggestions for adding solder pads to the packaging information8. Update marking information9. Delete VLCD optional power supply description |

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